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TECHNICAL MANUAL, TUBE TEST CONDITIONS

for

TUBE TEST PROGRAMING CARD KIT MK-827/USM-118

used with

ELECTRON TUBE TEST SETS AN/USM-118 A

and

AN/USM-118 B

DEPARTMENT OF THE NAVY
NAVAL ELECTRONIC SYSTEMS COMMAND

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SECTION 1

GENERAL INFORMATION

1-1. PURPOSE.

This publication provides a detailed listing of the conditions established for testing individual electron tube types in either the AN/USM-118A or AN/USM-118B Electron Tube Test Sets when used in conjunction with the MK-827/USM-118 Card Kit.

1-2. DESCRIPTION OF CARD KITS.

a. Card Kit MK-704/USM-118A consists of 944 prepunched programing cards for testing a total of 602 different tube types. This Card Kit was supplied as standard equipment with AN/USM-118( ) equipments ordered prior to 14 August 1967 when specified by the Contract or Order.

b. Card Kit MK-827/USM-118 contains 2484 prepunched programing cards for testing a total of 1556 different tube types. It includes all of the cards provided in the MK-704/USM-118A Card Kit and 1540 additional cards for 954 additional tube types. The MK-827/USM-118 Card Kit is supplied in lieu of the MK-704 when specified by the Contract or Order.

c. Card Kit MK-828/USM-118 (supplied only on special order) consists of a group of 1540 cards intended to supplement those in the MK-704 Card Kit and increase the number of tube types to 1556.

d. After interfiling the MK-828 cards with those in the MK-704, the combined set will be the same as Card Kit MK-827/USM-118.

SECTION 2

2-1. LIST OF ABBREVIATIONS OR SYMBOLS.

In order to conserve space the abbreviations and symbols listed in Table 2-1 will be used in the Tube Test Conditions List, Table 2-2.

TABLE 2-1. ABBREVIATIONS AND SYMBOLS

ABBREVIATION OR SYMBOL	DEFINITION
Ckt	Circuit
Cl	Load Capacitor
Eb	DC Positive Voltage applied to the plate
Ebb	DC Plate Supply Voltage
Ec1	DC Voltage applied to G1
Ec2	DC Voltage applied to G2
Ec3	DC Voltage applied to G3
Ec4	DC Voltage applied to G4
Ec5	DC Voltage applied to G5
Ef	Filament or heater Voltage
Epp	AC Plate Supply Voltage
Etd	Plate to Cathode Tube Voltage drop
F-W	Full-Wave, Rectifying Circuit
G1	Grid nearest Cathode
G2	Grid second from Cathode
G3	Grid third from Cathode
G4	Grid fourth from Cathode
G5	Grid fifth from Cathode
Gm	Mutual Conductance
H-K	Heater-Cathode leakage reject value in microamperes
H-W	Half-Wave, Rectifying Circuit
Ib	Plate Current
IG2	G2 Current
Ik	Cathode Current
Io	DC Component of output Current of Rectifiers
K	Cathode
MA	Milliamperes
P	Plate
Rk	Self-Bias Cathode Resistance
Rl	Plate Circuit Resistance
Spl	Special
μf	Microfarad
μmhos	Micromhos (Mutual Conductance)
V	Volts
VAC	Volts AC
VDC	Volts DC

2-2. TUBE TEST CONDITIONS.

The actual test conditions established for individual tube types by the programing cards are listed in Table 2-2. Tube types are listed in alphanumeric order starting with 01A.

TABLE 2-2. TUBE TEST CONDITIONS

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
01A	1 of 1	-	4.2	-	-	Ef = 5.0 VAC Eb = 150 Ec1 = - 13.0 Ib measured
0A2	1 of 4	Instruction Card				
0A2	2 of 4	-	0.2	-	-	Leakage test at 50 volts
0A2	3 of 4	-	-	300	-	Etd measured at 5 MA
0A2	4 of 4	-	-	300	-	Etd measured at 30 MA
0A3	1 of 4	Instruction Card				
0A3	2 of 4	-	0.1	-	-	Leakage test at 50 volts
0A3	3 of 4	-	-	150	-	Etd measured at 5 MA
0A3	4 of 4	-	-	150	-	Etd measured at 40 MA
0A4	1 of 2	Instruction Card				
0A4	2 of 2	-	38	-	-	Ebb (Anode) = 140 Rl (Anode) = 2800 Ω Ebb (Starter) = 114 (manually set) Rl (Starter) = 470,000 Ω Ib (Starter) = 115 Microamp Ik measured
0B2	1 of 4	Instruction Card				
0B2	2 of 4	-	0.2	-	-	Leakage test at 50 volts
0B2	3 of 4	-	-	200	-	Etd measured at 5 MA
0B2	4 of 4	-	-	200	-	Etd measured at 30 MA
0B3	1 of 4	Instruction Card				
0B3	2 of 4	-	0.1	-	-	Leakage test at 50 volts
0B3	3 of 4	-	-	200	-	Etd measured at 5 MA
0B3	4 of 4	-	-	200	-	Etd measured at 30 MA
0C2	1 of 4	Instruction Card				
0C2	2 of 4	-	0.2	-	-	Leakage test at 50 volts
0C2	3 of 4	-	-	100	-	Etd measured at 5 MA
0C2	4 of 4	-	-	100	-	Etd measured at 30 MA
0C3	1 of 4	Instruction Card				
0C3	2 of 4	-	0.1	-	-	Leakage test at 50 volts
0C3	3 of 4	-	-	200	-	Etd measured at 5 MA
0C3	4 of 4	-	-	200	-	Etd measured at 40 MA
0D3	1 of 4	Instruction Card				
0D3	2 of 4	-	0.1	-	-	Leakage test at 50 volts
0D3	3 of 4	-	-	300	-	Etd measured at 5 MA
0D3	4 of 4	-	-	300	-	Etd measured at 40 MA
0E3/85A1	1 of 3	Instruction Card				
0E3/85A1	2 of 3	-	-	100	-	Etd measured at 1.0 MA
0E3/85A1	3 of 3	-	-	100	-	Etd measured at 8.0 MA
0G3/85A2	1 of 3	Instruction Card				
0G3/85A2	2 of 3	-	-	100	-	Etd measured at 1.0 MA
0G3/85A2	3 of 3	-	-	100	-	Etd measured at 10.0 MA
0Z4	1 of 1	-	120	-	-	Ebb = 296 Rl = 3600 Ω Ib measured Dual test: 1st Diode: P pin 5 used 2nd Diode: P pin 3 used
0Z4A/1003	1 of 1	-	176	-	-	Epp = 250 VAC (F-W) Rl = 1850 Ω Io measured
1A3	1 of 2	-	0.6	-	20	Ef = 1.1 VAC Ebb = 50 Rl = 100,000 Ω Ib measured P pin 6 used

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
1A3	2 of 2	-	0.6	-	20	Ef = 1.1 VAC Ebb = 50 Rl = 100,000 Ω Ib measured P pin 2 used
1A4	1 of 1	-	3.28	-	-	Ef = 2.0 VAC Eb = 50 Ec2 = 50 Ec1 = -1.0 Ib measured
1A5	1 of 1	1100	-	-	-	Ef = 1.4 VAC Eb = 100 Ec2 = 100 Ec1 = -6.0 G1-P Gm measured
1A7	1 of 2	900	-	-	-	Ef = 1.4 VAC Eb = 50 Ec2, 3, 5 = 50 Ec1, 4 = -1.0 G1, G4-P Gm measured
1A7	2 of 2	500	-	-	-	Ef = 1.4 VAC Eb = 50 Ec2, 3, 5 = 50 Ec4 = 0 Ec1 = -1.0 G1-P, G3, G5 Gm measured
1AB5	1 of 1	-	10	-	-	Ef = 1.2 VAC Eb = 150 Ec2 = 150 Rk = 170 Ω Fil Pins 1 & 8 used Ib measured OK 4.5 MA to 9.5 MA
1AB6/ DK96	1 of 2	-	2.16	-	-	Ef = 1.4 VAC Eb = 50 Ec2, 4 = 50 Ec1, 3 = -1.0 Ib & IG2 measured
1AB6/ DK96	2 of 2	-	0.58	-	-	Ef = 1.4 VAC Eb = 50 Ec2, 4 = 50 Ec1, 3 = -1.0 Ib & IG4 measured
1AD4	1 of 1	2300	-	-	-	Ef = 1.25 VAC Eb = 50 Ec2 = 50 Ec1 = -1.0 G1-P Gm measured
1AD5	1 of 1	-	1.9	-	-	Ef = 1.25 VAC Eb = 50 Ec2 = 50 Ec1 = 0 Ib measured

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
1AE4	1 of 2	-	4.2	-	-	Ef = 1.3 VAC Eb = 100 Ec2 = 100 Ec1 = -1.3 Fil Pins 1 & 7 used Ib measured
1AE4	2 of 2	-	4.2	-	-	Ef = 1.3 VAC Eb = 100 Ec2 = 100 Ec1 = -1.3 Fil Pins 5 & 7 used Ib measured
1AF4	1 of 1	-	1.64	-	-	Ef = 1.4 VAC Eb = 100 Ec2 = 100 Ec1 = -1.0 Fil Pins 1 & 7 used Ib measured
1AG4	1 of 1	1200	-	-	-	Ef = 1.25 VAC Eb = 50 Ec2 = 50 Ec1 = -4.7 G1-P Gm measured
1AG5	1 of 2	-	1.0	-	-	Ef = 1.25 VAC Eb = 50 Ec2 = 50 Ec1 = -1.5 Pent. Ib measured
1AG5	2 of 2	-	0.4	-	-	Ef = 1.25 VAC Ebb = 9.0 Rl = 1500 Ω Diode Ib measured
1AH4	1 of 1	900	-	-	-	Ef = 1.25 VAC Eb = 50 Ec2 = 50 Ec1 = -1.0 G1-P Gm measured
1AH5/ DAF96	1 of 2	-	0.12	-	-	Ef = 1.4 VAC Eb = 50 Ec2 = 50 Ec1 = -1.7 Pent. Ib measured
1AH5/ DAF96	2 of 2	-	0.5	-	-	Ef = 1.4 VAC Ebb = 9.0 Rl = 11,000 Ω Diode Ib measured
1AJ4/ DF96	1 of 1	-	1.32	-	-	Ef = 1.3 VAC Eb = 50 Ec2 = 50 Ec1 = -0.7 Ib measured

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
1AJ5	1 of 2	-	1.26	-	-	Ef = 1.25 VAC Eb = 50 Ec2 = 50 Ec1 = -1.5 Pent. Ib measured
1AJ5	2 of 2	-	0.4	-	-	Ef = 1.25 VAC Ebb = 20 Rl = 50,000 Ω Diode Ib measured
1AK4	1 of 1	-	0.76	-	-	Ef = 1.25 VAC Eb = 50 Ec2 = 50 Ec1 = -1.0 Ib measured
1AU3	1 of 1	-	2.8	-	-	Ef = 1.25 VAC Ebb = 150 Rl = 11,000 Ω Ib measured
1AX2	1 of 1	-	4.6	-	-	Ef = 1.4 VAC Ebb = 240 Rl = 21,700 Ω Ib measured
1B3	1 of 1	-	6.1	-	-	Ef = 1.2 VAC Ebb = 150 Rl = 16,500 Ω Ib measured
1B4	1 of 1	-	1.54	-	-	Ef = 2.0 VAC Eb = 50 Ec2 = 50 Ec1 = -2.5 Ib measured
1C5	1 of 1	-	10	-	-	Ef = 1.4 VAC Eb = 100 Ec2 = 100 Ec1 = -8.6 Ib measured
1C21	1 of 2	Instruction Card				
1C21	2 of 2	-	28	-	-	Ebb (Anode) = 100 Rl (Anode) = 1500 Ω Ebb (Starter) = 84 (manually set) Rl (Starter) = 470,000 Ω Ib (Starter) = 50 microamps Ik measured
1D8	1 of 3	-	2.0	-	-	Ef = 1.4 VAC Eb = 50 Ec2 = 50 Ec1 = -6.2 Pent. Ib measured
1D8	2 of 3	-	1.4	-	-	Ef = 1.4 VAC Eb = 100 Ec1 = -1.0 Ib measured Triode: pin 6 & cap used
1D8	3 of 3	-	0.7	-	-	Ef = 1.4 VAC Ebb = 9.0 Rl = 11,100 Ω Ib measured Diode: pin 8 used
1DN5	1 of 2	-	1.5	-	-	Ef = 1.4 VAC Eb = 50 Ec2 = 50 Ec1 = -1.0 Pent. Ib measured
1DN5	2 of 2	-	0.3	-	-	Ef = 1.4 VAC Ebb = 20 Rl = 66,700 Ω Diode Ib measured
1G3	1 of 1	-	6.1	-	-	Ef = 1.2 VAC Ebb = 150 Rl = 16,500 Ω Ib measured
1G4	1 of 1	-	3.4	-	-	Ef = 1.4 VAC Eb = 100 Ec1 = -7.7 Ib measured OK 1.36 MA to 3.1 MA
1G6	1 of 1	-	1.7	-	-	Ef = 1.4 VAC Eb = 100 Ec1 = -0.9 Ib measured Dual Test: 1st Triode: pins 5, 6 2nd Triode: pins 3, 4 OK 0.5 MA to 1.5 MA
1H2	1 of 1	-	6.1	-	-	Ef = 1.4 VAC Ebb = 150 Rl = 11,285 Ω Ib measured Fil pins 1 & 2 used
1H4	1 of 1	-	3.9	-	-	Ef = 2.0 VAC Eb = 150 Ec1 = -10.5 Ib measured
1H5	1 of 2	-	0.14	-	-	Ef = 1.4 VAC Eb = 150 Ec1 = -1.0 Triode Ib measured
1H5	2 of 2	-	0.4	-	-	Ef = 1.4 VAC Ebb = 20 Rl = 50,000 Ω Diode Ib measured
1J3	1 of 1	-	3.8	-	-	Ef = 1.2 VAC Ebb = 200 Rl = 23,000 Ω Ib measured

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
1K3	1 of 1	-	6.1	-	-	Ef = 1.25 VAC Eb = 150 Ib measured OK over 1.8 MA
1L4	1 of 1	1200	-	-	-	Ef = 1.4 VAC Eb = 100 Ec2 = 100 Ec1 = -1.0 G1-P Gm measured
1L6	1 of 2	900	-	-	-	Ef = 1.4 VAC Eb = 50 Ec2, 3, 5 = 50 Ec1, 4 = -1.0 G1, G4-P Gm measured
1L6	2 of 2	600	-	-	-	Ef = 1.4 VAC Eb = 50 Ec2, 3, 5 = 50 Ec4 = 0 Ec1 = -1.0 G1-P, G3, G5 Gm measured
1LA4	1 of 1	1100	-	-	-	Ef = 1.4 VAC Eb = 100 Ec2 = 100 Ec1 = -6.0 G1-P Gm measured
1LA6	1 of 2	900	-	-	-	Ef = 1.4 VAC Eb = 50 Ec2, 3, 5 = 50 Ec1, 4 = -1.0 G1, G4-P Gm measured
1LA6	2 of 2	500	-	-	-	Ef = 1.4 VAC Eb = 50 Ec4 = 0 Ec2, 3, 5 = 50 Ec1 = -1.0 G1-P, G3, G5 Gm measured
1LB4	1 of 1	800	-	-	-	Ef = 1.4 VAC Eb = 50 Ec2 = 50 Ec1 = -5.5 G1-P Gm measured
1LC5	1 of 1	900	-	-	-	Ef = 1.4 VAC Eb = 50 Ec3 = 0 Ec2 = 50 Ec1 = -1.0 G1-P Gm measured
1LC6	1 of 2	800	-	-	-	Ef = 1.4 VAC Eb = 50 Ec2, 3, 5 = 50 Ec1, 4 = -1.0 G1, G4-P Gm measured

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
1LC6	2 of 2	500	-	-	-	Ef = 1.4 VAC Eb = 50 Ec4 = 0 Ec2, 3, 5 = 50 Ec1 = -1.0 G1-P, G3, G5 Gm measured
1LD5	1 of 2	-	0.32	-	-	Ef = 1.4 VAC Eb = 50 Ec2 = 50 Ec1 = -1.0 Pent. Ib measured
1LD5	2 of 2	-	0.4	-	-	Ef = 1.4 VAC Ebb = 20 Rl = 50,000 Ω Diode Ib measured
1LE3	1 of 1	-	1.76	-	-	Ef = 1.4 VAC Eb = 100 Ec1 = -4.3 Ib measured
1LF3	1 of 1	-	1.76	-	-	Ef = 1.4 VAC Eb = 100 Ec1 = -4.3 Ib measured
1LG5	1 of 1	1300	-	-	-	Ef = 1.4 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -2.5 G1-P Gm measured
1LH4	1 of 2	-	0.14	-	-	Ef = 1.4 VAC Eb = 150 Ec1 = -1.0 Triode Ib measured
1LH4	2 of 2	-	0.4	-	-	Ef = 1.4 VAC Ebb = 20 Rl = 50,000 Ω Diode Ib measured
1LN5	1 of 1	900	-	-	-	Ef = 1.4 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -1.0 G1-P Gm measured
1M3/ DM70	1 of 2	-	0.32	-	-	Ef = 1.4 VAC Eb = 100 Ec1 = -1.0 Ib measured Bar lights
1M3/ DM70	2 of 2	-	0.1	-	-	Ef = 1.4 VAC Eb = 150 Ec1 = -20 Ib measured OK 0 to 0.03 MA Dot lights

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
1N2	1 of 1	-	5.0	-	-	Ef = 1.1 VAC Ebb = 150 Rl = 20,000 Ω Ib measured
1N3/ DM71	1 of 2	-	0.32	-	-	Ef = 1.4 VAC Eb = 100 Ec1 = -1.0 Ib measured Bar lights
1N3/ DM71	2 of 2	-	0.1	-	-	Ef = 1.4 VAC Eb = 150 Ec1 = -20 Ib measured OK 0 to 0.03 MA Dot lights
1N5	1 of 1	900	-	-	-	Ef = 1.4 VAC Eb = 100 Ec2 = 100 Ec1 = -1.0 G1-P Gm measured
1P5	1 of 1	900	-	-	-	Ef = 1.4 VAC Eb = 100 Ec2 = 100 Ec1 = -1.0 G1-P Gm measured
1Q5	1 of 1	-	12	-	-	Ef = 1.4 VAC Eb = 100 Ec2 = 100 Ec1 = -6.5 Ib measured
1R4/ 1294	1 of 1	-	0.52	-	20	Ef = 1.4 VAC Ebb = 50 Rl = 140,000 Ω Ib measured
1R5	1 of 2	800	-	-	-	Ef = 1.4 VAC Eb = 50 Ec2, 4 = 50 Ec1, 3 = -1.0 G1, G3-P Gm measured Fil pin 1 used
1R5	2 of 2	1400	-	-	-	Ef = 1.4 VAC Eb = 50 Ec 3 = 0 Ec2, 4 = 50 Ec1 = -1.0 G1-P, G2, G4 Gm measured Fil pin 5 used
1S2A/ DY87	1 of 1	-	6.0	-	-	Ef = 1.4 VAC Ebb = 100 Rl = 10,000 Ω Ib measured Fil pins 1 & 2 used
1S4	1 of 1	1500	-	-	-	Ef = 1.4 VAC Eb = 50 Ec2 = 50 Ec1 = -6.8 G1-P Gm measured
1S5	1 of 2	-	2.0	-	-	Ef = 1.4 VAC Eb = 100 Ec2 = 100 Ec1 = -2.0 Pent. Ib measured
1S5	2 of 2	-	0.4	-	-	Ef = 1.4 VAC Ebb = 20 Rl = 50,000 Ω Diode Ib measured
1T4	1 of 1	900	-	-	-	Ef = 1.4 VAC Eb = 50 Ec2 = 50 Ec1 = -1.0 G1-P Gm measured
1T5	1 of 1	-	8.0	-	-	Ef = 1.4 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -8.0 Ib measured
1U4	1 of 1	1000	-	-	-	Ef = 1.4 VAC Eb = 100 Ec2 = 100 Ec1 = -1.0 G1-P Gm measured
1U5	1 of 2	-	2.0	-	-	Ef = 1.4 VAC Eb = 100 Ec2 = 100 Ec1 = -3.7 Pent. Ib measured
1U5	2 of 2	-	0.4	-	-	Ef = 1.4 VAC Ebb = 20 Rl = 50,000 Ω Diode Ib measured
1U6	1 of 2	-	1.26	-	-	Ef = 1.4 VAC Eb = 50 Ec2, 3, 5 = 50 Ec1, 4 = -1.0 Ib measured
1U6	2 of 2	-	4.1	-	-	Ef = 1.4 VAC Eb, Ec2, Ec3, Ec5 = 50 Ec4 = 0 Ec1 = -1.0 Ib, IG2, IG3, IG5 measured
1V	1 of 1	-	72	-	50	Ef = 6.3 VAC Epp = 250 VAC (H-W) Rl = 5400 Ω Cl = 4 μf Io measured
1V2	1 of 1	-	6.1	-	-	Ef = 0.6 VAC Ebb = 200 Rl = 21,400 Ω Ib measured

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
1V5	1 of 1	-	2.5	-	-	Ef = 1.3 VAC Eb = 50 Ec2 = 50 Ec1 = -2.9 Ib measured
1V6	1 of 2	-	0.5	-	-	Ef = 1.25 VAC Eb = 50 Ec2 = 50 Ec1 = -1.5 Pent. Ib measured
1V6	2 of 2	-	0.5	-	-	Ef = 1.25 VAC Eb = 50 Ec1 = -3.0 Triode Ib measured
1W5	1 of 1	-	0.66	-	-	Ef = 1.25 VAC Eb = 50 Ec2 = 50 Ec1 = -2.0 Ib measured OK 0.25 to 0.5 MA
1X2	1 of 1	-	6.1	-	-	Ef = 1.2 VAC Ebb = 150 Rl = 16,500 Ω Ib measured
1Z2	1 of 1	-	4.0	-	-	Ef = 1.35 VAC Epp = 250 VAC (H-W) Rl = 31,100 Ω Io measured
2A3	1 of 1	-	66	-	-	Ef = 2.5 VAC Eb = 150 Ec1 = -23 Ib measured
2A4	1 of 3	-	166	-	-	Ef = 2.5 VAC Ebb = 150 Ec1 = 0 Rl = 1300 Ω Ib measured
2A4	2 of 3	-	-	100	-	Ef = 2.5 VAC Etd measured at 100 MA OK under 24 V
2A4	3 of 3	-	36	-	-	Ef = 2.5 VAC Eb = 150 Ec1 = -31 Ib cut-off test OK under 3.6 MA
2A5	1 of 1	3500	-	-	70	Ef = 2.5 VAC Eb = 150 Ec2 = 150 Ec1 = -3.3 G1-P Gm measured
2A6	1 of 2	1200	-	-	20	Ef = 2.5 VAC Eb = 150 Ec1 = -1.0 Triode Gm measured
2A6	2 of 2	-	0.6	-	20	Ef = 2.5 VAC Ebb = 20 Rl = 33,300 Ω Diode Ib measured Dual Test: 1st Diode: P pin 4 used 2nd Diode: P pin 3 used
2A7	1 of 2	700	-	-	20	Ef = 2.5 VAC Eb = 100 Ec2, 3, 5 = 100 Ec1, 4 = -5.8 G1, G4-P Gm measured
2A7	2 of 2	1800	-	-	20	Ef = 2.5 VAC Eb = 100 Ec2,3, 5 = 100 Ec4 = 0 Ec1 = -7.6 G1-P, G3, G5 Gm measured
2AC15	1 of 1	-	0.6	-	-	Ef = 1.9 VAC Eb = 300 Ib measured
2AF4	1 of 1	6800	-	-	20	Ef = 2.35 VAC Eb = 100 Rk = 270 Ω Gm measured
2AS15	1 of 1	-	0.6	-	-	Ef = 1.9 VAC E = 300 Ib measured Fil. ckt. completed through tube jumper
2B3	1 of 1	-	6.1	-	-	Ef = 1.8 VAC Ebb = 150 Rl = 16,500 Ω Ib measured
2B4	1 of 3	-	100	-	20	Ef = 2.5 VAC Ebb = 150 Rl = 2180 Ω Ec1 = 0 Ib measured
2B4	2 of 3	-	-	100	20	Ef = 2.5 VAC Etd measured at 60 MA OK under 25 V
2B4	3 of 3	-	10	-	-	Ef = 2.5 VAC Eb = 150 Ec1 = -28 Ib measured OK under 1.0 MA
2B7	1 of 2	1200	-	-	20	Ef = 2.5 VAC Eb = 100 Ec2 = 100 Ec1 = -3.0 Pent. G1-P Gm measured

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
2B7	2 of 2	-	0.6	-	20	Ef = 2.5 VAC Ebb = 20 Rl = 33,300 Ω Diode Ib measured Dual Test: 1st Diode: P pin 5 used 2nd Diode: P pin 4 used
2B22	1 of 1	-	22	-	20	Ef = 6.3 VAC Ebb = 9.0 Rl = 215 Ω Ib measured K pin 8 used
2BN4	1 of 1	8600	-	-	20	Ef = 2.3 VAC Eb = 150 Rk = 220 Ω Gm measured Pins 1, 2, 5 used
2C4	1 of 3	-	8.1	-	20	Ef = 2.5 VAC Ebb = 100 Rl = 15,900 Ω Ec1 = 0 Ib measured
2C4	2 of 3	-	-	100	20	Ef = 2.5 VAC Etd measured at 5 MA OK under 20 V
2C4	3 of 3	-	44	-	20	Ef = 2.5 VAC Ebb = 150 Rl = 9000 Ω Ec1 = -43 Ib cut-off test OK under 4.4 MA
2C22	1 of 2	Instruction Card				
2C22	2 of 2	3800	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -4.0 Gm measured
2C26A	1 of 3	Instruction Card				
2C26A	2 of 3	2400	-	-	100	Ef = 6.3 VAC Eb = 150 Ec1 = -1.0 Gm measured
2C26A	3 of 3	-	-	100	100	Ef = 6.3 VAC Etd measured at 100 MA OK under 50 V
2C34	1 of 2	2700	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -6.1 Gm measured Triode: G pin 3 & P cap over pin 3 used
2C34	2 of 2	2700	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -6.1 Gm measured Triode: G pin 5 & P cap over pin 5 used
2C40	1 of 2	Instruction Card				
2C40	2 of 2	6300	-	-	20	Ef = 6.3 VAC Eb = 150 Rk = 120 Ω Gm measured K pin 8 used
2C42	1 of 2	Instruction Card				
2C42	2 of 2	8600	-	-	20	Ef = 6.3 VAC Eb = 150 Rk = 100 Ω Gm measured K pin 8 used
2C43	1 of 2	Instruction Card				
2C43	2 of 2	8600	-	-	20	Ef = 6.3 VAC Eb = 150 Rk = 100 Ω Gm measured K pin 8 used
2C46	1 of 2	Instruction Card				
2C46	2 of 2	4500	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -1.0 Gm measured OK over 1350 μmhos K pin 8 used
2C50	1 of 3	3600	-	-	20	Ef = 12.6 VAC Eb = 150 Ec1 = -7.3 Gm measured Dual Test: 1st Triode: pins 4, 5, 6 used 2nd Triode: pins 1, 2, 3 used
2C50	2 of 3	-	-	100	20	Ef = 12.6 VAC Etd measured at 60 MA OK under 30 V Dual Test: 1st Triode: pins 4, 5, 6 used 2nd Triode: pins 1, 2, 3 used
2C50	3 of 3	-	6.1	-	20	Ef = 12.6 VAC Eb = 150 Ec1 = -21 Ib cut-off test OK under 3 MA Dual Test: 1st Triode: pins 4, 5, 6 used 2nd Triode: pins 1, 2, 3 used
2C51	1 of 1	7600	-	-	20	Ef = 6.3 VAC Eb = 150 Rk = 240 Ω Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 2, 3, 4 used

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
2C52	1 of 4	1800	-	-	10	Ef = 12.6 VAC Eb = 150 Ec1 = -1.1 Gm measured Triode pins 4, 5, 6 used
2C52	2 of 4	-	80	-	-	Ef = 12.6 VAC Ebb = 50 Ec1 = +50 Rl = 500 Ω Ik measured Triode pins 4, 5, 6 used
2C52	3 of 4	1800	-	-	10	Ef = 12.6 VAC Eb = 150 Ec1 = -1.1 Gm measured Triode pins 1, 2, 3 used
2C52	4 of 4	-	80	-	-	Ef = 12.6 VAC Ebb = 50 Ec1 = +50 Rl = 500 Ω Ik measured Triode pins 1, 2, 3 used
2C53	1 of 2	-	14	-	20	Ef = 6.3 VAC Shorts and leakage test only Meter deflection independent of tube
2C53	2 of 2	-	48	-	20	Ef = 6.3 VAC Ebb = 50 Ec1 = +50 Rl = 880 Ω Ik measured
2CW4	1 of 1	10,600	-	-	10	Ef = 2.1 VAC Eb = 100 Rk = 100 Ω Gm measured Hickok Adapter 1050-127 required
2CY5	1 of 1	10,000	-	-	20	Ef = 2.4 VAC Eb = 100 Ec2 = 100 Ec1 = -1.4 G1-P Gm measured
2D21	1 of 3	-	166	-	20	Ef = 6.3 VAC Ebb = 150 Ec1, 2 = 0 Rl = 1450 Ω Ib measured G2 pin 7 used
2D21	2 of 3	-	-	100	20	Ef = 6.3 VAC Ebb = 285 Rl = 2800 Ω Etd measured at 100 MA OK under 10 V G2 pin 5 used
2D21	3 of 3	-	24	-	-	Ef = 6.3 VAC Epp = 250 VAC Ec2 = 0 Ec1 = -21.0 Rl = 10,000 Ω Ib cut-off test OK under 2.4 MA G2 pin 7 used
2DS4	1 of 1	13,400	-	-	10	Ef = 2.1 VAC Eb = 100 Rk = 100 Ω Gm measured Hickok Adapter 1050-127 required
2DZ4	1 of 1	8200	-	-	20	Ef = 2.4 VAC Eb = 100 Rk = 200 Ω Gm measured G pin 6, P pin 7 used
2E5	1 of 2	-	-	-	-	Ef = 2.5 VAC E (Screen) = Open Ckt E (Target) = 150 Ec1 = 0 (Eye open) Quality Test: No Meter Reading
2E5	2 of 2	-	-	-	-	Ef = 2.5 VAC E (Screen) = 150 E (Target) = 150 Ec1 = -64 (Eye Shut) Quality Test: No Meter Reading
2E22	1 of 2	-	76	-	-	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Ec1 = -2.5 Ib measured
2E22	2 of 2	-	-	100	-	Ef = 6.3 VAC Etd measured at 200 MA OK under 50 V
2E24	1 of 3	-	44	-	-	Ef = 3.1 VAC (Para.) Eb = 150 Ec3 = 0 Ec2 = 150 Ec1 = -6.5 Ib measured Pin 6 Fil center used
2E24	2 of 3	-	44	-	-	Ef = 3.1 VAC (Para.) Eb = 150 Ec3 = 0 Ec2 = 150 Ec1 = -6.5 Ib measured Pin 4 Fil center used

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
2E24	3 of 3	-	-	50	-	Ef = 3.1 VAC (Para.) Etd measured at 80 MA OK under 50 V Pin 1 Fil center used
2E25	1 of 1	-	50	-	-	Ef = 6.0 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Ec1 = -5.0 Ib measured
2E26	1 of 3	5000	-	-	50	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -13.5 G1-P Gm measured K pin 6 used
2E26	2 of 3	-	46	-	50	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -11 Ib measured K pin 4 used
2E26	3 of 3	-	-	50	50	Ef = 6.3 VAC Etd measured at 100 MA OK under 50 V K pin 1 used
2E30	1 of 1	-	38	-	-	Ef = 3.0 VAC (Para.) Eb = 150 Ec3 = 0 Ec2 = 150 Ec1 = -6.0 Ib measured
2E31	1 of 1	-	0.5	-	-	Ef = 1.25 VAC Eb = 50 Ec2 = 50 Ec1 = -3.1 Ib measured
2E32	1 of 1	-	0.5	-	-	Ef = 1.25 VAC Eb = 50 Ec2 = 50 Ec1 = 3.1 Ib measured
2E35	1 of 1	-	0.56	-	-	Ef = 1.25 VAC Eb = 50 Ec2 = 50 Ec1 = -2.4 Ib measured
2E36	1 of 1	-	0.56	-	-	Ef = 1.25 VAC Eb = 50 Ec2 = 50 Ec1 = -2.4 Ib measured
2E41	1 of 2	-	0.44	-	-	Ef = 1.25 VAC Eb = 50 Ec2 = 50 Ec1 = -3.1 Pent. Ib measured
2E41	2 of 2	-	0.38	-	-	Ef = 1.25 VAC Ebb = 9.0 Rl = 67 Ω Diode Ib measured
2E42	1 of 2	-	0.44	-	-	Ef = 1.25 VAC Eb = 50 Ec2 = 50 Ec1 = -3.1 Pent. Ib measured
2E42	2 of 2	-	0.38	-	-	Ef = 1.25 VAC Ebb = 9.0 Rl = 67 Ω Diode Ib measured
2EA5	1 of 1	9500	-	-	20	Ef = 2.3 VAC Eb = 150 Ec2 = 150 Ec1 = -1.0 G1-P Gm measured K pin 2 used
2EN5	1 of 1	-	14.1	-	20	Ef = 2.1 VAC Ebb = 9.0 Rl = 600 Ω Ib measured Dual Test: 1st Diode: P pin 7 used 2nd Diode: P pin 2 used
2ER5	1 of 2	13,200	-	-	20	Ef = 2.1 VAC Eb = 150 Ec1 = -0.8 Gm measured K pin 7 used
2ER5	2 of 2	13,200	-	-	20	Ef = 2.1 VAC Eb = 150 Ec1 = -0.8 Gm measured K pin 1 used
2ES5	1 of 2	10,000	-	-	20	Ef = 2.4 VAC Eb = 150 Ec1 = -0.8 Gm measured K pin 7 used
2ES5	2 of 2	10,000	-	-	20	Ef = 2.4 VAC Eb = 150 Ec1 = -0.8 Gm measured K pin 1 used
2EV5	1 of 1	11,100	-	-	20	Ef = 2.4 VAC Eb = 100 Ec2 = 100 Ec1 = -1.0 G1-P Gm measured K pin 2 used
2FH5	1 of 1	11,400	-	-	20	Ef = 2.4 VAC Eb = 150 Ec1 = -1.3 Gm measured K pin 1 used

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
2FQ5	1 of 1	13,800	-	-	20	Ef = 2.3 VAC Eb = 150 Ec1 = -1.5 Gm measured K pin 1 used
2FS5	1 of 1	6800	-	-	20	Ef = 2.4 VAC Eb = 150 Ec2 = 150 Ec1 = -0.9 G1-P Gm measured K pin 7 used
2FY5/ XC97	1 of 2	16,400	-	-	20	Ef = 2.4 VAC Eb = 150 Ec1 = -1.2 Gm measured K pin 7 used
2FY5/ XC97	2 of 2	16,400	-	-	20	Ef = 2.4 VAC Eb = 150 Ec1 = -1.2 Gm measured K pin 1 used
2G21	1 of 2	-	0.24	-	-	Ef = 1.25 VAC Eb = 50 Ec5 = 0 Ec2, 4 = 50 Ec1, 3 = -5.9 Pent. Ib measured
2G21	2 of 2	-	1.26	-	-	Ef = 1.25 VAC Eb = 50 Ec1 = -2.0 Triode Ib measured
2GK5	1 of 1	18,900	-	-	20	Ef = 2.3 VAC Eb = 150 Ec1 = -1.2 Gm measured K pin 7 used
2GW5	1 of 1	18,900	-	-	20	Ef = 2.4 VAC Eb = 150 Ec1 = -1.3 Gm measured
2HA5/ XC900	1 of 1	15,400	-	-	20	Ef = 1.9 VAC Eb = 150 Ec1 = -1.4 Gm measured
2T4	1 of 1	7600	-	-	20	Ef = 2.35 VAC Eb = 100 Rk = 270 Ω Gm measured Pins 1, 2, 5 used
2V2	1 of 1	-	6.1	-	-	Ef = 1.2 VAC (Para.) Ebb = 220 Rl = 23,625 Ω Ib measured
2V3	1 of 1	-	8.0	-	-	Ef = 2.5 VAC Ebb = 150 Rl = 11,416 Ω Ib measured
2X2A	1 of 1	-	32	-	-	Ef = 2.5 VAC Ebb = 170 Rl = 1200 Ω Ib measured
3A2	1 of 1	-	6.1	-	-	Ef = 3.15 VAC Ebb = 100 Rl = 11,425 Ω Ib measured
3A3	1 of 1	-	6.1	-	-	Ef = 3.1 VAC Ebb = 160 Rl = 16,925 Ω Ib measured
3A4	1 of 2	2400	-	-	-	Ef = 1.4 VAC (Para.) Eb = 100 Ec2 = 100 Ec1 = -10 G1-P Gm measured P pin 6 used
3A4	2 of 2	2400	-	-	-	Ef = 1.4 VAC (Para.) Eb = 100 Ec2 = 100 Ec1 = -10 G1-P Gm measured P pin 2 used
3A5	1 of 2	2100	-	-	-	Ef = 1.4 VAC (Para.) Eb = 100 Ec1 = -4.0 Gm measured Triode pins 5 & 6 used
3A5	2 of 2	2100	-	-	-	Ef = 1.4 VAC (Para.) Eb = 100 Ec1 = -4.0 Gm measured Triode pins 2 & 3 used
3AF4	1 of 1	6800	-	-	20	Ef = 3.2 VAC Eb = 100 Rk = 270 Ω Gm measured
3AJ8/ XCH81	1 of 2	7600	-	-	20	Ef = 3.6 VAC Eb = 150 Ec4, 2 = 150 Ec3 = 0 Ec1 = -4.0 G1-P Gm measured Heptode pins 1, 2, 3, 6, 7 used
3AJ8/ XCH81	2 of 2	4000	-	-	20	Ef = 3.6 VAC Eb = 100 Ec1 = -1.0 Triode Gm measured Pins 3, 8, 9 used

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE μMHOS	MA	VOLTS	H-K	TEST CONDITIONS
3AL5	1 of 1	-	26	-	10	Ef = 3.1 VAC Ebb = 6.0 Rl = 100 Ω Ib measured Dual Test: 1st Diode: pins 1 & 7 used 2nd Diode: pins 2 & 5 used
3AU6	1 of 1	6300	-	-	20	Ef = 3.1 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 70 Ω G1-P Gm measured
3AV6	1 of 2	1600	-	-	20	Ef = 3.1 VAC Eb = 100 Ec1 = -1.0 Triode Gm measured
3AV6	2 of 2	-	0.6	-	20	Ef = 3.2 VAC Ebb = 20 Rl = 33,300 Ω Diode Ib measured Dual Test: 1st Diode: P pin 6 used 2nd Diode: P pin 5 used
3AW3	1 of 1	-	6.1	-	-	Ef = 3.1 VAC Ebb = 150 Rl = 11,195 Ω Ib measured
3B2	1 of 1	-	6.1	-	-	Ef = 3.1 VAC Ebb = 200 Rl = 21,400 Ω Ib measured
3B4	1 of 2	-	24	-	-	Ef = 1.3 VAC (Para.) Eb = 150 Ec3 = 0 Ec2 = 150 Ec1 = -23 Ib measured Pin 2 Fil center used
3B4	2 of 2	-	4.0	-	-	Ef = 1.3 VAC (Para.) Eb = 150 Ec3 = 0 Ec2 = 150 Ec1 = -23 IG2 measured Pin 6 Fil center used OK under 2 MA
3B7	1 of 1	-	8.1	-	-	Ef = 1.4 VAC (Para.) Eb = 150 Ec1 = -3.4 Ib measured OK 3.4 MA to 7.0 MA Dual Test: 1st Triode: pins 6 & 7 used 2nd Triode: pins 2 & 3 used
3B24	1 of 2	-	120	-	-	Ef = 2.5 VAC Ebb = 295 Rl = 800 Ω Ib measured Fil pins 1 & 2 used
3B24	2 of 2	-	120	-	-	Ef = 2.5 VAC Ebb = 295 Rl = 800 Ω Ib measured Fil pins 1 & 4 used
3BA6	1 of 1	5400	-	-	20	Ef = 3.1 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Rk = 70 Ω G1-P Gm measured
3BC5	1 of 1	7000	-	-	20	Ef = 3.1 VAC Eb = 150 Ec2 = 150 Rk = 180 Ω G1-P Gm measured K pin 2 used
3BE6	1 of 2	600	-	-	20	Ef = 3.1 VAC Eb = 100 Ec2, 4 = 100 Ec1, 3 = -3.1 G3-P Gm measured
3BE6	2 of 2	8600	-	-	20	Ef = 3.1 VAC Eb = 100 Ec2, 4 = 100 Ec3 = 0 Ec1 = -1.0 G1-P, G2, G4 Gm measured
3BN4	1 of 1	8600	-	-	20	Ef = 2.8 VAC Eb = 150 Rk = 220 Ω Gm measured Pins 1, 2, 5 used
3BN6	1 of 2	1500	-	-	20	Ef = 3.1 VAC Eb = 50 Ec2, 3 = 50 Rk = 350 Ω G1-P Gm measured

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
3BN6	2 of 2	1500	-	-	20	Ef = 3.1 VAC Eb = 50 Ec1, 2 = 50 Rk = 150 Ω G3-P Gm measured
3BU8	1 of 2	-	2.4	-	20	Ef = 3.1 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -1.2 Ib measured P pin 8, G3 pin 9 used
3BU8	2 of 2	-	2.4	-	20	Ef = 3.1 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -1.2 Ib measured P pin 3, G3 pin 6 used
3BX6/ XF80	1 of 2	9300	-	-	20	Ef = 3.4 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Ec1 = -1.7 Gm measured K pin 3 used
3BX6/ XF80	2 of 2	9300	-	-	20	Ef = 3.4 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Ec1 = -1.7 Gm measured K pin 1 used
3BY6	1 of 2	2100	-	-	20	Ef = 3.1 VAC Eb = 100 Ec2, 4 = 100 Ec1, 3 = -2.5 G1-P Gm measured
3BY6	2 of 2	600	-	-	20	Ef = 3.1 VAC Eb = 100 Ec2, 4 = 100 Ec1, 3 = -2.5 G3-P Gm measured
3BZ6	1 of 1	7300	-	-	20	Ef = 3.1 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 180 Ω G1-P Gm measured
3C2	1 of 1	-	6.1	-	-	Ef = 1.6 VAC (Para.) Ebb = 100 Rl = 13,425 Ω Ib measured
3C4/ DL96	1 of 1	-	4.4	-	-	Ef = 0.9 VAC (Para.) Eb = 50 Ec2 = 50 Ec1 = -1.7 Ib measured
3CB6	1 of 1	7600	-	-	20	Ef = 3.1 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 180 Ω G1-P Gm measured
3CE5	1 of 1	7600	-	-	20	Ef = 3.1 VAC Eb = 150 Ec2 = 150 Rk = 180 Ω G1-P Gm measured
3CF6	1 of 1	7600	-	-	20	Ef = 3.1 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 180 Ω G1-P Gm measured
3CS6	1 of 2	1500	-	-	20	Ef = 3.1 VAC Eb = 50 Ec2, 4 = 50 Ec3 = 0 Ec1 = -1.5 G1-P Gm measured
3CS6	2 of 2	1500	-	-	20	Ef = 3.1 VAC Eb = 50 Ec2, 4 = 50 Ec3 = -1.0 Ec1 = 0 G3-P Gm measured
3CY5	1 of 1	10,000	-	-	20	Ef = 2.9 VAC Eb = 100 Ec2 = 100 Ec1 = -1.4 G1-P Gm measured
3D6/ 1299	1 of 1	-	12	-	-	Ef = 1.4 VAC (Para.) Eb = 100 Ec2 = 100 Ec1 = -6.3 Ib measured
3D21A	1 of 2	8800	-	-	150	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -11 G1-P Gm measured
3D21A	2 of 2	-	120	-	150	Ef = 6.3 VAC Ebb = 268 Rl = 3420 Ω Ec2 = 150 Ec1 = 0 Ib measured

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
3DG4	1 of 1	-	320	-	-	Ef = 3.3 VAC Epp = 250 VAC (F-W) Rl = 1100 Ω Cl = 4 μf Io measured
3DK6	1 of 1	11,100	-	-	20	Ef = 3.1 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 120 Ω G1-P Gm measured
3DT6	1 of 2	1000	-	-	20	Ef = 3.1 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Rk = 2100 Ω G1-P Gm measured
3DT6	2 of 2	600	-	-	20	Ef = 3.1 VAC Eb = 100 Ec2 = 100 Ec1, 3 = -1.7 G3-P Gm measured
3DZ4	1 of 1	8200	-	-	20	Ef = 3.2 VAC Eb = 100 Rk = 200 Ω Gm measured P pin 7, G pin 6 used
3E6	1 of 1	-	5.2	-	-	Ef = 1.4 VAC (Para.) Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -1.0 Ib measured
3EA5	1 of 1	9500	-	-	20	Ef = 3.0 VAC Eb = 150 Ec2 = 150 Ec1 = -1.0 G1-P Gm measured K pin 2 used
3EH7/ XF183	1 of 2	15,700	-	-	20	Ef = 3.4 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -2.2 G1-P Gm measured K pin 3 used
3EH7/ XF183	2 of 2	-	14.1	-	20	Ef = 3.4 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -2.2 Ib measured K pin 1 used
3EJ7/ XF184	1 of 2	18,900	-	-	20	Ef = 3.4 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Ec1 = -1.8 G1-P Gm measured K pin 3 used
3EJ7/ XF184	2 of 2	-	12	-	20	Ef = 3.4 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Ec1 = -1.8 Ib measured K pin 1 used
3ER5	1 of 2	13,200	-	-	20	Ef = 2.8 VAC Eb = 150 Ec1 = -0.8 Gm measured K pin 7 used
3ER5	2 of 2	13,200	-	-	20	Ef = 2.8 VAC Eb = 150 Ec1 = -0.8 Gm measured K pin 1 used
3ES5	1 of 2	10,000	-	-	20	Ef = 3.0 VAC Eb = 150 Ec1 = -0.8 Gm measured K pin 7 used
3ES5	2 of 2	10,000	-	-	20	Ef = 3.0 VAC Eb = 150 Ec1 = -0.8 Gm measured K pin 1 used
3EV5	1 of 1	11,100	-	-	20	Ef = 2.9 VAC Eb = 100 Ec2 = 100 Ec1 = -1.0 Gm measured K pin 2 used
3FH5	1 of 1	11,400	-	-	20	Ef = 3.0 VAC Eb = 150 Ec1 = -1.3 Gm measured K pin 1 used
3FQ5	1 of 1	13,800	-	-	20	Ef = 2.8 VAC Eb = 150 Ec1 = -1.5 Gm measured K pin 1 used
3FS5	1 of 1	6800	-	-	20	Ef = 2.9 VAC Eb = 150 Ec2 = 150 Ec1 = -0.9 G1-P Gm measured K pin 7 used
3FY5/ YC97	1 of 2	16,400	-	-	20	Ef = 3.1 VAC Eb = 150 Ec1 = -1.2 Gm measured K pin 7 used

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
3FY5/ YC97	2 of 2	16,400	-	-	20	Ef = 3.1 VAC Eb = 150 Ec1 = -1.2 Gm measured K pin 1 used
3GK5	1 of 1	18,900	-	-	20	Ef = 2.8 VAC Eb = 150 Ec1 = -1.2 Gm measured Pins 2, 5, 7 used
3GS8	1 of 2	-	1.38	-	50	Ef = 3.2 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -1.5 Ib measured P pin 8, G3 pin 9 used
3GS8	2 of 2	-	1.38	-	50	Ef = 3.2 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -1.5 Ib measured P pin 3, G3 pin 6 used
3GW5	1 of 1	18,900	-	-	20	Ef = 3.0 VAC Eb = 150 Ec1 = -1.3 Gm measured
3HA5/ LC900	1 of 1	15,400	-	-	20	Ef = 2.5 VAC Eb = 150 Ec1 = -1.4 Gm measured
3HM6	1 of 1	18,900	-	-	20	Ef = 3.2 VAC Eb = 150 Ec2 = 150 Rk = 100 Ω G1-P Gm measured K pin 1 used
3HT6	1 of 1	17,600	-	-	20	Ef = 3.2 VAC Eb = 150 Ec2 = 150 Rk = 90 Ω G1-P Gm measured K pin 1 used
3JD6	1 of 1	17,300	-	-	20	Ef = 3.5 VAC Eb = 100 Ec2 = 100 Rk = 40 Ω G1-P Gm measured
3KF8	1 of 2	1900	-	-	20	Ef = 3.2 VAC Eb = 100 Ec2 = 100 Ec1 = -0.9 G1-P Gm measured Pins 1, 2, 7, 8, 9 used
3KF8	2 of 2	1900	-	-	20	Ef = 3.2 VAC Eb = 100 Ec2 = 100 Ec1 = -0.9 G1-P Gm measured Pins 1, 2, 3, 6, 7 used
3LF4	1 of 1	2000	-	-	-	Ef = 1.4 VAC (Para.) Eb = 100 Ec2 = 100 Ec1 = -6.3 G1-P Gm measured
3Q4	1 of 2	2500	-	-	-	Ef = 1.4 VDC (Para.) Eb = 90 Ec2 = 90 Ec1 = -4.5 G1-P Gm measured P pin 2 used
3Q4	2 of 2	2500	-	-	-	Ef = 1.4 VDC (Para.) Eb = 90 Ec2 = 90 Ec1 = -4.5 G1-P Gm measured P pin 6 used
3Q5	1 of 1	2000	-	-	-	Ef = 1.4 VAC (Para.) Eb = 100 Ec2 = 100 Ec1 = -6.3 G1-P Gm measured P pin 2 used
3S4	1 of 1	1900	-	-	-	Ef = 1.4 VAC (Para.) Eb = 50 Ec2 = 50 Ec1 = -4.0 G1-P Gm measured
3V4	1 of 1	2500	-	-	-	Ef = 1.4 VDC (Para.) Eb = 90 Ec2 = 90 Ec1 = -4.5 G1-P Gm measured
4AU6	1 of 1	6300	-	-	20	Ef = 4.2 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 70 Ω G1-P Gm measured
4AV6	1 of 2	1600	-	-	20	Ef = 4.2 VAC Eb = 100 Ec1 = -1.0 Triode Gm measured

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
4AV6	2 of 2	-	0.6	-	20	Ef = 4.2 VAC Ebb = 20 Rl = 33,300 Ω Diode Ib measured Dual Test: 1st Diode: P pin 6 used 2nd Diode: P pin 5 used
4BA6	1 of 1	5400	-	-	20	Ef = 4.2 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Rk = 70 Ω G1-P Gm measured
4BC5	1 of 1	7000	-	-	20	Ef = 4.2 VAC Eb = 150 Ec2 = 150 Rk = 180 Ω G1-P Gm measured K pin 2 used
4BC8	1 of 1	7800	-	-	20	Ef = 4.2 VAC Eb = 150 Rk = 220 Ω Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
4BE6	1 of 2	600	-	-	20	Ef = 4.2 VAC Eb = 100 Ec2, 4 = 100 Ec1, 3 = -3.0 G3-P Gm measured
4BE6	2 of 2	8600	-	-	20	Ef = 4.2 VAC Eb = 100 Ec2, 4 = 100 Ec3 = 0 Ec1 = -1.0 G1-P, G2, G4 Gm measured
4BL8/ XCF80	1 of 2	7800	-	-	20	Ef = 4.6 VAC Eb = 150 Ec2 = 150 Ec1 = -1.7 Pent. G1-P Gm measured
4BL8/ XCF80	2 of 2	6300	-	-	20	Ef = 4.6 VAC Eb = 100 Ec = -2.0 Triode Gm measured
4BN6	1 of 2	1500	-	-	20	Ef = 4.2 VAC Eb = 50 Ec2, 3 = 50 Rk = 350 Ω G1-P Gm measured
4BN6	2 of 2	1500	-	-	20	Ef = 4.2 VAC Eb = 50 Ec1, 2 = 50 Rk = 150 Ω G3-P Gm measured
4BQ7A	1 of 1	8000	-	-	20	Ef = 4.2 VAC Eb = 150 Rk = 220 Ω Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
4BS8	1 of 1	9000	-	-	20	Ef = 4.5 VAC Eb = 150 Rk = 220 Ω Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
4BU8	1 of 2	-	2.4	-	20	Ef = 4.2 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -1.2 Ib measured P pin 8, G3 pin 9 used
4BU8	2 of 2	-	2.4	-	20	Ef = 4.2 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -1.2 Ib measured P pin 3, G3 pin 6 used
4BX8	1 of 1	6900	-	-	20	Ef = 4.5 VAC Eb = 50 Ec = -1.0 Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
4BZ6	1 of 1	7300	-	-	20	Ef = 4.2 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 180 Ω G1-P Gm measured
4BZ7	1 of 1	8600	-	-	20	Ef = 4.2 VAC Eb = 150 Rk = 220 Ω Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
4BZ8	1 of 1	8200	-	-	20	Ef = 4.2 VAC Eb = 150 Rk = 150 Ω Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
4CB6	1 of 1	7600	-	-	20	Ef = 4.2 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 180 Ω G1-P Gm measured
4CE5	1 of 1	7600	-	-	20	Ef = 4.2 VAC Eb = 150 Ec2 = 150 Rk = 180 Ω G1-P Gm measured
4CS6	1 of 2	1500	-	-	20	Ef = 4.2 VAC Eb = 50 Ec4, 2 = 50 Ec3 = 0 Ec1 = -1.5 G1-P Gm measured
4CS6	2 of 2	1500	-	-	20	Ef = 4.2 VAC Eb = 50 Ec4, 2 = 50 Ec3 = -1.0 Ec1 = 0 G3-P Gm measured
4CY5	1 of 1	10,000	-	-	20	Ef = 4.5 VAC Eb = 100 Ec2 = 100 Ec1 = -1.4 G1-P Gm measured
4DE6	1 of 1	7600	-	-	20	Ef = 4.2 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 180 Ω G1-P Gm measured
4DK6	1 of 1	11,100	-	-	20	Ef = 4.2 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 120 Ω G1-P Gm measured
4DT6	1 of 2	1000	-	-	20	Ef = 4.2 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Rk = 2100 Ω G1-P Gm measured
4DT6	2 of 2	600	-	-	20	Ef = 4.2 VAC Eb = 100 Ec1, 3 = -1.7 Ec2 = 100 G3-P Gm measured
4EH7/ YF183	1 of 2	15,700	-	-	20	Ef = 4.4 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -2.2 G1-P Gm measured K pin 3 used
4EH7/ YF183	2 of 2	-	14.1	-	20	Ef = 4.4 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -2.2 Ib measured K pin 1 used
4EJ7/ YF184	1 of 2	18,900	-	-	20	Ef = 4.4 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Ec1 = -1.8 G1-P Gm measured K pin 3 used
4EJ7/ YF184	2 of 2	-	12	-	20	Ef = 4.4 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Ec1 = -1.8 Ib measured K pin 1 used
4ES8/ XCC 189	1 of 1	15,800	-	-	10	Ef = 4.2 VAC Eb = 100 Ec = -1.5 Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
4EW6	1 of 1	17,600	-	-	20	Ef = 4.2 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 70 Ω G1-P Gm measured
4GK5	1 of 1	18,900	-	-	20	Ef = 4.2 VAC Eb = 150 Ec1 = -1.2 Gm measured K pin 7 used
4GS8	1 of 2	-	1.38	-	50	Ef = 4.2 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -1.5 Ib measured P pin 8, G3 pin 9 used

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
4GS8	2 of 2	-	1.38	-	50	Ef = 4.2 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -1.5 Ib measured P pin 3, G3 pin 6 used
4GW5	1 of 1	18,900	-	-	20	Ef = 4.2 VAC Eb = 150 Ec1 = -1.3 Gm measured
4GZ5	1 of 1	10,700	-	-	50	Ef = 4.0 VAC Eb = 150 Ec2 = 150 Rk = 190 Ω G1-P Gm measured G1 pin 5 used
4HA5/ PC900	1 of 1	15,400	-	-	20	Ef = 3.9 VAC Eb = 150 Ec1 = -1.4 Gm measured
4HS8	1 of 2	1200	-	-	20	Ef = 4.2 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -0.9 G1-P Gm measured Pins 1, 2, 7, 8, 9 used
4HS8	2 of 2	1200	-	-	20	Ef = 4.2 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -0.9 G1-P Gm measured Pins 1, 2, 3, 6, 7 used
4HT6	1 of 1	17,600	-	-	20	Ef = 4.2 VAC Eb = 150 Ec2 = 150 Rk = 90 Ω G1-P Gm measured K pin 1 used
4JD6	1 of 1	17,300	-	-	20	Ef = 4.5 VAC Eb = 100 Ec2 = 100 Rk = 40 Ω G1-P Gm measured
4KF8	1 of 2	1900	-	-	20	Ef = 4.2 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -0.9 G1-P Gm measured Pins 1, 2, 7, 8, 9 used
4KF8	2 of 2	1900	-	-	20	Ef = 4.2 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -0.9 G1-P Gm measured Pins 1, 2, 3, 6, 7 used
5A6	1 of 2	-	36	-	-	Ef = 2.5 VAC (Para.) Eb = 150 Ec3 = 0 Ec2 = 150 Ec1 = -10 Ib measured G3 pin 8 used
5A6	2 of 2	-	4.0	-	-	Ef = 2.5 VAC (Para.) Eb = 150 Ec3 = 0 Ec2 = 150 Ec1 = -25 Ib cut-off test OK under 2 MA G3 pin 3 used
5AM8	1 of 2	8500	-	-	20	Ef = 4.7 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 120 Ω Pent. G1-P Gm measured
5AM8	2 of 2	-	22	-	10	Ef = 4.7 VAC Ebb = 9.0 Rl = 115 Ω Diode Ib measured
5AN8	1 of 2	7600	-	-	20	Ef = 4.7 VAC Eb = 150 Ec2 = 150 Rk = 180 Ω Pent. G1-P Gm measured
5AN8	2 of 2	4100	-	-	20	Ef = 4.7 VAC Eb = 150 Ec1 = -4.4 Triode Gm measured
5AQ5	1 of 1	4700	-	-	50	Ef = 4.7 VAC Eb = 150 Ec2 = 150 Ec1 = -4.2 G1-P Gm measured G1 pin 1 used
5AR4/ GZ34	1 of 1	-	320	-	-	Ef = 5.0 VAC Epp = 250 VAC (F-W) Rl = 950 Ω Cl = 4 μf Io measured

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
5AS4	1 of 1	-	320	-	10	Ef = 5.0 VAC Epp = 250 VAC (F-W) Rl = 1030 Ω Cl = 4 μf Io measured
5AS8	1 of 2	7600	-	-	20	Ef = 4.7 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 180 Ω Pent. G1-P Gm measured
5AS8	2 of 2	-	26	-	10	Ef = 4.7 VAC Ebb = 9.0 Rl = 100 Ω Diode Ib measured
5AT8	1 of 2	5800	-	-	20	Ef = 4.7 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 200 Ω Pent. G1-P Gm measured
5AT8	2 of 2	7300	-	-	20	Ef = 4.7 VAC Eb = 100 Rk = 100 Ω Triode Gm measured
5AU4	1 of 1	-	320	-	-	Ef = 5.0 VAC Epp = 250 VAC (F-W) Rl = 1070 Ω Cl = 4 μf Io measured
5AV8	1 of 2	7600	-	-	20	Ef = 4.7 VAC Eb = 150 Ec2 = 150 Rk = 180 Ω Pent. G1-P Gm measured
5AV8	2 of 2	4100	-	-	20	Ef = 4.7 VAC Eb = 150 Ec1 = -4.4 Triode Gm measured
5AW4	1 of 1	-	320	-	-	Ef = 5.0 VAC Epp = 250 VAC (F-W) Rl = 970 Ω Cl = 4 μf Io measured
5AZ4	1 of 1	-	200	-	-	Ef = 5.0 VAC Epp = 250 VAC (F-W) Rl = 1500 Ω Cl = 4 μf Io measured
5B8	1 of 2	7600	-	-	20	Ef = 4.7 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 180 Ω Pent. G1-P Gm measured
5B8	2 of 2	4100	-	-	20	Ef = 4.7 VAC Eb = 150 Ec1 = -4.4 Triode Gm measured
5BC3	1 of 1	-	320	-	-	Ef = 5.0 VAC Epp = 250 VAC (F-W) Rl = 950 Ω Cl = 4 μf Io measured Hickok Adapter 1050-144 required
5BE8	1 of 2	5700	-	-	20	Ef = 4.7 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Rk = 70 Ω Pent. G1-P Gm measured
5BE8	2 of 2	10,700	-	-	20	Ef = 4.7 VAC Eb = 150 Rk = 60 Ω Triode Gm measured
5BK7A	1 of 1	11,700	-	-	20	Ef = 4.7 VAC Eb = 150 Rk = 60 Ω Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
5BQ7A	1 of 1	8000	-	-	20	Ef = 5.6 VAC Eb = 150 Rk = 220 Ω Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
5BR8	1 of 2	5700	-	-	20	Ef = 4.7 VAC Eb = 100 Ec2 = 100 Rk = 70 Ω Pent. G1-P Gm measured
5BR8	2 of 2	10,700	-	-	20	Ef = 4.7 VAC Eb = 150 Rk = 60 Ω Triode Gm measured

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
5BS8	1 of 1	9000	-	-	20	Ef = 5.6 VAC Eb = 150 Rk = 220 Ω Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
5BT8	1 of 2	7600	-	-	20	Ef = 4.7 VAC Eb = 150 Ec2 = 150 Rk = 180 Ω Pent. G1-P Gm measured
5BT8	2 of 2	-	4.1	-	10	Ef = 4.7 VAC Ebb = 9.0 Rl = 640 Ω Diode Ib measured Dual Test: 1st Diode: P pin 1 used 2nd Diode: P pin 2 used
5BW8	1 of 2	5700	-	-	20	Ef = 4.7 VAC Eb = 100 Ec2 = 100 Rk = 70 Ω Pent. G1-P Gm measured
5BW8	2 of 2	-	22	-	10	Ef = 4.7 VAC Ebb = 9.0 Rl = 115 Ω Diode Ib measured 1st Diode: P pin 3 used 2nd Diode: P pin 1 used
5BZ7	1 of 1	8600	-	-	20	Ef = 5.6 VAC Eb = 150 Rk = 220 Ω Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
5CG8	1 of 2	5800	-	-	20	Ef = 4.7 VAC Eb = 150 Ec2 = 150 Rk = 200 Ω Pent. G1-P Gm measured
5CG8	2 of 2	7300	-	-	20	Ef = 4.7 VAC Eb = 100 Rk = 100 Ω Triode Gm measured
5CL8	1 of 2	6000	-	-	20	Ef = 4.7 VAC Eb = 150 Ec2 = 150 Ec1 = -2.0 Pent. G1-P Gm measured
5CL8	2 of 2	6300	-	-	20	Ef = 4.7 VAC Eb = 150 Rk = 220 Ω Triode Gm measured
5CM6	1 of 1	4700	-	-	50	Ef = 4.7 VAC Eb = 150 Ec2 = 150 Ec1 = -4.2 G1-P Gm measured G1 pin 3 used
5CM8	1 of 2	7600	-	-	20	Ef = 4.7 VAC Eb = 150 Ec2 = 150 Rk = 180 Ω Pent. G1-P Gm measured
5CM8	2 of 2	2800	-	-	20	Ef = 4.7 VAC Eb = 150 Ec1 = -1.0 Triode Gm measured
5CQ8	1 of 2	5800	-	-	20	Ef = 4.7 VAC Eb = 150 Ec2 = 150 Ec1 = -2.5 Pent. G1-P Gm measured
5CQ8	2 of 2	8300	-	-	20	Ef = 4.7 VAC Eb = 150 Rk = 130 Ω Triode Gm measured
5CZ5	1 of 1	6000	-	-	50	Ef = 4.7 VAC Eb = 150 Ec2 = 150 Ec1 = -5.0 G1-P Gm measured
5DH8	1 of 2	8800	-	-	20	Ef = 5.2 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Rk = 100 Ω Pent. G1-P Gm measured
5DH8	2 of 2	5500	-	-	20	Ef = 5.2 VAC Eb = 150 Rk = 300 Ω Triode Gm measured
5DJ4	1 of 2	-	320	-	-	Ef = 5.0 VAC Epp = 250 VAC (F-W) Rl = 950 Ω C1 = 4 μf Io measured Pins 1, 4, 5, 8 used

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
5DJ4	2 of 2	-	320	-	-	Ef = 5.0 VAC Epp = 250 VAC (F-W) Rl = 950 Ω Cl = 4 μf Io measured Pins 2, 3, 6, 7 used
5EA8	1 of 2	6900	-	-	20	Ef = 4.7 VAC Eb = 100 Ec2 = 100 Ec1 = -1.0 Pent. G1-P Gm measured
5EA8	2 of 2	10,700	-	-	20	Ef = 4.7 VAC Eb = 150 Rk = 60 Ω Triode Gm measured
5EH8	1 of 2	6300	-	-	20	Ef = 4.7 VAC Eb = 100 Ec2 = 100 Ec1 = -1.0 Pent. G1-P Gm measured K pin 6 used
5EH8	2 of 2	9000	-	-	20	Ef = 4.7 VAC Eb = 150 Ec1 = -1.5 Triode Gm measured K pin 1 used
5ES8/ YCC 189	1 of 1	15,800	-	-	-	Ef = 5.6 VAC Eb = 100 Ec = -1.5 Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
5EU8	1 of 2	6900	-	-	20	Ef = 4.7 VAC Eb = 100 Ec2 = 100 Ec1 = -1.0 Pent. G1-P Gm measured
5EU8	2 of 2	10,700	-	-	20	Ef = 4.7 VAC Eb = 150 Rk = 60 Ω Triode Gm measured
5EW6	1 of 1	17,600	-	-	20	Ef = 5.6 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 70 Ω G1-P Gm measured
5FG7	1 of 2	6500	-	-	20	Ef = 4.7 VAC Eb = 100 Ec2 = 100 Ec1 = -1.0 Pent. G1-P Gm measured
5FG7	2 of 2	8500	-	-	20	Ef = 4.7 VAC Eb = 100 Ec1 = -1.0 Triode Gm measured
5FV8	1 of 2	6900	-	-	20	Ef = 4.7 VAC Eb = 100 Ec2 = 100 Ec1 = -1.0 Pent. G1-P Gm measured
5FV8	2 of 2	9000	-	-	20	Ef = 4.7 VAC Eb = 150 Ec1 = -1.5 Triode Gm measured
5GH8	1 of 2	7200	-	-	20	Ef = 4.7 VAC Eb = 100 Ec2 = 100 Ec1 = -1.0 Pent. G1-P Gm measured
5GH8	2 of 2	10,000	-	-	20	Ef = 4.7 VAC Eb = 150 Ec1 = -1.5 Triode Gm measured
5GM6	1 of 1	15,000	-	-	20	Ef = 5.6 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Rk = 60 Ω G1-P Gm measured
5GX6	1 of 1	4700	-	-	20	Ef = 4.7 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Rk = 170 Ω G1-P Gm measured
5HG8/ XCF86	1 of 2	15,000	-	-	20	Ef = 5.3 VAC Eb = 150 Ec2 = 150 Ec1 = -1.2 Pent. G1-P Gm measured K pin 3 used
5HG8/ XCF86	2 of 2	6900	-	-	20	Ef = 5.3 VAC Eb = 100 Ec1 = -3.0 Triode Gm measured K pin 1 used

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
5J6	1 of 1	6600	-	-	20	Ef = 4.7 VAC Eb = 100 Rk = 50 Ω Gm measured Dual Test: 1st Triode: pins 1, 6, 7 used 2nd Triode: pins 2, 5, 7 used
5KE8	1 of 2	12,300	-	-	20	Ef = 5.6 VAC Eb = 150 Ec2 = 150 Rk = 150 Ω Pent. G1-P Gm measured
5KE8	2 of 2	8400	-	-	20	Ef = 5.6 VAC Eb = 100 Rk = 140 Ω Triode Gm measured
5R4	1 of 1	-	320	-	-	Ef = 5.0 VAC Epp = 250 VAC (F-W) Rl = 950 Ω Cl = 4 μf Io measured
5T4	1 of 1	-	320	-	-	Ef = 5.0 VAC Epp = 250 VAC (F-W) Rl = 980 Ω Cl = 4 μf Io measured
5T8	1 of 3	1600	-	-	20	Ef = 4.7 VAC Eb = 100 Ec1 = -1.0 Triode Gm measured
5T8	2 of 3	-	22	-	10	Ef = 4.7 VAC Ebb = 9.0 Rl = 115 Ω Diode Ib measured Pins 6, 7 used
5T8	3 of 3	-	22	-	10	Ef = 4.7 VAC Ebb = 9.0 Rl = 115 Ω Diode Ib measured Dual Test: 1st Diode: pins 2, 3 used 2nd Diode: pins 1, 7 used
5U4	1 of 1	-	320	-	-	Ef = 5.0 VAC Epp = 250 VAC (F-W) Rl = 950 Ω Cl = 4 μf Io measured
5U8	1 of 2	5700	-	-	20	Ef = 4.7 VAC Eb = 100 Ec2 = 100 Rk = 70 Ω Pent. G1-P Gm measured
5U8	2 of 2	10,700	-	-	20	Ef = 4.7 VAC Eb = 150 Rk = 60 Ω Triode Gm measured
5V3	1 of 1	-	320	-	-	Ef = 5.0 VAC Epp = 250 VAC (F-W) Rl = 1070 Ω Cl = 4 μf Io measured
5V4	1 of 2	-	148	-	-	Ef = 5.0 VAC Epp = 500 VAC (H-W) Rl = 5500 Ω Cl = 4 μf Io measured P pin 6 used
5V4	2 of 2	-	148	-	-	Ef= 5.0 VAC Epp = 500 VAC (H-W) Rl = 5500 Ω Cl = 4 μf Io measured P pin 4 used
5V6	1 of 1	4700	-	-	50	Ef = 4.7 VAC Eb = 150 Ec2 = 150 Ec1 = -4.2 G1-P Gm measured
5W4	1 of 1	-	320	-	-	Ef = 5.0 VAC Epp = 250 VAC (F-W) Rl = 2300 Ω Cl = 4 μf Io measured
5X4	1 of 1	-	320	-	-	Ef = 5.0 VAC Epp = 250 VAC (F-W) Rl = 950 Ω Cl = 4 μf Io measured
5X8	1 of 2	5800	-	-	20	Ef = 4.7 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 200 Ω Pent. G1-P Gm measured
5X8	2 of 2	7300	-	-	20	Ef = 4.7 VAC Eb = 100 Rk = 100 Ω Triode Gm measured

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
5Y3	1 of 1	-	200	-	-	Ef = 5.0 VAC Epp = 250 VAC (F-W) Rl = 1700 Ω Cl = 4 μf Io measured
5Y4	1 of 1	-	200	-	-	Ef = 5.0 VAC Epp = 250 VAC (F-W) Rl = 1700 Ω Cl = 4 μf Io measured
5Z3	1 of 1	-	320	-	-	Ef = 5.0 VAC Epp = 250 VAC (F-W) Rl = 950 Ω Cl = 4 μf Io measured
5Z4	1 of 1	-	200	-	-	Ef = 5.0 VAC Epp = 250 VAC (F-W) Rl = 2000 Ω Cl = 4 μf Io measured
6A3	1 of 1	-	66	-	-	Ef = 6.3 VAC Eb = 150 Ec1 = -23 Ib measured
6A4	1 of 1	-	18	-	-	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -15 Ib measured
6A6	1 of 1	2100	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -2.0 Gm measured Dual Test: 1st Triode: pins 5 & 6 used 2nd Triode: pins 2 & 3 used
6A7	1 of 2	700	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2, 3, 5 = 100 Ec1, 4 = -5.8 G1, G4-P Gm measured
6A7	2 of 2	1800	-	-	20	Ef = 6.3 VAC Eb = 100 Ec4 = 0 Ec2, 3, 5 = 100 Ec1 = -7.6 G1-P, G3, G5 Gm measured
6A8	1 of 2	700	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2, 3, 5 = 100 Ec1, 4 = -5.8 G4-P Gm measured
6A8	2 of 2	1800	-	-	20	Ef = 6.3 VAC Eb = 100 Ec4 = 0 Ec2, 3, 5 = 100 Ec1 = -7.6 G1-P, G3, G5 Gm measured
6AB4	1 of 1	5000	-	-	20	Ef = 6.3 VAC Eb = 100 Rk = 270 Ω Gm measured
6AB5	1 of 2	-	-	-	20	Ef = 6.3 VAC E (Screen) = 150 E (Target) = 150 Ec1 = 0 (Eye Shut) Quality Test: No Meter Reading
6AB5	2 of 2	-	-	-	20	Ef = 6.3 VAC E (Screen) = 0 E (Target) = 150 Ec1 = 0 (Eye Open) Quality Test: No Meter Reading
6AB7	1 of 1	6300	-	-	20	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Ec1 = -1.5 G1-P Gm measured
6AB8/ ECL80	1 of 2	4000	-	-	20	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Ec1 = -5.3 Pent. G1-P Gm measured
6AB8/ ECL80	2 of 2	2300	-	-	20	Ef = 6.3 VAC Eb = 100 Ec1 = -1.0 Triode Gm measured
6AC5	1 of 1	-	78	-	50	Ef = 6.3 VAC Eb = 50 Ec1 = +50 Rl = 260 Ω Ib measured
6AC7	1 of 1	11,300	-	-	20	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 160 Ω G1-P Gm measured
6AD4	1 of 1	2500	-	-	20	Ef = 6.3 VAC Eb = 100 Rk = 820 Ω Gm measured

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
6AD7	1 of 2	3500	-	-	70	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -3.2 Pent. G1-P Gm measured
6AD7	2 of 2	500	-	-	70	Ef = 6.3 VAC Eb = 150 Ec1 = -9.0 Triode Gm measured
6AF3	1 of 1	-	148	-	10	Ef = 6.3 VAC Epp = 500 VAC (H-W) Rl = 5100 Ω Cl = 4 μf Io measured
6AF4	1 of 1	6800	-	-	20	Ef = 6.3 VAC Eb = 100 Rk = 270 Ω Gm measured
6AF6	1 of 2	-	-	-	20	Ef = 6.3 VAC Eb = 100 E (Deflect) 1, 2 = open ckt Eye Open Quality Test: No Meter Reading
6AF6	2 of 2	-	-	-	20	Ef = 6.3 VAC Eb = 100 E (Deflect) 1, 2 = 100 Eye Shut Quality Test: No Meter Reading
6AG5	1 of 1	6000	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Rk = 180 Ω G1-P Gm measured K pin 2 used
6AG7	1 of 1	14,000	-	-	50	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Ec1 = -3.0 G1-P Gm measured
6AH4	1 of 1	7500	-	-	50	Ef = 6.3 VAC Eb = 150 Ec1 = -12.4 Gm measured
6AH6	1 of 1	11,300	-	-	20	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 160 Ω G1-P Gm measured
6AH7	1 of 1	2000	-	-	20	Ef = 6.3 VAC Eb = 100 Ec1 = -3.6 Gm measured Dual Test: 1st Triode: pins 4, 5, 6 used 2nd Triode: pins 1, 2, 3 used
6AJ4	1 of 1	11,300	-	-	20	Ef = 6.3 VAC Eb = 100 Rk = 90 Ω Gm measured G1-P pin 1 used
6AJ5	1 of 2	3500	-	-	20	Ef = 6.3 VAC Eb = 50 Ec3 = 0 Ec2 = 50 Rk = 410 Ω G1-P Gm measured K pin 7 used
6AJ5	2 of 2	3500	-	-	20	Ef = 6.3 VAC Eb = 50 Ec3 = 0 Ec2 = 50 Rk = 410 Ω G1-P Gm measured K pin 2 used
6AJ8/ ECH81	1 of 2	2600	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2, 4 = 150 Ec3 = 0 Ec1 = -4.0 G1-P Gm measured Heptode pins 1, 2, 3, 6, 7 used
6AJ8/ ECH81	2 of 2	4000	-	-	20	Ef = 6.3 VAC Eb = 100 Ec1 = -1.0 Triode Gm measured Pins 3, 8, 9 used
6AK5	1 of 1	6300	-	-	20	Ef = 6.3 VAC Eb = 120 Ec2 = 120 Ec1 = -2.0 G1-P Gm measured K pin 2 used
6AK6	1 of 1	2800	-	-	20	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Ec1 = -5.5 G1-P Gm measured

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
6AK8/ EABC80	1 of 3	1800	-	-	20	Ef = 6.3 VAC Eb = 100 Ec1 = -1.0 Triode Gm measured
6AK8/ EABC80	2 of 3	-	0.54	-	10	Ef = 6.3 VAC Ebb = 9.0 Rl = 11,100 Ω Diode Ib measured Pins 6 & 7 used
6AK8/ EABC80	3 of 3	-	44	-	10	Ef = 6.3 VAC Ebb = 9.0 Rl = 55 Ω Diode Ib measured Dual Test: 1st Diode: pins 2 & 3 used 2nd Diode: pins 1 & 7 used
6AL3/ EY88	1 of 1	-	148	-	10	Ef = 6.3 VAC Epp = 500 VAC (H-W) Rl = 5300 Ω Cl = 4 μf Io measured
6AL5	1 of 1	-	26	-	10	Ef = 6.3 VAC Ebb = 6.0 Rl = 100 Ω Ib measured Dual Test: 1st Diode: pins 1 & 7 used 2nd Diode: pins 2 & 5 used
6AL7	1 of 2	-	-	-	20	Ef = 6.3 VAC E (Target) = 250 VAC E (Deflect) 1, 2, 3 = 9.0 Ec1 = 0 Target Bright No Meter Reading
6AL7	2 of 2	-	-	-	20	Ef = 6.3 VAC E (Target) = 250 VAC E (Deflect) 1, 2, 3 = 0 Ec1 = -4.0 Target Dim No Meter Reading
6AM4	1 of 1	11,300	-	-	20	Ef = 6.3 VAC Eb = 150 Rk = 100 Ω Gm measured G pin 1 used
6AM5/ EL91	1 of 1	3300	-	-	20	Ef = 6.3 VAC Eb = 250 Ec2 = 250 Ec1 = -13.5 G1-P Gm measured
6AM8	1 of 2	8500	-	-	20	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 120 Ω Pent. G1-P Gm measured
6AM8	2 of 2	-	22	-	10	Ef = 6.3 VAC Ebb = 9.0 Rl = 116 Ω Diode Ib measured
6AN4	1 of 1	12,600	-	-	20	Ef = 6.3 VAC Eb = 150 Rk = 90 Ω Gm measured P pin 1 used G pin 2 used
6AN5	1 of 1	10,700	-	-	50	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Rk = 70 Ω G1-P Gm measured
6AN6	1 of 2	-	6.1	-	20	Ef = 6.3 VAC Ebb = 50 Rl = 11,520 Ω Ib measured Dual Test: 1st Diode: P pin 5 used 2nd Diode: P pin 3 used
6AN6	2 of 2		6.1	-	20	Ef = 6.3 VAC Ebb = 50 Rl = 11,520 Ω Ib measured Dual Test: 1st Diode: P pin 4 used 2nd Diode: P pin 2 used
6AN8	1 of 2	7600	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Rk = 180 Ω Pent. Gm measured
6AN8	2 of 2	4100	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -4.4 Triode Gm measured
6AQ4/ EC91	1 of 2	8200	-	-	20	Ef = 6.3 VAC Eb = 150 Rk = 200 Ω Gm measured Pins 5, 6, 7 used
6AQ4/ EC91	2 of 2	8200	-	-	20	Ef = 6.3 VAC Eb = 150 Rk = 200 Ω Gm measured Pins 1, 2, 7 used

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
6AQ5	1 of 1	4700	-	-	50	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Ec1 = -4.2 G1-P Gm measured G pin 1 used
6AQ6	1 of 2	1400	-	-	20	Ef = 6.3 VAC Eb = 100 Ec1 = -1.0 Triode Gm measured
6AQ6	2 of 2	-	0.6	-	20	Ef = 6.3 VAC Ebb = 20 R1 = 33,300 Ω Diode Ib measured Dual Test: 1st Diode: P pin 6 used 2nd Diode: P pin 5 used
6AQ7	1 of 2	1900	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -1.0 Triode Gm measured
6AQ7	2 of 2	-	1.2	-	20	Ef = 6.3 VAC Ebb = 20 R1 = 16,700 Ω Diode Ib measured Dual Test: 1st Diode: pins 3 & 2 used 2nd Diode: pins 1 & 2 used
6AQ8/ ECC85	1 of 1	5000	-	-	20	Ef = 6.3 VAC Eb = 100 Ec1 = -1.0 Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
6AR5	1 of 1	1900	-	-	20	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -7.0 G1-P Gm measured
6AR6	1 of 1	6700	-	-	70	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -10 G1-P Gm measured
6AR8	1 of 3	4400	-	-	20	Ef = 6.3 VAC Eb = 150 E (Deflector) = 0 E (Accelerator) = 150 Rk = 300 Ω G1-P Gm measured Pins 1, 2 jumpered Pins 8, 9 jumpered
6AR8	2 of 3	-	3.0	-	20	Ef = 6.3 VAC Eb = 150 E (Deflector No. 2) = 0 E (Deflector No. 1) = -50 Ec1 = -1.0 I (Plate No. 1) measured OK under 1.5 MA
6AR8	3 of 3	-	3.0	-	20	Ef = 6.3 VAC Eb = 150 E (Deflector No. 1) = 0 E (Deflector No. 2) = -50 Ec1 = -1.0 I (Plate No. 2) measured OK under 1.5 MA
6AS5	1 of 1	7000	-	-	50	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -6.5 G1-P Gm measured
6AS6	1 of 2	4500	-	-	20	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -1.0 G1-P Gm measured
6AS6	2 of 2	1130	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1, 3 = -1.0 G1, G3-P Gm measured OK over 340 μmhos
6AS7	1 of 1	8300	-	-	100	Ef = 6.3 VAC Eb = 150 Rk = 370 Ω Gm measured Dual Test: 1st Triode: pins 4, 5, 6 used 2nd Triode: pins 1, 2, 3 used

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
6AS8	1 of 2	7600	-	-	20	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 180 Ω Pent. Gm measured
6AS8	2 of 2	-	26	-	10	Ef = 6.3 VAC Ebb = 9.0 Rl = 100 Ω Diode Ib measured
6AT6	1 of 2	1700	-	-	20	Ef = 6.3 VAC Eb = 100 Ec1 = -1.0 Triode Gm measured
6AT6	2 of 2	-	0.6	-	20	Ef = 6.3 VAC Ebb = 20 Rl = 33,300 Ω Diode Ib measured Dual Test: 1st Diode: P pin 6 used 2nd Diode: P pin 5 used
6AT8	1 of 2	5800	-	-	20	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 200 Ω Pent. G1-P Gm measured
6AT8	2 of 2	7300	-	-	20	Ef = 6.3 VAC Eb = 100 Rk = 100 Ω Triode Gm measured
6AU4	1 of 1	-	148	-	10	Ef = 6.3 VAC Epp = 250 VAC (H-W) Rl = 5800 Ω Cl = 4 μf Io measured
6AU5	1 of 2	7000	-	-	100	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Ec1 = -16 G1-P Gm measured
6AU5	2 of 2	-	294	-	100	Ef = 6.3 VAC Ebb = 234 Rl = 830 Ω Ec3 = 0 Ec2 = 150 Ec1 = 0 Ib measured
6AU6	1 of 1	6300	-	-	20	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 70 Ω G1-P Gm measured
6AU7	1 of 1	3800	-	-	20	Ef = 3.1 (Para.) Eb = 150 Ec1 = -3.0 Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
6AU8	1 of 2	8800	-	-	20	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Rk = 60 Ω Pent. G1-P Gm measured
6AU8	2 of 2	6200	-	-	20	Ef = 6.3 VAC Eb = 150 Rk = 150 Ω Triode Gm measured
6AV5	1 of 2	6900	-	-	100	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Ec1 = -21 G1-P Gm measured
6AV5	2 of 2	-	316	-	100	Ef = 6.3 VAC Ebb = 230 Rl = 750 Ω Ec3 = 0 Ec2 = 150 Ec1 = 0 Ib measured
6AV6	1 of 2	1600	-	-	20	Ef = 6.3 VAC Eb = 100 Ec1 = -1.0 Triode Gm measured
6AV6	2 of 2	-	0.6	-	20	Ef = 6.3 VAC Ebb = 20 Rl = 33,300 Ω Diode Ib measured Dual Test: 1st Diode: P pin 6 used 2nd Diode: P pin 5 used
6AW8A	1 of 2	11,300	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Rk = 180 Ω Pent. G1-P Gm measured

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
6AW8A	2 of 2	6300	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -1.2 Triode Gm measured
6AX4	1 of 1	-	148	-	10	Ef = 6.3 VAC Epp = 250 VAC (H-W) Rl = 5500 Ω Cl = 4 μf Io measured
6AX5	1 of 1	-	200	-	150	Ef = 6.3 VAC Epp = 250 VAC (F-W) Rl = 1700 Ω Cl = 4 μf Io measured
6AX7	1 of 1	1600	-	-	20	Ef = 3.2 VAC (Para.) Eb = 100 Ec = -1.0 Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
6AX8	1 of 2	5000	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Rk = 70 Ω Pent. G1-P Gm measured
6AX8	2 of 2	10,700	-	-	20	Ef = 6.3 VAC Eb = 150 Rk = 60 Ω Triode Gm measured
6AY3	1 of 1	-	148	-	10	Ef = 6.3 VAC Epp = 500 VAC (H-W) Rl = 5500 Ω Cl = 4 μf Io measured Hickok Adapter 1050-144 required
6AZ8	1 of 2	7300	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Rk = 180 Ω Pent. G1-P Gm measured
6AZ8	2 of 2	4100	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -4.4 Triode Gm measured
6B4	1 of 1	-	66	-	-	Ef = 6.3 VAC Eb = 150 Ec1 = -23 Ib measured
6B6	1 of 2	1200	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -1.0 Triode Gm measured
6B6	2 of 2	-	0.6	-	20	Ef = 6.3 VAC Ebb = 20 Rl = 33,300 Ω Diode Ib measured Dual Test: 1st Diode: P pin 5 used 2nd Diode: P pin 4 used
6B7	1 of 2	1200	-	-	20	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -3.0 Pent. G1-P Gm measured
6B7	2 of 2	-	0.6	-	20	Ef = 6.3 VAC Ebb = 20 Rl = 33,300 Ω Diode Ib measured Dual Test: 1st Diode: P pin 5 used 2nd Diode: P pin 4 used
6B8	1 of 2	1200	-	-	20	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -3.0 Pent. G1-P Gm measured Pins 3, 6, 8, cap used
6B8	2 of 2	-	0.6	-	20	Ef = 6.3 VAC Ebb = 20 Rl = 33,300 Ω Diode Ib measured Dual Test: 1st Diode: P pin 5 used 2nd Diode: P pin 4 used
6BA3	1 of 1	-	148	-	10	Ef = 6.3 VAC Epp = 500 VAC (H-W) Rl = 5400 Ω Cl = 4 μf Io measured
6BA5	1 of 1	2700	-	-	20	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Rk = 270 Ω G1-P Gm measured

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
6BA6	1 of 1	5400	-	-	20	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Rk = 70 Ω G1-P Gm measured
6BA7	1 of 2	2200	-	-	20	Ef = 6.3 VAC Eb = 100 Ec5 = 0 Ec2, 4 = 100 Ec1, 3 = -1.0 G3-P Gm measured
6BA7	2 of 2	8800	-	-	20	Ef = 6.3 VAC Eb = 100 Ec3, 5 = 0 Ec2, 4 = 100 Ec1 = -1.0 G1-P, G2, G4 Gm measured
6BA8	1 of 2	10,700	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Rk = 180 Ω Pent. G1-P Gm measured
6BA8	2 of 2	3800	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -5.0 Triode Gm measured
6BC4	1 of 1	12,600	-	-	20	Ef = 6.3 VAC Eb = 150 Rk = 100 Ω Gm measured Pins 1, 2, 6 used
6BC5	1 of 1	7000	-	-	20	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 180 Ω G1-P Gm measured K pin 2 used
6BC7	1 of 2	-	38	-	10	Ef = 6.3 VAC Ebb = 9.0 Rl = 90 Ω Ib measured Diode pins 8 & 9 used
6BC7	2 of 2	-	38	-	10	Ef = 6.3 VAC Ebb = 9.0 Rl = 90 Ω Ib measured Dual Test: 1st Diode: pins 6 & 7 used 2nd Diode: pins 1 & 2 used
6BC8	1 of 1	7800	-	-	20	Ef = 6.3 VAC Eb = 150 Rk = 220 Ω Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
6BD4	1 of 1	-	1.52	-	20	Ef = 6.3 VAC Ebb = 9.0 Rl = 3700 Ω Ib measured
6BD5	1 of 2	6300	-	-	100	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -8.0 G1-P Gm measured
6BD5	2 of 2	-	106	-	100	Ef =6. 3 VAC Ebb = 289 Rl = 3300 Ω Ec2 = 150 Ec1 = 0 Ib measured
6BD6	1 of 1	3200	-	-	20	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -1.0 G1-P Gm measured
6BD7A EBC81	1 of 2	1600	-	-	20	Ef = 6.3 VAC Eb = 100 Ec1 = -1.0 Triode Gm measured
6BD7A EBC81	2 of 2	-	0.28	-	20	Ef = 6.3 VAC Ebb = 10 Rl = 35,560 Ω Diode Ib measured Dual Test: 1st Diode: P pin 8 used 2nd Diode: P pin 6 used
6BE6	1 of 2	600	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2, 4 = 100 Ec1, 3 = -3.1 G3-P Gm measured
6BE6	2 of 2	8600	-	-	20	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2, 4 = 100 Ec1 = -1.0 G1-P, G2, G4 Gm measured

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
6BE7/ EQ80	1 of 2	900	-	-	20	Ef = 6.3 VAC Eb = 50 Ec2, 4, 6 = 50 Ec3, 5 = 0 Rk = 280 Ω G1-P Gm measured K pin 8 used
6BE7/ EQ80	2 of 2	3600	-	-	20	Ef = 6.3 VAC Eb = 50 Ec2, 3, 4, 5, 6 = 50 Rk = 280 Ω G1-G2, 3, 4, 5, 6 Gm measured K pin 3 used
6BE8	1 of 2	5700	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Rk = 70 Ω Pent. G1-P Gm measured
6BE8	2 of 2	10,700	-	-	20	Ef = 6.3 VAC Eb = 150 Rk = 60 Ω Triode Gm measured
6BF5	1 of 1	10,000	-	-	70	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -6.2 G1-P Gm measured
6BF6	1 of 2	2500	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -3.0 Triode Gm measured
6BF6	2 of 2	-	0.6	-	20	Ef = 6.3 VAC Ebb = 20 Rl = 33,300 Ω Diode Ib measured Dual Test: 1st Diode: P pin 6 used 2nd Diode: P pin 5 used
6BF7W	1 of 1	6300	-	-	10	Ef = 6.3 VAC Eb = 100 Rk = 100 Ω Gm measured Dual Test: 1st Triode: pins 5, 7, 8 used 2nd Triode: pins 1, 2, 4 used
6BF8	1 of 3	-	10	-	20	Ef = 6.3 VAC Ebb = 10 Rl = 1003 Ω Diode Ib measured Dual Test: 1st Diode: P pin 9 used 2nd Diode: P pin 3 used
6BF8	2 of 3	-	10	-	20	Ef = 6.3 VAC Ebb = 10 Rl = 1003 Ω Diode Ib measured Dual Test: 1st Diode: P pin 8 used 2nd Diode: P pin 2 used
6BF8	3 of 3	-	10	-	20	Ef = 6.3 VAC Ebb = 10 Rl = 1003 Ω Diode Ib measured Dual Test: 1st Diode: P pin 7 used 2nd Diode: P pin 1 used
6BG6	1 of 2	8800	-	-	100	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Ec1 = -1.9 G1-P Gm measured
6BG6	2 of 2	-	126	-	100	Ef = 6.3 VAC Ebb = 285 Rl = 2610 Ω Ec3 = 0 Ec2 = 150 Ec1 = 0 Ib measured
6BG7	1 of 1	6300	-	-	10	Ef = 6.3 VAC Eb = 100 Rk = 100 Ω Gm measured Dual Test: 1st Triode: pins 5, 7, 8 used 2nd Triode: pins 1, 2, 4 used
6BH3	1 of 1	-	148	-	10	Ef = 6.3 VAC Epp = 500 VAC (H-W) Rl = 5500 Ω Cl = 4 μf Io measured Hickok Adapter 1050-144 required

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
6BH6	1 of 1	4300	-	-	20	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -1.0 G1-P Gm measured
6BH8	1 of 2	8800	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Rk = 60 Ω Pent. G1-P Gm measured
6BH8	2 of 2	4100	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -5.0 Triode Gm measured
6BJ5/ N78	1 of 1	12,600	-	-	50	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Rk = 100 Ω G1-P Gm measured
6BJ6	1 of 1	4600	-	-	20	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -1.0 G1-P Gm measured
6BJ7	1 of 2	-	24	-	10	Ef = 6.3 VAC Eb = 9.0 Diode Ib measured P pin 8 used K pin 9 used
6BJ7	2 of 2	-	24	-	10	Ef = 6.3 VAC Eb = 9.0 Diode Ib measured Dual Test: 1st Diode: pins 6 & 7 used 2nd Diode: pins 1 & 2 used
6BJ8	1 of 2	5900	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -1.5 Triode Gm measured
6BJ8	2 of 2	-	26	-	20	Ef = 6.3 VAC Ebb = 9.0 Rl = 198 Ω Diode Ib measured Dual Test: 1st Diode: pins 3 & 6 used 2nd Diode: pins 1 & 2 used
6BK4	1 of 1	-	1.3	-	10	Ef = 6.3 VAC Eb = 0 Ec1 = +9.0 Rk = 7000 Ω Ik measured
6BK5	1 of 1	10,000	-	-	70	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -1.0 G1-P Gm measured
6BK6	1 of 2	1600	-	-	20	Ef = 6.3 VAC Eb = 100 Ec1 = -1.0 Triode Gm measured
6BK6	2 of 2	-	1.2	-	20	Ef = 6.3 VAC Ebb = 20 Rl = 16,700 Ω Diode Ib measured Dual Test: 1st Diode: P pin 6 used 2nd Diode: P pin 5 used
6BK7A	1 of 1	11,700	-	-	20	Ef = 6.3 VAC Eb = 150 Rk = 60 Ω Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
6BL4	1 of 1	-	148	-	10	Ef = 6.3 VAC Epp = 500 VAC (H-W) Rl = 5800 Ω Cl = 4 μf Io measured
6BL7	1 of 1	12,600	-	-	50	Ef = 6.3 VAC Eb = 150 Ec1 = -2.3 Gm measured Dual Test: 1st Triode: pins 4, 5, 6 used 2nd Triode: pins 1, 2, 3 used
6BL8/ ECF80	1 of 2	7800	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -1.7 Pent. G1-P Gm measured

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
6BL8/ ECF80	2 of 2	6300	-	-	20	Ef = 6.3 VAC Eb = 100 Ec1 = -2.0 Triode Gm measured
6BM8/ ECL82	1 of 2	8600	-	-	50	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -6.0 Pent. G1-P Gm measured
6BM8/ ECL82	2 of 2	3200	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -1.2 Triode Gm measured
6BN4	1 of 1	8600	-	-	20	Ef = 6.3 VAC Eb = 150 Rk = 220 Ω Gm measured Pins 1, 2, 5 used
6BN5/ EL85	1 of 1	4000	-	-	50	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -6.3 G1-P Gm measured
6BN6	1 of 2	1500	-	-	20	Ef = 6.3 VAC Eb = 50 Ec2, 3 = 50 Rk = 350 Ω G1-P Gm measured
6BN6	2 of 2	1500	-	-	20	Ef = 6.3 VAC Eb = 50 Ec1, 2 = 50 Rk = 150 Ω G3-P Gm measured
6BN8	1 of 2	4400	-	-	20	Ef = 6.3 VAC Eb = 100 Ec1 = -1.0 Triode Gm measured
6BN8	2 of 2	-	22	-	10	Ef = 6.3 VAC Ebb = 9.0 Rl = 115 Ω Diode Ib measured Dual Test: 1st Diode: pins 3 & 6 used 2nd Diode: pins 1 & 2 used
6BQ5/ EL84	1 of 1	14,200	-	-	70	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -2.0 G1-P Gm measured
6BQ6	1 of 2	6900	-	-	100	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -21 G1-P Gm measured
6BQ6	2 of 2	-	316	-	100	Ef = 6.3 VAC Ebb = 230 Rl = 750 Ω Ec2 = 150 Ec1 = 0 Ib measured
6BQ7A	1 of 1	8000	-	-	20	Ef = 6.3 VAC Eb = 150 Rk = 220 Ω Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
6BR5/ EM80	1 of 2	-	-	-	20	Ef = 6.3 VAC E (Screen) = 150 E (Target) = 150 Ec1 = -3.0 (Bright) Quality Test: No Meter Reading
6BR5/ EM80	2 of 2	-	-	-	20	Ef = 6.3 VAC E (Screen) = 0 E (Target) = 150 Ec1 = -28 (Dim) Quality Test: No Meter Reading
6BR7	1 of 1	1400	-	-	20	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -3.0 G1-P Gm measured
6BR8	1 of 2	5700	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Rk = 70 Ω Pent. G1-P Gm measured
6BR8	2 of 2	10,700	-	-	20	Ef = 6.3 VAC Eb = 150 Rk = 60 Ω Triode Gm measured
6BS3	1 of 1	-	148	-	10	Ef = 6.3 VAC Epp = 500 VAC (F-W) Rl = 6100 Ω Ib measured Hickok Adapter 1050-144 required

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
6BS7	1 of 1	1400	-	-	20	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -3.0 G1-P Gm measured
6BS8	1 of 1	9000	-	-	20	Ef = 6.3 VAC Eb = 150 Rk = 220 Ω Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
6BT6	1 of 2	1700	-	-	20	Ef = 6.3 VAC Eb = 100 Ec1 = -1.0 Triode Gm measured
6BT6	2 of 2	-	1.2	-	20	Ef = 6.3 VAC Ebb = 20 Rl = 16,700 Ω Diode Ib measured Dual Test: 1st Diode: P pin 6 used 2nd Diode: P pin 5 used
6BT8	1 of 2	7600	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Rk = 180 Ω Pent. G1-P Gm measured
6BT8	2 of 2	-	4.1	-	10	Ef = 6.3 VAC Ebb = 9.0 Rl = 640 Ω Diode Ib measured Dual Test: 1st Diode: P pin 1 used 2nd Diode: P pin 2 used
6BU8	1 of 2	-	2.4	-	20	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -1.2 Ib measured P pin 8, G3 pin 9 used
6BU8	2 of 2	-	2.4	-	20	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -1.2 Ib measured P pin 3, G3 pin 6 used
6BV8	1 of 2	10,300	-	-	20	Ef = 6.3 VAC Eb = 150 Rk = 110 Ω Triode Gm measured
6BV8	2 of 2	-	26	-	10	Ef = 6.3 VAC Eb = 9.0 Diode Ib measured Dual Test: 1st Diode: pins 7 & 9 used 2nd Diode: pins 6 & 8 used
6BW4	1 of 1	-	160	-	150	Ef = 6.3 VAC Epp = 250 (F-W) Rl = 2400 Ω Cl = 4 μf Io measured
6BW6/ 6061	1 of 1	4700	-	-	50	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -4.2 G1-P Gm measured
6BW8	1 of 2	5700	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Rk = 70 Ω Pent. G1-P Gm measured
6BW8	2 of 2	-	22	-	10	Ef = 6.3 VAC Ebb = 9.0 Rl = 115 Ω Diode Ib measured Dual Test: 1st Diode: P pin 3 used 2nd Diode: P pin 1 used
6BX6/ EF80	1 of 2	9300	-	-	20	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Ec1 = -1.7 G1-P Gm measured K pin 3 used
6BX6/ EF80	2 of 2	9300	-	-	20	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Ec1 = -1.7 G1-P Gm measured K pin 1 used

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
6BX7	1 of 2	15,800	-	-	50	Ef = 6.3 VAC Eb = 150 Rk = 70 Ω Gm measured Dual Test: 1st Triode: pins 4, 5, 6 used 2nd Triode: pins 1, 2, 3 used
6BX7	2 of 2	-	128	-	50	Ef = 6.3 VAC Eb = 100 Ec1 = 0 Ib measured Dual Test: 1st Triode: pins 4, 5, 6 used 2nd Triode: pins 1, 2, 3 used
6BX8	1 of 1	6900	-	-	20	Ef = 6.3 VAC Eb = 50 Ec1 = -1.0 Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
6BY5	1 of 2	-	148	-	10	Ef = 6.3 VAC Epp = 500 VAC (H-W) Rl = 5500 Ω Cl = 4 μf Io measured Pins 5, 8 used
6BY5	2 of 2	-	148	-	10	Ef = 6.3 VAC Epp = 500 VAC (H-W) Rl = 5500 Ω Cl = 4 μf Io measured Pins 1, 4 used
6BY6	1 of 2	2100	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1, 3 = -2.5 G1-P Gm measured
6BY6	2 of 2	600	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1, 3 = -2.5 G3-P Gm measured
6BY7/ EF85	1 of 1	7500	-	-	20	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -1.7 G1-P Gm measured K pin 1 used
6BY8	1 of 2	6300	-	-	20	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 70 Ω Pent. G1-P Gm measured
6BY8	2 of 2	-	26	-	10	Ef = 6.3 VAC Ebb = 9.0 Rl = 100 Ω Diode Ib measured
6BZ6	1 of 1	7300	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Rk = 180 Ω G1-P Gm measured
6BZ7	1 of 1	8600	-	-	20	Ef = 6.3 VAC Eb = 150 Rk = 220 Ω Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
6BZ8	1 of 1	8200	-	-	20	Ef = 6.3 VAC Eb = 150 Rk = 150 Ω Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
6C4	1 of 1	3800	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -3.0 Gm measured
6C5	1 of 1	2500	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -3.5 Gm measured
6C6	1 of 1	1500	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -3.0 G1-P Gm measured
6C8	1 of 1	2000	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -2.0 Gm measured Dual Test: 1st Triode: pins 5, 6, 8 used 2nd Triode: pins 3, 4, cap used
6CA4/ EZ81	1 of 1	-	240	-	150	Ef = 6.3 VAC Epp = 250 VAC (F-W) R1 = 1700 Ω C1 = 4 μf Io measured

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
6CA5	1 of 1	10,000	-	-	70	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -3.2 G1-P Gm measured G1 pin 2 used
6CA7/ EL34	1 of 1	11,300	-	-	70	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Ec1 = -8.0 G1-P Gm measured
6CB5	1 of 2	11,000	-	-	100	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = 23 G1-P Gm measured
6CB5	2 of 2	-	350	-	100	Ef = 6.3 VAC Ebb = 215 Rl = 680 Ω Ec2 = 100 Ec1 = 0 Ib measured
6CB6	1 of 1	7600	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Rk = 180 Ω G1-P Gm measured
6CD6	1 of 2	10,700	-	-	100	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -24 G1-P Gm measured
6CD6	2 of 2	-	316	-	100	Ef = 6.3 VAC Ebb = 231 Rl = 760 Ω Ec2 = 100 Ec1 = 0 Ib measured
6CD7/ EM34	1 of 3	-	-	-	20	Ef = 6.3 VAC E (Deflectors) = 0 E (Target) = 150 Ec1 = 0 (Eyes Open) Quality Test: No Meter Reading
6CD7/ EM34	2 of 3	-	-	-	20	Ef = 6.3 VAC E (Deflector No. 1) = 150 E (Deflector No. 2) = 0 E (Target) = 150 Ec1 = -64 (Eye No. 1 open) Quality Test: No Meter Reading
6CD7/ EM34	3 of 3	-	-	-	20	Ef = 6.3 VAC E (Deflector No. 2) = 150 E (Deflector No. 1) = 0 E (Target) = 150 Ec1 = -64 (Eye No. 2 Open) Quality Test: No Meter Reading
6CE5	1 of 1	7600	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Rk = 180 Ω G1-P Gm measured
6CF6	1 of 1	7600	-	-	20	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 180 Ω G1-P Gm measured
6CG7	1 of 1	3500	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -2.9 Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
6CG8	1 of 2	5800	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Rk = 200 Ω Pent. G1-P Gm measured
6CG8	2 of 2	7300	-	-	20	Ef = 6.3 VAC Eb = 100 Rk = 100 Ω Triode Gm measured
6CH6/ 6132	1 of 1	14,000	-	-	20	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Ec1 = -1.0 G1-P Gm measured
6CH7	1 of 1	8600	-	-	20	Ef = 6.3 VAC Eb = 150 Rk = 220 Ω Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
6CH8	1 of 2	7600	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Rk = 180 Ω Pent. G1-P Gm measured
6CH8	2 of 2	4100	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -4.2 Triode Gm measured
6CJ6/ EL81	1 of 2	7800	-	-	100	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Ec1 = -18.5 G1-P Gm measured
6CJ6/ EL81	2 of 2	-	224	-	100	Ef = 6.3 VAC Ebb = 255 Rl = 1350 Ω Ec3 = 0 Ec2 = 100 Ec1 = 0 Ib measured
6CK4	1 of 2	6900	-	-	100	Ef = 6.3 VAC Eb = 150 Ec = -15 Gm measured G1 pin 3 used
6CK4	2 of 2	-	200	-	100	Ef = 6.3 VAC Ebb = 275 Rl = 1400 Ω Ec1 = 0 Ib measured G1 pin 1 used
6CK6/ EL83	1 of 1	12,600	-	-	50	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Ec1 = -1.0 G1-P Gm measured
6CL5	1 of 2	8200	-	-	100	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -33 G1-P Gm measured Pins 5, 6, 8 used
6CL5	2 of 2	-	390	-	100	Ef = 6.3 VAC Ebb = 215 Rl = 480 Ω Ec2 = 100 Ec1 = 0 Ib measured Pins 1, 3, 5
6CL6	1 of 1	14,000	-	-	50	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -3.0 G1-P Gm measured G2 pin 3 used
6CL8	1 of 2	6000	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 ≙ -2.0 G1-P Gm measured
6CL8	2 of 2	6300	-	-	20	Ef = 6.3 VAC Eb = 150 Rk = 220 Ω Triode Gm measured
6CM4/ EC86	1 of 1	17,600	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -1.2 Gm measured Pins 7, 8, 9 used
6CM5/ EL36	1 of 2	12,000	-	-	100	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -20 G1-P Gm measured
6CM5/ EL36	2 of 2	-	280	-	100	Ef = 6.3 VAC Ebb = 230 Rl = 950 Ω Ec2 = 100 Ec1 = 0 Ib measured
6CM6	1 of 1	4700	-	-	50	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -4.2 G1-P Gm measured G1 pin 3 used
6CM7	1 of 2	3300	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -4.0 Gm measured Pins 3, 6, 7 used
6CM7	2 of 2	6300	-	-	20	Ef = 6.3 VAC Eb = 150 Ec = -3.5 Gm measured Pins 1, 8, 9 used
6CM8	1 of 2	7600	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Rk = 180 Ω Pent. Gm measured
6CM8	2 of 2	2800	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -1.0 Triode Gm measured
6CN6/ EL38	1 of 1	17,700	-	-	100	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Ec1 = -2.5 G1-P Gm measured

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
6CN7	1 of 2	1600	-	-	20	Ef = 6.3 VAC Eb = 100 Ec1 = -1.0 Triode Gm measured
6CN7	2 of 2	-	22	-	10	Ef = 3.1 VAC (Para.) Ebb = 9 Rl = 115 Ω Ib measured Dual Test: 1st Diode: P pin 2 used 2nd Diode: P pin 1 used
6CQ4	1 of 1	-	148	-	10	Ef = 6.3 VAC Epp = 500 VAC (H-W) Rl = 5000 Ω Cl = 4 μf Io measured
6CQ8	1 of 2	5800	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -2.5 Pent. Gm measured Pentode pins 2, 3, 6, 7 used
6CQ8	2 of 2	8300	-	-	20	Ef = 6.3 VAC Eb = 150 Rk = 130 Ω Triode Gm measured
6CR6	1 of 2	2500	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -2.0 Pent. G1-P Gm measured
6CR6	2 of 2	-	0.6	-	20	Ef = 6.3 VAC Ebb = 20 Rl = 33,300 Ω Diode Ib measured
6CR8	1 of 2	9700	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Rk = 70 Ω Pent. Gm measured
6CR8	2 of 2	5000	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -2.4 Triode Gm measured
6CS6	1 of 2	1500	-	-	20	Ef = 6.3 VAC Eb = 50 Ec3 = 0 Ec2 = 50 Ec1 = -1.5 G1-P Gm measured
6CS6	2 of 2	1500	-	-	20	Ef = 6.3 VAC Eb = 50 Ec3 = -1.0 Ec2 = 50 Ec1 = 0 G3-P Gm measured
6CS7	1 of 2	3200	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -2.0 Gm measured Pins 6, 7, 8 used
6CS7	2 of 2	6700	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -4.2 Gm measured Pins 1, 3, 9 used
6CU5	1 of 1	9400	-	-	70	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -6.2 G1-P Gm measured
6CU6	1 of 2	6900	-	-	100	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -21 G1-P Gm measured
6CU6	2 of 2	-	316	-	100	Ef = 6.3 VAC Ebb = 230 Rl = 750 Ω Ec2 = 150 Ec1 = 0 Ib measured
6CU8	1 of 2	7600	-	-	20	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 180 Ω Pent. G1-P Gm measured
6CU8	2 of 2	4100	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -4.2 Triode Gm measured
6CW4	1 of 1	13,400	-	-	10	Ef = 6.3 VAC Eb = 100 Rk = 100 Ω Gm measured Hickok Adapter 1050-127 required
6CW5/ EL86	1 of 1	12,600	-	-	100	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -10 G1-P Gm measured

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
6CW7 ECC84	1 of 1	7500	-	-	20	Ef = 6.3 VAC Eb = 100 Ec1 = -2.3 Gm measured
6CX8	1 of 2	13,000	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Rk = 40 Ω G1-P Gm measured
6CX8	2 of 2	6000	-	-	20	Ef = 6.3 VAC Eb = 150 Rk = 150 Ω Triode Gm measured
6CY5	1 of 1	10,000	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -1.4 G1-P Gm measured
6CY7	1 of 3	1600	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -1.5 Gm measured Pins 6, 7, 8 used
6CY7	2 of 3	6800	-	-	20	Ef = 6.3 VAC Eb = 150 Rk = 620 Ω Gm measured Pins 1, 3, 9 used
6CY7	3 of 3	-	128	-	20	Ef = 6.3 VAC Eb = 150 Rk = 1125 Ω Ib measured Pins 1, 3, 9 used
6CZ5	1 of 1	6000	-	-	50	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -5.0 G1-P Gm measured
6D4	1 of 3	-	166	-	20	Ef = 6.3 VAC Ebb = 150 Ec1 = 0 Rl = 1350 Ω Ik measured
6D4	2 of 3	-	-	100	20	Ef = 6.3 VAC Etd measured at 100 MA OK under 20 V
6D4	3 of 3	-	20	-	-	Ef = 6.3 VAC Epp = 250 VAC Ec2 = -30 Ib cut-off test OK under 2 MA
6D6	1 of 1	1900	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -3.0 G1-P Gm measured
6DA4	1 of 1	-	148	-	10	Ef = 6.3 VAC Epp = 500 VAC (H-W) Rl = 5500 Ω Cl = 4 μf Io measured
6DA5/ EM81	1 of 2	-	-	-	20	Ef = 6.3 VAC Eb = 150 E (Target) = 150 Ec1 = -2.9 (Bright) Quality Test: No Meter Reading
6DA5/ EM81	2 of 2	-	-	-	20	Ef = 6.3 VAC Eb = 0 E (Target) = 150 Ec1 = -60 (Dim) Quality Test: No Meter Reading
6DA6/ EF89	1 of 1	4500	-	-	20	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -1.9 G1-P Gm measured
6DA7	1 of 3	3500	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -2.9 Gm measured Pins 6, 7, 8 used
6DA7	2 of 3	7200	-	-	50	Ef = 6.3 VAC Eb = 150 Ec = -17.5 Gm measured Pins 1, 3, 9 used
6DA7	3 of 3	-	102	-	50	Ef = 6.3 VAC Ebb = 150 Rl = 1120 Ω Ec1 = 0 Ib measured Pins 1, 3, 9 used
6DB5	1 of 2	10,100	-	-	70	Ef = 6.3 VAC Eb = 150 Ec2 = 100 Ec1 = -12 G1-P Gm measured G1 pin 6 used K pin 7 used

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
6DB5	2 of 2	10,100	-	-	70	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = 12 G1-P Gm measured G1 pin 3 used K pin 2 used
6DB6	1 of 2	4800	-	-	20	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Ec1 = -1.5 G1-P Gm measured
6DB6	2 of 2	600	-	-	20	Ef = 6.3 VAC Eb = 150 Ec3 = -1.5 Ec2 = 150 Ec1 = -1.5 G3-P Gm measured
6DC6	1 of 1	6500	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Rk = 180 Ω G1-P Gm measured
6DC8/ EBF89	1 of 2	5700	-	-	20	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -1.4 Pent. G1-P Gm measured
6DC8/ EBF89	2 of 2	-	0.6	-	20	Ef = 6.3 VAC Ebb = 20 Rl = 33,300 Ω Ib measured Dual Test: 1st Diode: P pin 8 used 2nd Diode: P pin 7 used
6DE4	1 of 1	-	148	-	10	Ef = 6.3 VAC Epp = 500 VAC (H-W) Rl = 5000 Ω Cl = 4 μf Io measured
6DE6	1 of 1	7600	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Rk = 180 Ω G1-P Gm measured
6DE7	1 of 3	3400	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -4.0 Gm measured Pins 6, 7, 8 used
6DE7	2 of 3	8200	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -17.5 Gm measured Pins 1, 3, 9 used
6DE7	3 of 3	-	98	-	20	Ef = 6.3 VAC Eb = 50 Ec1 = 0 Ib measured Pins 1, 2, 9 used
6DG6	1 of 1	10,100	-	-	70	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -12 G1-P Gm measured
6DJ8/ ECC88	1 of 1	15,800	-	-	10	Ef = 6.3 VAC Eb = 100 Ec1 = -1.5 Gm measured
6DK6	1 of 1	11,100	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Rk = 120 Ω G1-P Gm measured
6DL4/ EC88	1 of 1	17,000	-	-	20	Ef = 6.3 VAC Eb = 150 Rk = 100 Ω Gm measured Grid pin 9 used
6DL5/ EL95	1 of 1	6300	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -3.8 G1-P Gm measured G1 pin 1 used
6DM4	1 of 1	-	148	-	10	Ef = 6.3 VAC Epp = 500 VAC (H-W) Rl = 5000 Ω Cl = 4 μf Io measured
6DN6	1 of 2	12,500	-	-	100	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -12 G1-P Gm measured
6DN6	2 of 2	-	384	-	100	Ef = 6.3 VAC Ebb = 223 Rl = 720 Ω Ec2 = 100 Ec1 = 0 Ib measured
6DN7	1 of 2	3300	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -3.3 Gm measured Pins 4, 5, 6 used

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
6DN7	2 of 2	10,800	-	-	50	Ef = 6.3 VAC Eb = 150 Ec1 = -2.9 Gm measured Pins 1, 2, 3 used
6DQ4	1 of 1	-	150	-	10	Ef = 6.3 VAC Epp = 250 VAC (H-W) Rl = 5400 Ω Cl = 4 μf Io measured
6DQ5	1 of 2	10,000	-	-	100	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -33 G1-P Gm measured Pins 5, 6, 8 used
6DQ5	2 of 2	-	230	-	100	Ef = 6.3 VAC Ebb = 252 Rl = 1220 Ω Ec2 = 50 Ec1 = 0 Ib measured Pins 1, 3, 4 used
6DQ6	1 of 2	7000	-	-	100	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -21 G1-P Gm measured
6DQ6	2 of 2	-	420	-	100	Ef = 6.3 VAC Ebb = 207 Rl = 490 Ω Ec2 = 150 Ec1 = 0 Ib measured
6DR4	1 of 1	1600	-	-	20	Ef = 6.3 VAC Eb = 100 Ec1 = -1.0 G1-P Gm measured P pins 5 used
6DR7	1 of 3	2000	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -1.8 Gm measured Pins 1, 3, 9 used
6DR7	2 of 3	8200	-	-	20	Ef = 6.3 VAC Eb = 150 Ec = -17.5 Gm measured Pins 1, 3, 9 used
6DR7	3 of 3	-	98	-	20	Ef = 6.3 VAC Eb = 50 Ec1 = 0 Ib measured Pins 1, 2, 9 used
6DR8/ EBF83	1 of 2	500	-	-	20	Ef = 6.3 VAC Eb = 9.0 Ec3 = 0 Ec2 = 9.0 Rk = 6100 Ω Pent. G1-P, G2 Gm measured
6DR8/ EBF83	2 of 2	-	0.6	-	20	Ef = 6.3 VAC Ebb = 20 Rl = 33,300 Ω Diode Ib measured Dual Test: 1st Diode: P pin 8 used 2nd Diode: P pin 7 used
6DS4	1 of 1	13,400	-	-	10	Ef = 6.3 VAC Eb = 100 Rk = 100 Ω Gm measured Hickok Adapter 1050-127 required
6DS5	1 of 1	7500	-	-	70	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -4.7 G1-P Gm measured
6DS8/ ECH83	1 of 2	-	0.1	-	20	Ef = 6.3 VAC Eb = 9.0 Ec3 = 0 Ec2, 4 = 9.0 Rk = 4100 Ω Pent. Ib measured
6DS8/ ECH83	2 of 2	500	-	-	20	Ef = 6.3 VAC Eb = 9.0 Rk = 7100 Ω Triode Gm measured
6DT4	1 of 1	-	148	-	10	Ef = 6.3 VAC Epp = 500 VAC (H-W) Rl = 5400 Cl = 4 μf Io measured
6DT5	1 of 2	7800	-	-	50	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -8.5 G1-P Gm measured G1 pin 3 used
6DT5	2 of 2	-	140	-	50	Ef = 6.3 VAC Ebb = 275 Rl = 2150 Ω Ec2 = 150 Ec1 = 0 Ib measured G1 pin 6 used

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
6DT6	1 of 2	1000	-	-	20	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Rk = 2100 Ω G1-P Gm measured
6DT6	2 of 2	600	-	-	20	Ef = 6.3 VAC Eb = 100 Ec1, 3 = -1.7 Ec2 = 100 G3-P Gm measured
6DT8	1 of 1	5000	-	-	20	Ef = 6.3 VAC Eb = 100 Rk = 270 Ω Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
6DW4	1 of 1	-	148	-	10	Ef = 6.3 VAC Epp = 500 VAC (H-W) Rl = 5400 Ω Cl = 4 μf Io measured P pin 7 used Hickok Adapter 1050-144 required
6DW5	1 of 2	6900	-	-	100	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -21 G1-P Gm measured G1 pin 3 used
6DW5	2 of 2	-	364	-	100	Ef = 6.3 VAC Ebb = 221 Rl = 620 Ω Ec2 = 150 Ec1 = 0 Ib measured G1 pin 6 used
6DX8/ ECL84	1 of 2	13,800	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -1.5 Pent. G1-P Gm measured
6DX8/ ECL84	2 of 2	5000	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -1.2 Triode Gm measured
6DZ4	1 of 1	8200	-	-	20	Ef = 6.3 VAC Eb = 150 Rk = 200 Ω Gm measured P pin 7 used G pin 6 used
6DZ7	1 of 2	14,200	-	-	70	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -3.6 G1-P Gm measured P pin 3 used G1 pin 1 used
6DZ7	2 of 2	14,200	-	-	70	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -3.6 G1-P Gm measured P pin 6 used G1 pin 5 used
6DZ8	1 of 2	9500	-	-	50	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Rk = 140 Ω G1-P Gm measured
6DZ8	2 of 2	1800	-	-	20	Ef = 6.3 VAC Eb = 100 Rk = 1200 Ω Triode Gm measured
6E5	1 of 2	-	-	-	20	Ef = 6.3 VAC E (Screen) = Open ckt E (Target) = 300 V Ec1 = 0 (Eye Open) Quality Test: No Meter Reading
6E5	2 of 2	-	-	-	20	Ef = 6.3 VAC E (Screen) = 150 E (Target) = 150 Ec1 = -64 (Eye Shut) Quality Test: No Meter Reading
6E6	1 of 1	2000	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -12 Gm measured Dual Test: 1st Triode: pins 4, 5, 6 used 2nd Triode: pins 2, 3, 4 used
6E7	1 of 1	1900	-	-	20	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -3.0 G1-P Gm measured

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
6EA5	1 of 1	9500	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -1.0 G1-P Gm measured K pin 2 used
6EA7	1 of 3	2400	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -1.6 Gm measured Pins 4, 5, 6 used
6EA7	2 of 3	8200	-	-	50	Ef = 6.3 VAC Eb = 150 Ec1 = -21 Gm measured Pins 1, 2, 3 used
6EA7	3 of 3	-	134	-	50	Ef = 6.3 VAC Ebb = 150 Rl = 950 Ω Ib measured Pins 1, 2, 3 used
6EA8	1 of 2	6900	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -1.0 Pent. G1-P Gm measured
6EA8	2 of 2	10,700	-	-	20	Ef = 6.3 VAC Eb = 150 Rk = 60 Ω Triode Gm measured
6EB5	1 of 1	-	8.1	-	20	Ef = 6.3 VAC Ebb = 9.0 Rl = 385 Ω Diode Ib measured Dual Test: 1st Diode: pins 1 & 7 used 2nd Diode: pins 2 & 5 used
6EB8	1 of 2	14,500	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Rk = 60 Ω Pent. G1-P Gm measured
6EB8	2 of 2	3500	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -1.2 Triode Gm measured
6EH5	1 of 1	18,400	-	-	70	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Rk = 50 Ω G1-P Gm measured G1-pin 2 used
6EH7/ EF183	1 of 2	15,700	-	-	20	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -2.2 G1-P Gm measured K pin 3 used
6EH7/ EF183	2 of 2	-	14.1	-	20	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -2.2 Ib measured K pin 1 used
6EH8	1 of 2	6300	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -1.0 Pent. G1-P Gm measured K pin 6 used
6EH8	2 of 2	9000	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -1.5 Triode Gm measured K pin 1 used
6EJ7/ EF184	1 of 2	18,900	-	-	20	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Ec1 = -1.8 G1-P Gm measured K pin 3 used
6EJ7/ EF184	2 of 2	-	12	-	20	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Ec1 = -1.8 Ib measured K pin 1 used
6EM5	1 of 2	6400	-	-	70	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -8.5 G1-P Gm measured G1 pin 3 used
6EM5	2 of 2	-	120	-	70	Ef = 6.3 VAC Ebb = 286 Rl = 2900 Ω Ec2 = 150 Ec1 = 0 Ib measured G1 pin 6 used
6EM7	1 of 3	2000	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -1.8 Gm measured Pins 4, 5, 6 used

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
6EM7	2 of 3	9100	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -20 Gm measured Pins 1, 2, 3 used
6EM7	3 of 3	-	112	-	20	Ef = 6.3 VAC Eb = 50 Ec1 = 0 Ib measured Pins 1, 2, 3 used
6EQ7	1 of 2	3500	-	-	20	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -1.0 Pent. G1-P Gm measured
6EQ7	2 of 2	-	0.48	-	20	Ef = 6.3 VAC Ebb = 9.0 Rl = 11,100 Ω Diode Ib measured
6ER5/ EC95	1 of 2	13,200	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -0.8 Gm measured K pin 7 used
6ER5/ EC95	2 of 2	13,200	-	-	20	Ef = 6. 3 VAC Eb = 150 Ec1 = -0.8 Gm measured K pin 1 used
6ES5	1 of 2	10,000	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -0.8 Gm measured K pin 7 used
6ES5	2 of 2	10,000	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -0.8 Gm measured K pin 1 used
6ES6/ EF97	1 of 1	2700	-	-	20	Ef = 6.3 VAC Eb = 9.0 Ec3 = 0 Ec2 = 9.0 Ec1 = -1.7 G1-P, G2 Gm measured
6ES8/ ECC189	1 of 1	15,800	-	-	10	Ef = 6.3 VAC Eb = 100 Ec1 = -1.5 Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
6ET6/ EF98	1 of 1	2600	-	-	20	Ef = 6.3 VAC Eb = 9.0 Ec3 = 0 Ec2 = 9.0 Ec1 = -2.2 G1-P Gm measured
6ET7	1 of 3	14,500	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Rk = 100 Ω Pent. G1-P Gm measured
6ET7	2 of 3	-	70	-	20	Ef = 6.3 VAC Ebb = 297 Rl = 4300 Ω Ec2 = 150 Ec1 = 0 Pent. Ib measured
6ET7	3 of 3	-	0.6	-	20	Ef = 6.3 VAC Ebb = 20 Rl = 33,300 Ω Diode Ib measured Dual Test: 1st Diode: P pin 3 used 2nd Diode: P pin 2 used
6EU7	1 of 1	1600	-	-	20	Ef = 6.3 VAC Eb = 100 Ec1 = -1.0 Gm measured Dual Test: 1st Triode: pins 7, 8, 9 used 2nd Triode: pins 4, 5, 6 used
6EU8	1 of 2	6900	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -1.0 Pent. G1-P Gm measured
6EU8	2 of 2	10,700	-	-	20	Ef = 6.3 VAC Eb = 150 Rk = 60 Ω Triode Gm measured
6EV5	1 of 1	11,100	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -1.0 G1-P Gm measured K pin 2 used

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
6EV7	1 of 3	5800	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -1.0 Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
6EV7	2 of 3	-	12	-	20	Ef = 6.3 VAC Ebb = 150 Ec1 = 0 Rk = 2500 Ω Ib measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
6EV7	3 of 3	-	0.20	-	20	Ef = 6.3 VAC Eb = 150 Ib measured OK under 0.10 MA Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
6EW6	1 of 1	17,600	-	-	20	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 70 Ω G1-P Gm measured
6EW7	1 of 2	2500	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -6.0 Gm measured Pins 6, 7, 8 used
6EW7	2 of 2	9400	-	-	50	Ef = 6.3 VAC Eb = 150 Ec1 = -17.5 Gm measured Pins 1, 2, 9 used
6EX6	1 of 2	10,700	-	-	100	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -23 G1-P Gm measured
6EX6	2 of 2	-	322	-	100	Ef = 6.3 VAC Ebb = 229 Rl = 730 Ω Ec2 = 100 Ec1 = 0 Ib measured
6EY6	1 of 2	7500	-	-	70	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -5.1 G1-P Gm measured
6EY6	2 of 2	-	106	-	70	Ef = 6.3 VAC Ebb = 292 Rl = 3300 Ω Ec2 = 150 Ec1 = 0 Ib measured
6EZ5	1 of 2	5200	-	-	50	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -10 G1-P Gm measured
6EZ5	2 of 2	-	140	-	50	Ef = 6.3 VAC Ebb = 280 Rl = 2200 Ω Ec2 = 150 Ec1 = 0 Ib measured
6EZ8	1 of 2	5300	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -1.3 Gm measured Pins 1, 2, 3 used
6EZ8	2 of 2	5300	-	-	-	Ef = 6.3 VAC Eb = 150 Ec1 = -1.3 Gm measured Dual Test: 1st Triode: pins 4, 8, 9 used 2nd Triode: pins 4, 6, 7 used
6F5	1 of 1	1400	-	-	20	Ef = 6.3 VAC Eb = 100 Ec1 = -1.0 Gm measured
6F6	1 of 1	3500	-	-	70	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -3.3 G1-P Gm measured
6F7	1 of 2	1300	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -3.0 Pent. G1-P Gm measured
6F7	2 of 2	600	-	-	20	Ef = 6.3 VAC Eb = 100 Ec1 = -3.0 Triode Gm measured
6F8	1 of 1	3500	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -2.9 Gm measured Dual Test: 1st Triode: pins 5, 6, 8 used 2nd Triode: pins 3, 4, cap used

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
6F33	1 of 1	4600	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 100 Ec1 = -1.0 G1-P Gm measured
6FA7	1 of 3	2400	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Rk = 150 Ω Pent. G1-P Gm measured P pin 9 used
6FA7	2 of 3	2400	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Rk = 150 Ω Pent. G1-P Gm measured P pin 1 used
6FA7	3 of 3	-	0.6	-	20	Ef = 6.3 VAC Ebb = 20 Rl = 33,300 Ω Diode Ib measured
6FD6	1 of 1	1600	-	-	20	Ef = 6.3 VAC Eb = 9.0 Ec3 = 0 Ec2 = 9.0 Ec1 = -1.0 G1-P G2 Gm measured
6FD7	1 of 2	2000	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -1.8 Gm measured Pins 6, 7, 8 used
6FD7	2 of 2	9400	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -1.8 Gm measured Pins 1, 2, 9 used
6FE5	1 of 1	12,000	-	-	100	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Rk = 130 Ω G1-P Gm measured
6FG5	1 of 1	2500	-	-	20	Ef = 6.3 VAC Eb = 150 Ec3 = 150 Rk = 800 Ω G1-P Gm measured
6FG6/ EM84	1 of 2	-	2.2	-	20	Ef = 6.3 VAC Ebb (Target, screen) = 300 Rl = 15,000 Ω E (Deflector) = 150 Rk = 1800 Ω I (Screen) measured Split Bar
6FG6/ EM84	2 of 2	-	2.2	-	20	Ef = 6.3 VAC Ebb (Target, screen, deflector) = 300 Rl = 15,000 Ω Rk = 1800 Ω I (Screen) measured Solid Bar
6FG7	1 of 2	6500	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -1.0 Pent. G1-P Gm measured
6FG7	2 of 2	8500	-	-	20	Ef = 6.3 VAC Eb = 100 Ec1 = -1.0 Triode Gm measured
6FH5	1 of 1	11,400	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -1.3 Gm measured K pin 1 used
6FH6	1 of 2	6800	-	-	100	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -20 G1-P Gm measured
6FH6	2 of 2	-	238	-	100	Ef = 6.3 VAC Ebb = 253 Rl = 1140 Ω Ec2 = 100 Ec1 = 0 Ib measured
6FH8	1 of 4	4400	-	-	-	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -2.0 Tetrode G1-P Gm measured P pin 9 used
6FH8	2 of 4	-	0.1	-	-	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Rk = 400 Ω Tetrode Ib measured P pin 8 used
6FH8	3 of 4	-	0.1	-	-	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Rk = 400 Ω Tetrode Ib measured P pin 1 used
6FH8	4 of 4	6800	-	-	-	Ef = 6.3 VAC Eb = 100 Ec1 = -1.0 Triode Gm measured

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
6FM8	1 of 2	1600	-	-	20	Ef = 6.3 VAC Eb = 100 Ec1 = -1.0 Triode Gm measured
6FM8	2 of 2	-	22	-	10	Ef = 6.3 VAC Ebb = 9.0 Rl = 266 Ω Diode Ib measured Dual Test: 1st Diode: pins 6, 1 used 2nd Diode: pins 2, 3 used
6FQ5	1 of 1	13,800	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -1.5 Gm measured K pin 1 used
6FQ7	1 of 1	3500	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -2.9 Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
6FS5	1 of 1	6800	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -0.9 G1-P Gm measured K pin 7 used
6FV6	1 of 1	10,000	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -1.3 G1-P Gm measured
6FV8	1 of 2	6900	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -1.0 Pent. G1-P Gm measured
6FV8	2 of 2	9000	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -1.5 Triode Gm measured
6FW5	1 of 2	8300	-	-	100	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -21 G1-P Gm measured
6FW5	2 of 2	-	266	-	100	Ef = 6.3 VAC Ebb = 245 Rl = 1080 Ω Ec2 = 100 Ec1 = 0 Ib measured
6FW8	1 of 1	15,700	-	-	20	Ef = 6.3 VAC Eb = 100 Ec1 = -1.5 Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
6FY5/ EC97	1 of 2	16,400	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -1.2 Gm measured K pin 7 used
6FY5/ EC97	2 of 2	16,400	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -1.2 Gm measured K pin 1 used
6FY8	1 of 2	9400	-	-	50	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Rk = 100 Ω Pent. G1-P Gm measured
6FY8	2 of 2	3400	-	-	20	Ef = 6.3 VAC Eb = 100 Ec1 = -1.5 Triode Gm measured
6G5	1 of 2	-	-	-	20	Ef = 6.3 VAC E (Screen) = Open ckt E (Target) = 300 Ec1 = 0 (Eye Open) Quality Test: No Meter Reading
6G5	2 of 2	-	-	-	20	Ef = 6.3 VAC E (Screen) = 150 E (Target) = 150 Ec1 = -64 (Eye Shut) Quality Test: No Meter Reading
6G6	1 of 1	2800	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -5.5 G1-P Gm measured

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
6GC5	1 of 2	10,100	-	-	70	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -6.3 G1-P Gm measured G1 pin 6 used G2 pin 8 used
6GC5	2 of 2	-	56	-	70	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -6.3 Ib measured G1 pin 3 used G2 pin 1 used
6GC6	1 of 2	8300	-	-	100	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -21.5 G1-P Gm measured G2 pin 8 used
6GC6	2 of 2	-	252	-	100	Ef = 6.3 VAC Ebb = 242 R1 = 910 Ω Ec2 = 100 Ec1 = 0 Ib measured G2 pin 4 used
6GD7	1 of 2	15,200	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Rk = 120 Ω Pent. G1-P Gm measured K pin 8 used
6GD7	2 of 2	12,600	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -1.4 Triode Gm measured K pin 3 used
6GE8	1 of 4	4000	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -2.0 Pent. G1-P Gm measured
6GE8	2 of 4	6300	-	-	50	Ef = 6.3 VAC Eb = 150 Ec1 = -21 Triode Gm measured
6GE8	3 of 4	-	88	-	50	Ef = 6.3 VAC Eb = 50 Ec1 = 0 Triode Ib measured
6GE8	4 of 4	-	3.0	-	50	Ef = 6.3 VAC Eb = 150 Ec1 = -42 Triode Ib measured OK 0 to 1.5 MA

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
6GF7	1 of 2	2000	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -1.8 Triode Gm measured Pins 1, 8, 9 used Hickok Adapter 1050-144 required
6GF7	2 of 2	9100	-	-	100	Ef = 6.3 VAC Eb = 150 Ec1 = -20 Triode Gm measured Pins 2, 3, 6 used
6GH8	1 of 2	7200	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -1.0 Pent. G1-P Gm measured
6GH8	2 of 2	10,000	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -1.5 Triode Gm measured
6GJ5	1 of 2	8800	-	-	100	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -21 G1-P Gm measured G1 pin 6 used G2 pin 7 used Hickok Adapter 1050-144 required
6GJ5	2 of 2	-	250	-	100	Ef = 6.3 VAC Ebb = 239 R1 = 900 Ω Ec2 = 100 Ec1 = 0 Ib measured G1 pin 2 used G2 pin 1 used Hickok Adapter 1050-144 required
6GJ7/ ECF801	1 of 2	13,800	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -1.6 Pent: G1-P Gm measured K pin 3 used
6GJ7/ ECF801	2 of 2	11,400	-	-	20	Ef = 6.3 VAC Eb = 100 Ec1 = -3.0 Triode Gm measured K pin 1 used

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
6GJ8	1 of 2	9400	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -1.5 Pent. G1-P Gm measured
6GJ8	2 of 2	10,700	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -1.4 Triode Gm measured
6GK5	1 of 1	18,900	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -1.2 Gm measured K pin 7 used
6GK6	1 of 1	14,200	-	-	50	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 60 Ω G1-P Gm measured
6GL7	1 of 2	2800	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -1.5 Gm measured Pins 4, 5, 6 used
6GL7	2 of 2	8100	-	-	50	Ef = 6.3 VAC Eb = 150 Ec1 = -23 Gm measured Pins 1, 2, 3 used
6GM5	1 of 1	11,100	-	-	50	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -4.1 G1-P Gm measured
6GM6	1 of 1	15,000	-	-	20	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Rk = 60 Ω G1-P Gm measured
6GM8/ ECC86	1 of 1	3100	-	-	20	Ef = 6.3 VAC Eb = 9.0 Ec1 = -0.7 Triode Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
6GN8	1 of 3	14,500	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Rk = 90 Ω Pent. G1-P Gm measured
6GN8	2 of 3	-	76	-	20	Ef = 6.3 VAC Ebb = 297 Rl = 4260 Ω Ec2 = 150 Ec1 = 0 Pent. Ib measured
6GN8	3 of 3	3400	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -1.2 Triode Gm measured
6GS8	1 of 2	-	1.38	-	50	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -1.5 Ib measured P pin 8 used G3 pin 9 used
6GS8	2 of 2	-	1.38	-	50	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -1.5 Ib measured P pin 3 used G3 pin 6 used
6GT5	1 of 2	8800	-	-	100	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -21 G1-P Gm measured G1 pin 6 used G2 pin 7 used Hickok Adapter 1050-144 required
6GT5	2 of 2	-	250	-	100	Ef = 6.3 VAC Ebb = 239 Rl = 900 Ω Ec2 = 100 Ec1 = 0 Ib measured G1 pin 2 used G2 pin 1 used
6GU5	1 of 1	9900	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -0.7 G1-P Gm measured
6GU7	1 of 1	3900	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -6.0 Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
6GV8/ ECL85	1 of 3	9400	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -12.9 Pent. G1-P Gm measured
6GV8/ ECL85	2 of 3	-	266	-	20	Ef = 6.3 VAC Eb = 30 Ec2 = 150 Ec1 = 0 Pent. Ib measured
6GV8/ ECL85	3 of 3	6400	-	-	20	Ef = 6.3 VAC Eb = 100 Ec1 = -1.0 Triode Gm measured
6GW5	1 of 1	18,900	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -1.3 Gm measured
6GW6	1 of 2	8800	-	-	100	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -21 G1-P Gm measured
6GW6	2 of 2	-	250	-	100	Ef = 6.3 VAC Ebb = 239 Rl = 900 Ω Ec2 = 100 Ec1 = 0 Ib measured
6GW8/ ECL86	1 of 2	12,600	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -2.8 Pent. G1-P Gm measured
6GW8/ ECL86	2 of 2	2000	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -1.0 Triode Gm measured
6GX6	1 of 1	4700	-	-	20	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Rk = 170 Ω G1-P Gm measured
6GY6	1 of 1	4400	-	-	20	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Rk = 180 Ω G1-P Gm measured
6GY8	1 of 3	-	4.66	-	20	Ef = 6.3 VAC Eb = 50 Ec1 = 0 Ib measured Pins 4, 6 & 7 used
6GY8	2 of 3	5600	-	-	20	Ef = 6.3 VAC Eb = 100 Ec1 = -0.7 Gm measured Pins 3, 8, 9 used
6GY8	3 of 3	5600	-	-	-	Ef = 6.3 VAC Eb = 100 Ec1 = -0.7 Gm measured Pins 1, 2 & 4 used
6H6	1 of 1	-	6.1	-	10	Ef = 6.3 VAC Eb = 9.0 Ib measured Dual Test: 1st Diode: pins 5 & 8 used 2nd Diode: pins 3 & 4 used
6HA5/ EC900	1 of 1	15,000	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -1.4 Gm measured K pin 7 used
6HB6	1 of 2	26,000	-	-	50	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 60 Ω G1-P Gm measured
6HB6	2 of 2	-	96	-	50	Ef = 6.3 VAC Ebb = 285 Rl = 3320 Ω Ec3, 1 = 0 Ec2 = 150 Ib measured
6HC8	1 of 3	6400	-	-	50	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -8.3 Pent. G1-P Gm measured
6HC8	2 of 3	-	100	-	50	Ef = 6.3 VAC Ebb = 287 Rl = 3120 Ω Ec2 = 150 Ec1 = 0 Pent. Ib measured
6HC8	3 of 3	2500	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -1.7 Triode Gm measured

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
6HF8	1 of 2	15,700	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Rk = 70 Ω Pent. G1-P Gm measured
6HF8	2 of 2	5000	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -1.4 Triode Gm measured
6HG8/ ECF86	1 of 2	15,000	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -1.2 Pent. G1-P Gm measured K pin 3 used
6HG8/ ECF86	2 of 2	6900	-	-	20	Ef = 6.3 VAC Eb = 100 Ec1 = -3.0 Triode Gm measured K pin 1 used
6HJ8	1 of 2	9300	-	-	20	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 160 Ω Pent. G1-P Gm measured
6HJ8	2 of 2	-	32	-	20	Ef = 6.3 VAC Ebb = 9.0 Rl = 80 Ω Diode Ib measured
6HL8	1 of 2	12,600	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -1.3 Pent. G1-P Gm measured
6HL8	2 of 2	8800	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -1.1 Triode Gm measured
6HM6	1 of 1	18,900	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Rk = 100 Ω G1-P Gm measured K pin 1 used
6HR6	1 of 1	8800	-	-	20	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 100 Ω G1-P Gm measured
6HS6	1 of 1	12,000	-	-	20	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Rk = 90 Ω G1-P Gm measured
6HS8	1 of 2	1200	-	-	20	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -0.9 G1-P Gm measured P pin 8 & G3 pin 9 used
6HS8	2 of 2	1200	-	-	20	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -0.9 G1-P Gm measured P pin 3 & G3 pin 6 used
6HT6	1 of 1	17,600	-	-	20	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 90 Ω G1-P Gm measured K pin 1 used
6HU6/ EM87	1 of 2	-	3.92	-	20	Ef = 6.3 VAC Ebb = 300 Rl = 16,800 Ω Rk = 1800 Ω E (Deflector) = 150 Triode Ip measured Indicator Bar: Split
6HU6/ EM87	2 of 2	-	3.22	-	20	Ef = 6.3 VAC Ebb = 300 Rl = 16,800 Ω Rk = 1800 Ω E (Deflector) = 300 Triode Ib measured Indicator Bar: Solid
6HU8/ ELL80	1 of 2	7600	-	-	50	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Rk = 160 Ω G1-P Gm measured Pins 1, 2, 3, 7 used

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
6HU8/ ELL80	2 of 2	7600	-	-	50	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Rk = 160 Ω G1-P Gm measured Pins 6, 7, 8, 9 used
6HW8	1 of 3	4800	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Rk = 100 Ω G1-P Gm measured
6HW8	2 of 3	-	0.1	-	20	Ef = 6.3 VAC Eb = 150 E (Deflector No. 1) = -50 E (Deflector No. 2) = 0 Ec2 = 150 Ec1 = -1.0 Ib (Plate No. 1) measured OK under 0.02 MA
6HW8	3 of 3	-	0.1	-	20	Ef = 6.3 VAC Eb = 150 E (Deflector No. 2) = -50 E (Deflector No. 1) = 0 Ec2 = 150 Ec1 = -1.0 Ib (Plate No. 2) measured OK under 0.02 MA
6HZ6	1 of 1	4300	-	-	20	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 210 Ω G1-P Gm measured
6HZ8	1 of 3	15,900	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Rk = 80 Ω Pent. G1-P Gm measured
6HZ8	2 of 3	-	106	-	20	Ef = 6.3 VAC Ebb = 298 Ec2 = 150 Ec1 = 0 Rl = 4500 Ω Pent. Ib measured
6HZ8	3 of 3	5000	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -1.4 Triode Gm measured
6J4	1 of 3	15,600	-	-	10	Ef = 6.3 VAC Eb = 150 Rk = 100 Ω Gm measured G pin 6 used
6J4	2 of 3	15,600	-	-	10	Ef = 6.3 VAC Eb = 150 Rk = 100 Ω Gm measured G pin 5 used
6J4	3 of 3	15,600	-	-	10	Ef = 6.3 VAC Eb = 150 Rk = 100 Ω Gm measured G pin 1 used
6J5	1 of 1	3500	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -2.9 Gm measured
6J6	1 of 1	6600	-	-	20	Ef = 6.3 VAC Eb1, 2 = 100 Rk = 50 Ω Gm measured Dual Test: 1st Triode: pins 1, 6, 7 used 2nd Triode: pins 2, 5, 7 used
6J7	1 of 1	1500	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -3.0 G1-P Gm measured
6J8	1 of 2	800	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -4.2 Pent. G1-P Gm measured
6J8	2 of 2	2100	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -3.0 Triode Gm measured
6JA8	1 of 2	17,600	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -1.7 Tetrode Gm measured
6JA8	2 of 2	4900	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -1.5 Triode Gm measured

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
6JB6	1 of 2	8800	-	-	100	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Ec1 = -21 G1-P Gm measured
6JB6	2 of 2	-	250	-	100	Ef = 6.3 VAC Ebb = 239 Rl = 900 Ω Ec3 = 0 Ec2 = 100 Ec1 = 0 Ib measured
6JB8	1 of 2	2000	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -3.0 Pent. G1-P Gm measured
6JB8	2 of 2	3800	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -3.0 Triode Gm measured
6JC8	1 of 2	6900	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -1.3 Pent. G1-P Gm measured K pin 7 used
6JC8	2 of 2	8200	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -1.4 Triode Gm measured K pin 1 used
6JD6	1 of 1	17,300	-.	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Rk = 40 Ω G1-P Gm measured
6JE8	1 of 2	15,000	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Rk = 80 Ω Pent. G1-P Gm measured
6JE8	2 of 2	5800	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -1.4 Triode Gm measured
6JF8	1 of 3	8100	-	-	100	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -21 Pent. G1-P Gm measured
6JF8	2 of 3	-	420	-	100	Ef = 6.3 VAC Ebb = 207 Rl = 490 Ω Ec2 = 150 Ec1 = 0 Pent. Ib measured
6JF8	3 of 3	-	148	-	10	Ef = 6.3 VAC Epp = 500 VAC (H-W) Rl = 5500 Ω Cl = 4 μf Diode Io measured
6JH6	1 of 1	10,000	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Rk = 80 Ω G1-P Gm measured
6JH8	1 of 3	5500	-	-	20	Ef = 6.3 VAC Eb = 150 E (Deflector) = 0 E (Accelerator) = 150 Rk = 70 Ω G1-P Gm measured Pins 1, 2 jumpered Pins 8, 9 jumpered
6JH8	2 of 3	-	3.0	-	20	Ef = 6.3 VAC Eb = 150 E (Deflector No. 2) = 0 E (Deflector No. 1) = -50 Ec1 = -1.0 Ib (Plate No. 1) measured OK under 1.5 MA
6JH8	3 of 3	-	3.0	-	20	Ef = 6.3 VAC Eb = 150 E (Deflector No. 1) = 0 E (Deflector No. 2) = -50 Ec1 = -1.0 Ib (Plate No. 2) measured OK under 1.5 MA
6JK8	1 of 2	8500	-	-	20	Ef = 6.3 VAC Eb = 100 Ec1 = -1.0 Gm measured Pins 6, 7, 8 used
6JK8	2 of 2	16,000	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -1.4 Gm measured Pins 1, 2, 3 used

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
6JT8	1 of 2	24,000	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Rk = 80 Ω Pent. G1-P Gm measured
6JT8	2 of 2	3400	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -1.3 Triode Gm measured
6JU8	1 of 2	-	48	-	10	Ef = 6.3 VAC Eb = 9.0 Ib measured Dual Test: 1st Diode: pins 2 & 3 used 3rd Diode: pins 8 & 9 used
6JU8	2 of 2	-	48	-	10	Ef = 6.3 VAC Eb = 9.0 Ib measured Dual Test: 2nd Diode: pins 1 & 2 used 4th Diode: pins 7 & 8 used
6JV8	1 of 2	10,800	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -2.2 Pent. G1-P Gm measured
6JV8	2 of 2	5000	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -1.5 Triode Gm measured
6JX8/ ECH84	1 of 2	-	2.14	-	20	Ef = 6.3 VAC Eb = 50 Ec2, 4 = 50 Ec3 = 0 Rk = 600 Ω Pent. Ib measured
6JX8/ ECH84	2 of 2	4600	-	-	20	Ef = 6.3 VAC Eb = 100 Ec1 = -0.8 Triode Gm measured
6K5	1 of 1	1100	-	-	20	Ef = 6.3 VAC Eb = 100 Ec1 = -1.5 Gm measured
6K6	1 of 1	1900	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -7.0 G1-P Gm measured
6K7	1 of 1	2100	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -1.0 G1-P Gm measured
6K8	1 of 2	900	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1, 3 = -3.0 Pent. G3-P Gm measured
6K8	2 of 2	3500	-	-	20	Ef = 6.3 VAC Eb = 100 Ec1 = -1.0 Triode Gm measured
6KA8	1 of 2	5500	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Rk = 110 Ω Pent. G1-P Gm measured
6KA8	2 of 2	5000	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -1.3 Triode Gm measured
6KD8	1 of 2	5500	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -1.0 Pent. G1-P Gm measured
6KD8	2 of 2	8200	-	-	20	Ef = 6.3 VAC Eb = 100 Ec1 = -1.0 Triode Gm measured
6KE8	1 of 2	13,900	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Rk = 60 Ω Pent. G1-P Gm measured
6KE8	2 of 2	9400	-	-	20	Ef = 6.3 VAC Eb = 150 Rk = 120 Ω Triode Gm measured
6KF8	1 of 2	1900	-	-	20	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -0.9 G1-P Gm measured P pin 8 used

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
6KF8	2 of 2	1900	-	-	20	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -0.9 G1-P Gm measured P pin 3 used
6KL8	1 of 2	5000	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -0.5 Pent. G1-P Gm measured
6KL8	2 of 2	-	0.6	-	20	Ef = 6.3 VAC Ebb = 20 Rl = 33,000 Ω Diode Ib measured
6KM8	1 of 4	2200	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -1.1 Tetrode: G1-P Gm measured P pin 9 used
6KM8	2 of 4	2100	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -1.1 Tetrode G1-P Gm measured P pin 2 used
6KM8	3 of 4	2100	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -1.1 Tetrode G1-P Gm measured P pin 1 used
6KM8	4 of 4	-	0.6	-	20	Ef = 6.3 VAC Ebb = 20 Rl = 33,000 Ω Diode Ib measured
6KS8	1 of 2	17,000	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Rk = 150 Ω Pent. G1-P Gm measured
6KS8	2 of 2	5000	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -1.4 Triode Gm measured
6KT8	1 of 2	12,600	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -1.0 Pent. G1-P Gm measured
6KT8	2 of 2	4000	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -1.3 Triode Gm measured
6KZ8	1 of 2	9400	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -1.4 Pent. G1-P Gm measured
6KZ8	2 of 2	10,600	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -1.3 Triode Gm measured
6L5	1 of 1	1900	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -5.0 Gm measured
6L6	1 of 1	6700	-	-	70	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -7.0 G1-P Gm measured
6L7	1 of 2	1300	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1,3 = -3.0 G1-P Gm measured
6L7	2 of 2	600	-	-	20	Ef = 6.3 VAC Eb = 50 Ec3 = -1.5 Ec2 = 50 Ec1 = 0 G3-P Gm measured
6LB8	1 of 2	25,200	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Rk = 80 Ω Pent. G1-P Gm measured
6LB8	2 of 2	6600	-	-	20	Ef = 6.3 VAC Eb = 150 Rk = 70 Ω Triode Gm measured
6M3	1 of 1	-	148	-	10	Ef = 6.3 VAC Epp = 500 VAC (H-W) Rl = 5300 Ω Cl = 4 *uf* Io measured
6N4	1 of 2	7900	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -1.9 Gm measured Pins 6 & 7 used

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
6N4	2 of 2	7900	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -1.9 Gm measured Pins 1 & 2 used
6N5	1 of 2	-	-	-	20	Ef = 6.3 VAC E (Screen) = 150 E (Target) = 150 Ec1 = 0 (Eye Shut) Quality Test: No Meter Reading
6N5	2 of 2	-	-	-	20	Ef = 6.3 VAC E (Screen) = 0 E (Target) = 150 Ec1 = 0 (Eye Open) Quality Test: No Meter Reading
6N7	1 of 1	2100	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -2.0 Gm measured Dual Test: 1st Triode: pins 5, 6, 8 used 2nd Triode: pins 3, 4, 8 used
6N8/ EBF80	1 of 2	2800	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -2.4 Pent. G1-P Gm measured
6N8/ EBF80	2 of 2	-	0.6	-	20	Ef = 6.3 VAC Ebb = 20 Rl = 33,300 Ω Diode Ib measured Dual Test: 1st Diode: P pin 7 used 2nd Diode: P pin 8 used
6P5	1 of 1	1400	-	-	20	Ef = 6.3 VAC Eb = 100 Ec1 = -5.0 Gm measured
6Q5	1 of 3	-	100	-	20	Ef = 6.3 VAC Ebb = 150 Ec1 = 0 Rl = 2180 Ω Ik measured
6Q5	2 of 3	-	-	100	20	Ef = 6.3 VAC Etd measured at 60 MA OK under 25 V
6Q5	3 of 3	-	10	-	-	Ef = 6.3 VAC Eb = 150 Ec1 = -28 Ib measured OK under 1.0 MA
6Q7	1 of 2	1500	-	-	20	Ef = 6.3 VAC Eb = 100 Ec1 = -1.0 Triode Gm measured
6Q7	2 of 2	-	0.6	-	20	Ef = 6.3 VAC Ebb = 20 Rl = 33,300 Ω Diode Ib measured Dual Test: 1st Diode: P pin 5 used 2nd Diode: P pin 4 used
6R3/ EY81	1 of 1	-	148	-	10	Ef = 6.3 VAC Epp = 500 VAC (H-W) Rl = 5000 Ω Cl = 4 μf Io measured
6R4/ EC81	1 of 1	6900	-	-	50	Ef = 6.3 VAC Eb = 150 Ec1 = -2.0 Gm measured
6R7	1 of 2	2500	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -3.0 Triode Gm measured
6R7	2 of 2	-	0.6	-	20	Ef = 6.3 VAC Ebb = 20 Rl = 33,300 Ω Diode Ib measured Dual Test: 1st Diode: P pin 5 used 2nd Diode: P pin 4 used
6R8	1 of 3	2500	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -3.0 Triode Gm measured
6R8	2 of 3	-	22	-	20	Ef = 6.3 VAC Ebb = 9.0 Rl = 230 Ω Diode Ib measured Pins 6, 7 used

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
6R8	3 of 3	-	22	-	20	Ef = 6.3 VAC Ebb = 9.0 Rl = 230 Ω Diode Ib measured Dual Test: 1st Diode: pins 2 & 3 used 2nd Diode: pins 1 & 7 used
6S2/ EY86	1 of 1	-	6.0	-	-	Ef = 6.3 VAC Ebb = 100 Rl = 10,000 Ω Ib measured Fil pins 1 & 2 used
6S4	1 of 1	6900	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -2.0 Gm measured G pin 3 used
6S7	1 of 1	2200	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -2.5 G1-P Gm measured
6S8	1 of 3	1100	-	-	20	Ef = 6.3 VAC Eb = 100 Ec1 = -1.0 Triode Gm measured
6S8	2 of 3	-	0.74	-	20	Ef = 6.3 VAC Ebb = 20 Rl = 27,000 Ω Diode Ib measured Pins 3 & 5 used
6S8	3 of 3	-	0.74	-	20	Ef = 6.3 VAC Ebb = 20 Rl = 27,000 Ω Diode Ib measured Dual Test: 1st Diode: pins 2 & 4 used 2nd Diode: pins 1 & 2 used
6SA7	1 of 2	700	-	-	20	Ef = 6.3 VAC Eb = 100 Ec5 = 0 Ec2, 4 = 100 Ec1, 3 = -1.0 G3-P Gm measured
6SA7	2 of 2	4800	-	-	20	Ef = 6.3 VAC Eb = 100 Ec3, 5 = 0 Ec2, 4 = 100 Ec1 = -1.0 G1-P, G2, G4 Gm measured
6SB7	1 of 2	1500	-	-	20	Ef = 6.3 VAC Eb = 100 Ec5 = 0 Ec2, 4 = 100 Ec1, 3 = -3.0 G3-P Gm measured
6SB7	2 of 2	10,000	-	-	20	Ef = 6.3 VAC Eb = 100 Ec3, 5 = 0 Ec2, 4 = 100 Ec1 = -1.0 G1-P, G2, G4 Gm measured
6SC7	1 of 1	1400	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -1.0 Gm measured Dual Test: 1st Triode: pins 4, 5, 6 used 2nd Triode: pins 2, 3, 6 used
6SD7	1 of 1	4200	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -2.0 G1-P Gm measured
6SF5	1 of 1	1400	-	-	20	Ef = 6.3 VAC Eb = 100 Ec1 = -1.0 Gm measured
6SF7	1 of 2	2500	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -1.0 Pent. G1-P Gm measured
6SF7	2 of 2	-	0.6	-	20	Ef = 6.3 VAC Ebb = 20 Rl = 33,300 Ω Diode Ib measured
6SG7	1 of 1	5100	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Rk = 90 Ω G1-P Gm measured
6SH7	1 of 1	5000	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -1.0 G1-P Gm measured
6SJ7	1 of 1	2000	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -3.0 G1-P Gm measured

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
6SK7	1 of 1	3000	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -1.0 G1-P Gm measured
6SL7	1 of 1	1400	-	-	20	Ef = 6.3 VAC Eb = 100 Ec1 = -1.0 Gm measured Dual Test: 1st Triode: pins 4, 5, 6 used 2nd Triode: pins 1, 2, 3 used
6SN7	1 of 1	3500	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -2.9 Gm measured Dual Test: 1st Triode: pins 4, 5, 6 used 2nd Triode: pins 1, 2, 3 used
6SQ7	1 of 2	1100	-	-	20	Ef = 6.3 VAC Eb = 100 Ec1 = -1.0 Triode Gm measured
6SQ7	2 of 2	-	0.6	-	20	Ef = 6.3 VAC Ebb = 20 Rl = 33,300 Ω Diode Ib measured Dual Test: 1st Diode: P pin 5 used 2nd Diode: P pin 4 used
6SR7	1 of 2	2500	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -3.0 Triode Gm measured
6SR7	2 of 2	-	0.6	-	20	Ef = 6.3 VAC Ebb = 20 Rl = 33,300 Ω Diode Ib measured Dual Test: 1st Diode: P pin 5 used 2nd Diode: P pin 4 used
6SS7	1 of 1	2400	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -1.0 G1-P Gm measured
6ST7	1 of 2	2500	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -3.1 Triode Gm measured
6ST7	2 of 2	-	0.6	-	20	Ef = 6.3 VAC Ebb = 20 Rl = 33,300 Ω Diode Ib measured Dual Test: 1st Diode: P pin 5 used 2nd Diode: P pin 4 used
6SU7	1 of 2	1400	-	-	10	Ef = 6.3 VAC Eb = 100 Ec1 = -1.0 Gm measured Dual Test: 1st Triode: pins 4, 5, 6 used 2nd Triode: pins 1, 2, 3 used
6SU7	2 of 2	-	-	100	10	Ef = 6.3 VAC Etd measured at 40 MA OK under 30 V Dual Test: 1st Triode: pins 4, 5, 6 used 2nd Triode: pins 1, 2, 3 used
6SV7	1 of 2	4300	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -1.0 Pent. G1-P Gm measured
6SV7	2 of 2	-	6.1	-	20	Ef = 6.3 VAC Ebb = 9.0 Rl = 930 Ω Diode Ib measured
6SZ7	1 of 2	1500	-	-	20	Ef = 6.3 VAC Eb = 100 Ec1 = -1.0 Triode Gm measured
6SZ7	2 of 2	-	0.6	-	20	Ef = 6.3 VAC Ebb = 20 Rl = 33,300 Ω Diode Ib measured Dual Test: 1st Diode: P pin 4 used 2nd Diode: P pin 5 used
6T4	1 of 1	7600	-	-	20	Ef = 6.3 VAC Eb = 100 Rk = 270 Ω Gm measured

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
6T7	1 of 2	1200	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -1.7 Triode Gm measured
6T7	2 of 2	-	0.6	-	20	Ef = 6.3 VAC Ebb = 20 Rl = 33,300 Ω Diode Ib measured Dual Test: 1st Diode: P pin 5 used 2nd Diode: P pin 4 used
6T8	1 of 3	1600	-	-	20	Ef = 6.3 VAC Eb = 100 Ec1 = -1.0 Triode Gm measured
6T8	2 of 3	-	22	-	10	Ef = 6.3 VAC Ebb = 9.0 Rl = 115 Ω Diode Ib measured Pins 6 & 7 used
6T8	3 of 3	-	22	-	10	Ef = 6.3 VAC Ebb = 9.0 Rl = 115 Ω Diode Ib measured 1st Diode: pins 2 & 3 used 2nd Diode: pins 1 & 7 used
6U5	1 of 2	-	-	-	20	Ef = 6.3 VAC E (Screen) = Open ckt E (Target) = 300 Ec1 = 0 (Eye Open) Quality Test: No Meter Reading
6U5	2 of 2	-	-	-	20	Ef = 6.3 VAC E (Screen) = 150 E (Target) = 150 Ec1 = -64 (Eye Shut) Quality Test: No Meter Reading
6U6	1 of 1	7000	-	-	50	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -9.4 G1-P Gm measured
6U7	1 of 1	1900	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -3.0 G1-P Gm measured
6U8	1 of 2	5700	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Rk = 70 Ω Pent. G1-P Gm measured
6U8	2 of 2	10,700	-	-	20	Ef = 6.3 VAC Eb = 150 Rk = 60 Ω Triode Gm measured
6V3	1 of 1	-	148	-	10	Ef = 6.3 VAC Epp = 500 VAC (H-W) Rl = 5800 Ω Cl = 4 μf Io measured P pin 2 used
6V4/ EZ80	1 of 1	-	144	-	150	Ef = 6.3 VAC Epp = 250 VAC (F-W) Rl = 2800 Ω Cl = 4 μf Io measured
6V6	1 of 1	4700	-	-	50	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -4.2 G1-P Gm measured
6V7	1 of 2	1100	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -11 Triode Gm measured
6V7	2 of 2	-	0.6	-	20	Ef = 6.3 VAC Ebb = 20 Rl = 33,300 Ω Diode Ib measured Dual Test: 1st Diode: pins 5 & 8 used 2nd Diode: pins 2 & 8 used
6V8	1 of 3	1600	-	-	20	Ef = 6.3 VAC Eb = 100 Ec1 = -1.0 Triode Gm measured
6V8	2 of 3	-	0.6	-	20	Ef = 6.3 VAC Ebb = 20 Rl = 33,300 Ω Diode Ib measured Pins 3 & 9 used

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
6V8	3 of 3	-	44	-	10	Ef = 6.3 VAC Ebb = 9.0 Rl = 58 Ω Diode Ib measured Dual Test: 1st Diode: pins 7 & 8 used 2nd Diode: pins 2 & 3 used
6W4	1 of 1	-	148	-	10	Ef = 6.3 VAC Epp = 500 VAC (H-W) Rl = 5800 Ω Cl = 4 μf Io measured
6W6	1 of 1	10,100	-	-	70	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -12 G1-P Gm measured
6W7	1 of 1	1500	-	-	20	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -3.0 G1-P Gm measured
6X4	1 of 1	-	112	-	150	Ef = 6.3 VAC Epp = 250 VAC (F-W) Rl = 3950 Ω Cl = 4 μf Io measured
6X5	1 of 1	-	112	-	150	Ef = 6.3 VAC Epp = 250 VAC (F-W) Rl = 3950 Ω Cl = 4 μf Io measured
6X6	1 of 2	-	-	-	20	Ef = 6.3 VAC Ebb = 250 Rl = 100,000 Ω E (Target) = 250 Ec1 = 0 (Eye Open) Quality Test: No Meter Reading
6X6	2 of 2	-	-	-	20	Ef = 6.3 VAC Ebb = 250 Rl = 16,100 Ω Eb = E (Target) Rk = 6100 Ω (Eye Shut) Quality Test: No Meter Reading
6X8	1 of 2	5800	-	-	20	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 200 Ω Pent. G1-P Gm measured
6X8	2 of 2	7300	-	-	20	Ef = 6.3 VAC Eb = 100 Rk = 100 Ω Triode Gm measured
6Y6	1 of 1	9400	-	-	70	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -8.0 G1-P Gm measured
6Y7	1 of 1	1700	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -1.0 Gm measured Dual Test: 1st Triode: pins 5 & 6 used 2nd Triode: pins 3 & 4 used
6Z4	1 of 1	-	96	-	150	Ef = 6.3 VAC Epp = 250 VAC (F-W) Rl = 5000 Ω Cl = 4 μf Io measured
6Z5/ 12Z5	1 of 1	-	96	-	100	Ef = 6.3 VAC (Para.) Epp = 250 VAC (F-W) Rl = 3380 Ω Io measured
6ZY5	1 of 1	-	64	-	100	Ef = 6.3 VAC Epp = 250 VAC (F-W) Rl = 7100 Ω Cl = 4 μf Io measured
7A4	1 of 1	3500	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -2.9 Gm measured
7A5	1 of 1	7300	-	-	70	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -6.0 G1-P Gm measured

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
7A6	1 of 1	-	6.1	-	10	Ef = 6.3 VAC Ebb = 9.0 Rl = 425 Ω Ib measured Dual Test: 1st Diode: pins 6 & 7 used 2nd Diode: pins 2 & 3 used
7A7	1 of 1	3000	-	-	20	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -1.0 G1-P Gm measured
7A8	1 of 2	700	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2, 3, 5 = 100 Ec1, 4 = -1.0 G4-P Gm measured
7A8	2 of 2	2000	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2, 3, 5 = 100 Ec1, 4 = -1.0 G1-P, G3, G5 Gm measured
7AD7	1 of 1	12,000	-	-	20	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 60 Ω G1-P Gm measured
7AF7	1 of 1	2400	-	-	20	Ef = 6.3 VAC Eb = 100 Ec1 = -3.0 Gm measured Dual Test: 1st Triode: pins 5, 6, 7 used 2nd Triode: pins 2, 3, 4 used
7AG7	1 of 1	3300	-	-	20	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -1.0 G1-P Gm measured
7AH7	1 of 1	3400	-	-	20	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 250 Ω G1-P Gm measured
7AK7	1 of 3	6000	-	-	50	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -1.0 G1-P Gm measured
7AK7	2 of 3	-	5.0	-	50	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -12.5 Ib cut-off test OK under 2.5 MA
7AK7	3 of 3	-	4.0	-	50	Ef = 6.3 VAC Eb = 100 Ec3 = -8.3 Ec2 = 100 Ec1 = 0 Ib cut-off test OK under 2.0 MA
7AU7	1 of 1	3800	-	-	20	Ef = 3.5 VAC (Para.) Eb = 150 Ec1 = -3.0 Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
7B4	1 of 1	1400	-	-	20	Ef = 6.3 VAC Eb = 100 Ec1 = -1.0 Gm measured
7B5	1 of 1	1900	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -7.0 G1-P Gm measured
7B6	1 of 2	1100	-	-	20	Ef = 6.3 VAC Eb = 100 Ec1 = -1.0 Triode Gm measured
7B6	2 of 2	-	0.6	-	20	Ef = 6.3 VAC Ebb = 20 Rl = 33,300 Ω Diode Ib measured Dual Test: 1st Diode: P pin 6 used 2nd Diode: P pin 5 used
7B7	1 of 1	2100	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -3.0 G1-P Gm measured
7B8	1 of 2	700	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2, 3, 5 = 100 Ec1, 4 = -5.8 G4-P Gm measured

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
7B8	2 of 2	1800	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2, 3, 5 = 100 Ec4 = 0 Ec1 = -7.6 G1, P, G3, G5 Gm measured
7C4/ 1203A	1 of 1	-	14	-	20	Ef = 6.3 VAC Ebb = 100 Rl = 7500 Ω Ib measured
7C5	1 of 1	4700	-	-	50	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -4.2 G1-P Gm measured
7C6	1 of 2	1100	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -1.0 Triode Gm measured
7C6	2 of 2	-	0.6	-	20	Ef = 6.3 VAC Ebb = 20 Rl = 33,300 Ω Diode Ib measured Dual Test: 1st Diode: P pin 6 used 2nd Diode: P pin 5 used
7C7	1 of 1	2900	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -1.0 G1-P Gm measured
7DJ8/ PCC88	1 of 1	15,800	-	-	10	Ef = 6.3 VAC Eb = 100 Ec1 = -1.5 Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
7E5/ 1201	1 of 2	3800	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -2.4 Gm measured Pins 5, 6, 7 used
7E5/ 1201	2 of 2	3800	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -2.4 Gm measured Pins 1, 3, 4 used
7E6	1 of 2	2500	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -3.0 Triode Gm measured
7E6	2 of 2	-	0.6	-	20	Ef = 6.3 VAC Ebb = 20 Rl = 33,300 Ω Diode Ib measured Dual Test: 1st Diode: P pin 6 used 2nd Diode: P pin 5 used
7E7	1 of 2	2000	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -1.0 Pent. G1-P Gm measured
7E7	2 of 2	-	0.6	-	20	Ef = 6.3 VAC Ebb = 20 Rl= 33,300 Ω Diode Ib measured Dual Test: 1st Diode: P pin 4 used 2nd Diode: P pin 3 used
7ES8/ PCC189	1 of 1	15,800	-	-		Ef = 7.2 VAC Eb = 100 Ec1 = -1.5 Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
7EY6	1 of 2	7500	-	-	70	Ef = 7.2 VAC Eb = 150 Ec2 = 150 Ec1 = -5.1 G1-P Gm measured
7EY6	2 of 2	-	106	-	70	Ef = 7.2 VAC Ebb = 292 Rl = 3300 Ω Ec2 = 150 Ec1 = 0 Ib measured
7F7	1 of 1	1400	-	-	20	Ef = 6.3 VAC Eb = 100 Ec1 = -1.0 Gm measured Dual Test: 1st Triode: pins 5, 6, 7 used 2nd Triode: pins 2, 3, 4 used
7F8	1 of 1	6500	-	-	10	Ef = 6.3 VAC Eb = 150 Rk = 100 Ω Gm measured Dual Test: 1st Triode: pins 5, 6, 8 used 2nd Triode: pins 1, 3, 4 used

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
7G7/ 1232	1 of 1	5700	-	-	20	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -1.8 G1-P Gm measured
7G8	1 of 2	2300	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -2.5 G1-P Gm measured Tetrode pins 3, 5, 6, 7 used
7G8	2 of 2	2300	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -2.5 G1-P Gm measured Tetrode pins 2, 3, 4, 6 used
7H7	1 of 1	5000	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -1.5 G1-P Gm measured
7HG8/ PCF86	1 of 2	15,000	-	-	20	Ef = 8.0 VAC Eb = 150 Ec2 = 150 Ec1 = -1.2 Pent. G1-P Gm measured K pin 3 used
7HG8/ PCF86	2 of 2	6900	-	-	20	Ef = 8.0 VAC Eb = 100 Ec1 = -3.0 Triode Gm measured K pin 1 used
7J7	1 of 2	1000	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2, 4 = 100 Ec3 = 0 Ec1 = -3.0 Hept. G1-P Gm measured Hept. pins: 2, 4, 5, 6, 7 used
7J7	2 of 2	1800	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -3.0 Triode Gm measured
7K7	1 of 2	1700	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -1.0 Triode Gm measured
7K7	2 of 2	-	0.6	-	20	Ef = 6.3 VAC Ebb = 9.0 Rl = 11,100 Ω Diode Ib measured Dual Test: 1st Diode: P pin 6 used 2nd Diode: P pin 5 used
7L7	1 of 1	3800	-	-	20	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Rk = 120 Ω G1-P Gm measured
7N7	1 of 1	3500	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -2.9 Gm measured Dual Test: 1st Triode: pins 5, 6, 7 used 2nd Triode: pins 2, 3, 4 used
7Q7	1 of 2	900	-	-	20	Ef = 6.3 VAC Eb = 100 Ec5 = 0 Ec2, 4 = 100 Ec1, 3 = -1.0 G3-P Gm measured
7Q7	2 of 2	5700	-	-	20	Ef = 6.3 VAC Eb = 100 Ec3, 5 = 0 Ec2, 4 = 100 Ec1 = -1.0 G1-P, G2, G4 Gm measured
7R7	1 of 2	3800	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -1.0 Pent. G1-P Gm measured
7R7	2 of 2	-	0.6	-	20	Ef = 6.3 VAC Ebb = 20 Rl = 33,300 Ω Diode Ib measured Dual Test: 1st Diode: P pin 4 used 2nd Diode: P pin 3 used
7S7	1 of 2	1800	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2, 4 = 100 Ec3 = 0 Rk = 240 Ω Pent. G1-P Gm measured

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
7S7	2 of 2	1900	-	-	20	Ef = 6.3 VAC Eb = 100 Ec1 = -1.0 Triode Gm measured
7T7	1 of 1	5000	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -1.0 G1-P Gm measured
7V7	1 of 1	6900	-	-	20	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 160 Ω G1-P Gm measured
7W7	1 of 1	6900	-	-	20	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 160 Ω G1-P Gm measured
7X6	1 of 1	-	120	-	100	Ef = 6.3 VAC Epp = 250 VAC (H-W) Rl = 2550 Ω Cl = 4 μf Io measured Dual Test: 1st Diode: pins 6 & 7 used 2nd Diode: pins 2 & 3 used
7X7	1 of 2	1400	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -1.0 Triode Gm measured
7X7	2 of 2	-	10.1	-	20	Ef = 6.3 VAC Ebb = 9.0 Rl = 255 Ω Diode Ib measured Dual Test: 1st Diode: pins 6 & 7 used 2nd Diode: pins 4 & 5 used
7Y4	1 of 1	-	112	-	150	Ef = 6.3 VAC Epp = 250 VAC (F-W) Rl = 3950 Ω Cl = 4 μf Io measured
7Z4	1 of 1	-	160	-	150	Ef = 6.3 VAC Epp = 250 VAC (F-W) Rl = 3950 Ω Cl = 4 μf Io measured
8AU8	1 of 2	8800	-	-	20	Ef = 8.4 VAC Eb = 100 Ec2 = 100 Rk = 60 Ω Pent. G1-P Gm measured
8AU8	2 of 2	6200	-	-	20	Ef = 8.4 VAC Eb = 150 Rk = 150 Ω Triode Gm measured
8AW8A	1 of 2	11,300	-	-	20	Ef = 8.4 VAC Eb = 150 Ec2 = 150 Rk = 180 Ω Pent. G1-P Gm measured
8AW8A	2 of 2	6300	-	-	20	Ef = 8.4 VAC Eb = 150 Ec1 = -1.2 Triode Gm measured
8B8/ XCL82	1 of 2	8600	-	-	50	Ef = 8.0 VAC Eb = 100 Ec2 = 100 Ec1 = -6.0 Pent. G1-P Gm measured
8B8/ XCL82	2 of 2	3200	-	-	20	Ef = 8.0 VAC Eb = 150 Ec1 = -1.2 Triode Gm measured
8BA8A	1 of 2	10,700	-	-	20	Ef = 8.4 VAC Eb = 150 Ec2 = 150 Rk = 180 Ω Pent. G1-P Gm measured
8BA8A	2 of 2	3800	-	-	20	Ef = 8.4 VAC Eb = 150 Ec1 = -5.0 Triode Gm measured
8BH8	1 of 2	8800	-	-	20	Ef = 8.4 VAC Eb = 100 Ec2 = 100 Rk = 60 Ω Pent. G1-P Gm measured
8BH8	2 of 2	4100	-	-	20	Ef = 8.4 VAC Eb = 150 Ec1 = -5.0 Triode Gm measured
8BN8	1 of 2	4400	-	-	20	Ef = 8.4 VAC Eb = 100 Ec1 = -1.0 Triode Gm measured

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
8BN8	2 of 2	-	22	-	10	Ef = 8.4 VAC Ebb = 9.0 Rl = 115 Ω Diode Ib measured Dual Test: 1st Diode: pins 3 & 6 used 2nd Diode: pins 1 & 2 used
8BQ5/ XL84	1 of 1	14,200	-	-	70	Ef = 8.0 VAC Eb = 150 Ec2 = 150 Ec1 = -2.0 G1-P Gm measured
8CG7	1 of 1	3500	-	-	20	Ef = 8.4 VAC Eb = 150 Ec1 = -2.9 Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
8CM7	1 of 2	3300	-	-	20	Ef = 8.4 VAC Eb = 150 Ec1 = -4.0 Gm measured Pins 3, 6, 7 used
8CM7	2 of 2	6300	-	-	20	Ef = 8.4 VAC Eb = 150 Ec1 = -3.5 Gm measured Pins 1, 8, 9 used
8CN7	1 of 2	1600	-	-	20	Ef = 4.2 VAC (Para.) Eb = 100 Ec1 = -1.0 Triode Gm measured
8CN7	2 of 2	-	22	-	10	Ef = 4.2 VAC (Para.) Ebb = 9.0 Rl = 115 Ω Diode Ib measured Dual Test: 1st Diode: P pin 2 used 2nd Diode: P pin 1 used
8CS7	1 of 2	3200	-	-	20	Ef = 8.4 VAC Eb = 150 Ec1 = -2.0 Gm measured Pins 6, 7, 8 used
8CS7	2 of 2	6670	-	-	20	Ef = 8.4 VAC Eb = 150 Ec1 = -4.2 Gm measured Pins 1, 3, 9 used
8CX8	1 of 2	13,000	-	-	20	Ef = 8.0 VAC Eb = 100 Ec2 = 100 Rk = 40 Ω Pent. G1-P Gm measured
8CX8	2 of 2	6000	-	-	20	Ef = 8.0 VAC Eb = 150 Rk = 150 Ω Triode Gm measured
8CY7	1 of 3	1600	-	-	20	Ef = 7.9 VAC Eb = 150 Ec1 = -1.5 Gm measured Pins 6, 7, 8 used
8CY7	2 of 3	6800	-	-	20	Ef = 7.9 VAC Eb = 150 Rk = 620 Ω Gm measured Pins 1, 3, 9 used
8CY7	3 of 3	-	128	-	20	Ef = 7.9 VAC Ebb = 150 Rl = 1125 Ω Ib measured Pins 1, 3, 9 used
8EB8	1 of 2	14,500	-	-	20	Ef = 8.0 VAC Eb = 100 Ec2 = 100 Rk = 60 Ω Pent. G1-P Gm measured
8EB8	2 of 2	3500	-	-	20	Ef = 8.0 VAC Eb = 150 Ec1 = -1.2 Triode Gm measured
8EM5	1 of 2	6400	-	-	70	Ef = 8.4 VAC Eb = 150 Ec2 = 150 Ec1 = -8.5 G1-P Gm measured G pin 3 used
8EM5	2 of 2	-	120	-	70	Ef = 8.4 VAC Ebb = 286 Rl = 2900 Ω Ec2 = 150 Ec1 = 0 Ib measured G pin 6 used
8ET7	1 of 3	14,500	-	-	20	Ef = 8.0 VAC Eb = 150 Ec2 = 150 Rk = 100 Ω Pent. G1-P Gm measured

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
8ET7	2 of 3	-	70	-	20	Ef = 8.0 VAC Ebb = 297 Rl = 4300 Ω Ec2 = 150 Ec1 = 0 Pent. Ib measured
8ET7	3 of 3	-	0.6	-	20	Ef = 8.0 VAC Ebb = 20 Rl = 33,300 Ω Diode Ib measured Dual Test: 1st Diode: P pin 3 used 2nd Diode: P pin 2 used
8FQ7	1 of 1	3500	-	-	20	Ef = 8.4 VAC Eb = 150 Ec1 = -2.9 Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
8GN8	1 of 3	14,500	-	-	20	Ef = 8.0 VAC Eb = 150 Ec2 = 150 Rk = 90 Ω Pent. G1-P Gm measured
8GN8	2 of 3	-	76	-	20	Ef = 8.0 VAC Ebb = 297 Rl =4260 Ec2 = 150 Ec1 = 0 Pent. Ib measured
8GN8	3 of 3	3400	-	-	20	Ef = 8.0 VAC Eb = 150 Ec1 = -1.2 Triode Gm measured
8JK8	1 of 2	8500	-	-	20	Ef = 8.4 VAC Eb = 100 Ec1 = -1.0 Gm measured Pins 6, 7, 8 used
8JK8	2 of 2	16,000	-	-	20	Ef = 8.4 VAC Eb = 150 Ec1 = -1.4 Gm measured Pins 1, 2, 3 used
8JT8	1 of 2	24,000	-	-	20	Ef = 7.7 VAC Eb = 100 Ec2 = 100 Rk = 80 Ω Pent. G1-P Gm measured
8JT8	2 of 2	3400	-	-	20	Ef = 7.7 Eb = 150 Ec1 = -1.3 Triode Gm measured
8JV8	1 of 2	10,800	-	-	20	Ef = 8.5 V Eb = 150 Ec2 = 150 Ec1 = -2.2 Pent. G1-P Gm measured
8JV8	2 of 2	5000	-	-	20	Ef = 8.5 V Eb = 150 Ec1 = -1.5 Triode Gm measured
8KA8	1 of 2	5500	-	-	20	Ef = 8.4 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Rk = 110 Ω Pent. G1-P Gm measured
8KA8	2 of 2	5000	-	-	20	Ef = 8.4 VAC Eb = 150 Ec1 = -1.3 Triode Gm measured
8KS8	1 of 2	12,000	-	-	20	Ef = 8.4 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 150 Ω Pent. G1-P Gm measured
8KS8	2 of 2	5000	-	-	20	Ef = 8.4 VAC Eb = 150 Ec1 = -1.4 Triode Gm measured
8SN7	1 of 1	3500	-	-	20	Ef = 8.4 VAC Eb = 150 Ec1 = -2.9 Gm measured Dual Test: 1st Triode: pins 4, 5, 6 used 2nd Triode: pins 1, 2, 3 used
9A8/ PCF80	1 of 2	7800	-	-	20	Ef = 9.0 VAC Eb = 150 Ec2 = 150 Ec1 = -1.7 Pent. G1-P Gm measured
9A8/ PCF80	2 of 2	6300	-	-	20	Ef = 9.0 VAC Eb = 100 Ec1 = -2.0 Triode Gm measured

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
9AQ8/ PCC85	1 of 1	5800	-	-	20	Ef = 9.0 VAC Eb = 100 Ec1 = -1.1 Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
9AU7	1 of 1	3800	-	-	20	Ef = 4.7 VAC (Para.) Eb = 150 Ec1 = -3.0 Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
9BR7	1 of 2	5000	-	-	20	Ef = 4.7 VAC (Para.) Eb = 100 Rk = 270 Ω Triode Gm measured
9BR7	2 of 2	-	18	-	10	Ef = 4.7 VAC (Para.) Ebb = 9.0 Rl = 140 Ω Diode Ib measured Dual Test: 1st Diode: P pin 7 used 2nd Diode: P pin 6 used
9CL8	1 of 2	6000	-	-	20	Ef = 9.5 VAC Eb = 150 Ec2 = 150 Ec1 = -2.0 Pent. G1-P Gm measured
9CL8	2 of 2	6300	-	-	20	Ef = 9.5 VAC Eb = 150 Rk = 220 Ω Triode Gm measured
9DZ8	1 of 2	9500	-	-	50	Ef = 9.0 VAC Eb = 100 Ec2 = 100 Rk = 140 Ω Pent. G1-P Gm measured
9DZ8	2 of 2	1800	-	-	20	Ef = 9.0 VAC Eb = 100 Rk = 1200 Ω Triode Gm measured
9GV8/ XCL85	1 of 3	9400	-	-	20	Ef = 9.5 VAC Eb = 150 Ec2 = 150 Ec1 = -13 Pent. G1-P Gm measured
9GV8/ XCL85	2 of 3	-	266	-	20	Ef = 9.5 VAC Ebb = 235 Rl = 1070 Ω Ec2 = 150 Ec1 = 0 Pent. Ib measured
9GV8/ XCL85	3 of 3	6400	-	-	20	Ef = 9.5 VAC Eb = 100 Ec1 = -1.0 Triode Gm measured
9U8	1 of 2	5700	-	-	20	Ef = 9.4 VAC Eb = 100 Ec2 = 100 Rk = 70 Ω Pent. G1-P Gm measured
9U8	2 of 2	10,700	-	-	20	Ef = 9.4 VAC Eb = 150 Rk = 60 Ω Triode Gm measured
9X8	1 of 2	5800	-	-	20	Ef = 9.5 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 200 Ω Pent. G1-P Gm measured
9X8	2 of 2	7300	-	-	20	Ef = 9.5 VAC Eb = 100 Rk = 100 Ω Triode Gm measured
10BQ5	1 of 1	14,200	-	-	70	Ef = 10.6 VAC Eb = 150 Ec2 = 150 Ec1 = -2.0 G1-P Gm measured
10C8	1 of 3	8800	-	-	20	Ef = 10.5 VAC Eb = 150 Ec2 = 150 Rk = 150 Ω Pent. G1-P Gm measured
10C8	2 of 3	-	54.1	-	20	Ef = 10.5 VAC Eb = 150 Ec2 = 150 Ec1 = 0 Pent. Ib measured
10C8	3 of 3	5550	-	-	20	Ef = 10.5 VAC Eb = 150 Rk = 300 Ω Triode Gm measured

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
10DA7	1 of 3	3500	-	-	20	Ef = 10.5 VAC Eb = 150 Ec1 = -2.9 Gm measured Pins 6, 7, 8 used
10DA7	2 of 3	7200	-	-	50	Ef = 10.5 VAC Eb = 150 Ec1 = -18 Gm measured Pins 1, 3, 9 used
10DA7	3 of 3	-	102.1	-	50	Ef = 10.5 VAC Ebb = 150 Ec1 = 0 Rl = 1120 Ω Ib measured Pins 1, 3, 9 used
10DE7	1 of 3	3400	-	-	20	Ef = 10.0 VAC Eb = 150 Ec1 = -4.0 Gm measured Pins 6, 7, 8 used
10DE7	2 of 3	8200	-	-	20	Ef = 10.0 VAC Eb = 150 Ec1 = -18 Gm measured Pins 1, 3, 9 used
10DE7	3 of 3	-	98	-	20	Ef = 10.0 VAC Eb = 50 Ec1 = 0 Ib measured Pins 1, 2, 9 used
10DR7	1 of 3	2000	-	-	20	Ef = 9.7 VAC Eb = 150 Ec1 = -1.8 Gm measured Pins 6, 7, 8 used
10DR7	2 of 3	8200	-	-	20	Ef = 9.7 VAC Eb = 150 Ec1 = -18 Gm measured Pins 1, 3, 9 used
10DR7	3 of 3	-	98	-	20	Ef = 9.7 VAC Eb = 50 Ec1 = 0 Ib measured Pins 1, 2, 9 used
10EG7	1 of 3	3400	-	-	20	Ef = 9.7 VAC Eb = 150 Ec1 = -4.0 Gm measured Triode pins 4, 5, 6 used
10EG7	2 of 3	9500	-	-	50	Ef = 9.7 VAC Eb = 150 Ec1 = -18 Gm measured Triode pins 1, 2, 3 used
10EG7	3 of 3	-	134	-	50	Ef = 9.7 VAC Ebb = 150 Ec1 = 0 Rl = 950 Ω Ib measured Triode pins 1, 2, 3 used
10EM7	1 of 3	2000	-	-	20	Ef = 9.7 VAC Eb = 150 Ec1 = -1.8 Gm measured Pins 4, 5, 6 used
10EM7	2 of 3	9100	-	-	20	Ef = 9.7 VAC Eb = 150 Ec1 = -20 Gm measured Pins 1, 2, 3 used
10EM7	3 of 3	-	112	-	20	Ef = 9.7 VAC Eb = 50 Ec1 = 0 Ib measured Pins 1, 2, 3 used
10EW7	1 of 2	2500	-	-	20	Ef = 10.6 VAC Eb = 150 Ec1 = -6.0 Gm measured Pins 6, 7, 8 used
10EW7	2 of 2	9400	-	-	50	Ef = 10.6 VAC Eb = 150 Ec1 = -18 Gm measured Pins 1, 2, 9 used
10FD7	1 of 2	2000	-	-	20	Ef = 9.7 VAC Eb = 150 Ec1 = -1.8 Gm measured Pins 6, 7, 8 used
10FD7	2 of 2	9400	-	-	20	Ef = 9.7 VAC Eb = 150 Ec1 = -18 Gm measured Pins 1, 2, 9 used
10GF7	1 of 2	2000	-	-	20	Ef = 9.7 VAC Eb = 150 Ec1 = -1.2 Gm measured Pins 1, 8, 9 used Hickok Adapter 1050-144 required
10GF7	2 of 2	9100	-	-	100	Ef = 9.7 VAC Eb = 150 Ec1 = -20 Gm measured Pins 2, 3, 6 used Hickok Adapter 1050-144 required

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
10GN8	1 of 3	14,500	-	-	20	Ef = 10.0 VAC Eb = 150 Ec2 = 150 Rk = 90 Ω Pent. G1-P Gm measured
10GN8	2 of 3	-	76	-	20	Ef = 10.0 VAC Ebb = 297 Rl = 4260 Ω Ec2 = 150 Ec1 = 0 Pent. Ib measured
10GN8	3 of 3	3400	-	-	20	Ef = 10.0 VAC Eb = 150 Ec1 = -1.2 Triode Gm measured
10HF8	1 of 2	15,700	-	-	20	Ef = 10.5 VAC Eb = 150 Ec2 = 150 Rk = 70 Ω Pent. G1-P Gm measured
10HF8	2 of 2	5000	-	-	20	Ef = 10.5 VAC Eb = 150 Ec1 = -1.4 Triode Gm measured
10JT8	1 of 2	24,000	-	-	20	Ef = 10.2 VAC Eb = 100 Ec2 = 100 Rk = 80 Ω Pent. G1-P Gm measured
10JT8	2 of 2	3400	-	-	20	Ef = 10.2 VAC Eb = 150 Ec = -1.3 Triode Gm measured
10JY8	1 of 2	13,900	-	-	20	Ef = 10.5 VAC Eb = 150 Ec2 = 150 Rk = 90 Ω Pent. G1-P Gm measured
10JY8	2 of 2	13,100	-	-	20	Ef = 10.5 VAC Eb = 150 Rk = 80 Ω Triode Gm measured
10LB8	1 of 2	25,200	-	-	20	Ef = 10.2 VAC Eb = 100 Ec2 = 100 Rk = 80 Ω Pent. G1-P Gm measured
10LB8	2 of 2	6550	-	-	20	Ef = 10.2 VAC Eb = 150 Rk = 70 Ω Triode Gm measured
11C5	1 of 1	7300	-	-	70	Ef = 11.6 VAC Eb = 100 Ec2 = 100 Ec1 = -6.0 G1-P Gm measured
11CY7	1 of 3	1600	-	-	20	Ef = 11.0 VAC Eb = 150 Ec1 = -1.5 Gm measured Pins 6, 7, 8 used
11CY7	2 of 3	6800	-	-	20	Ef = 11.0 VAC Eb = 150 Rk = 620 Ω Gm measured Pins 1, 3, 9 used
11CY7	3 of 3	-	128	-	20	Ef = 11.0 VAC Eb = 150 Rl = 1120 Ω Ec1 = 0 Ib measured Pins 1, 3, 9 used
11JE8	1 of 2	15,000	-	-	20	Ef = 10.9 VAC Eb = 150 Ec2 = 150 Rk = 80 Ω Pent. G1-P Gm measured
11JE8	2 of 2	5800	-	-	20	Ef = 10.9 VAC Eb = 150 Ec1 = -1.4 Triode Gm measured
12A4	1 of 1	11,300	-	-	20	Ef = 6.3 VAC (Para.) Eb = 150 Ec1 = -4.2 Gm measured
12A6	1 of 1	4000	-	-	100	Ef = 12.6 VAC Eb = 150 Ec2 = 150 Ec1 = -2.0 G1-P Gm measured
12A7	1 of 2	1300	-	-	20	Ef = 12.6 VAC Eb = 100 Ec2 = 100 Ec1 = -7.4 Pent. G1-P Gm measured
12A7	2 of 2	-	48	-	20	Ef = 12.6 VAC Epp = 250 VAC (H-W) Rl = 3300 Ω Diode Io measured
12A8	1 of 2	700	-	-	20	Ef = 12.6 VAC Eb = 100 Ec2, 3, 5 = 100 Ec1, 4 = -5.8 G4-P Gm measured

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
12A8	2 of 2	1800	-	-	20	Ef = 12.6 VAC Eb = 100 Ec2, 3, 5 = 100 Ec4 = 0 Ec1 = -7.6 G1-P, G3, G5, Gm measured
12AB5	1 of 1	4700	-	-	50	Ef = 12.6 VAC Eb = 150 Ec2 = 150 Ec1 = -4.2 Pent. G1-P Gm measured G1 pin 3, G2 pin 1 used
12AC6	1 of 1	600	-	-	20	Ef = 12.6 VAC Eb = 9.0 Ec3 = 0 Ec2 = 9.0 Ec1 = -1.0 Pent. G1-P, G2 Gm measured
12AD6	1 of 1	750	-	-	20	Ef = 12.6 VAC Eb = 9.0 Ec3 = 0 Ec2 = 9.0 Ec1 = -1.0 Pent. G1-P, G2 Gm measured
12AD7	1 of 1	2300	-	-	10	Ef = 6.3 VAC (Para.) Eb = 150 Ec = -1.0 Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
12AE6	1 of 2	600	-	-	20	Ef = 12.6 VAC Eb = 9.0 Ec1 = -1.0 Triode Gm measured
12AE6	2 of 2	-	0.6	-	20	Ef = 12.6 VAC Eb = 20 Rl = 33,300 Ω Diode Ib measured Dual Test: 1st Diode: P pin 6 used 2nd Diode: P pin 5 used
12AE7	1 of 2	3300	-	-	20	Ef = 6.3 VAC (Para.) Eb = 9.0 Ec1 = -1.0 Gm measured Pins 6, 7, 8 used
12AE7	2 of 2	6000	-	-	20	Ef = 6.3 VAC (Para.) Eb = 9.0 Ec1 = -1.0 Gm measured Pins 1, 2, 3 used
12AF3	1 of 1	-	148	-	10	Ef = 12.6 VAC Epp = 500 VAC (H-W) Rl = 5100 Ω Cl = 4 μf Io measured
12AF6	1 of 1	1600	-	-	20	Ef = 12.6 VAC Eb = 9.0 Ec3 = 0 Ec2 = 9.0 Ec1 = -1.0 Pent. G1-P Gm measured
12AG6	1 of 1	1500	-	-	20	Ef = 12.6 VAC Eb = 9.0 Ec3 = 0 Ec2 = 9.0 Ec1 = -1.0 Pent. G1-P, G2 Gm measured
12AH7	1 of 1	2000	-	-	20	Ef = 17.6 VAC Eb = 100 Ec1 = -3.6 Gm measured Dual Test: 1st Triode: pins 4, 5, 6 used 2nd Triode: pins 1, 2, 3 used
12AJ6	1 of 3	-	-	-	10	Ef = 17.6 VAC Shorts and Leakage tests only. Quality meter reading not dependent on tube. Triode: pins 1, 2, 7 used
12AJ6	2 of 3	-	0.63	-	10	Ef = 12.6 VAC Eb = 12.6 Ec1 = 0 Triode Ib measured
12AJ6	3 of 3	-	0.6	-	20	Ef = 17.6 VAC Ebb = 20 Rl = 33,300 Ω Diode Ib measured Dual Test: 1st Diode: P pin 6 used 2nd Diode: P pin 5 used
12AJ7/HCH81	1 of 2	2600	-	-	20	Ef = 12.6 VAC Eb, Ec2, 4 = 150 Ec5, 3 = 0 Ec1 = -4.0 Heptode G1-P Gm measured

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
12AJ7/ HCH81	2 of 2	4000	-	-	20	Ef = 12.6 VAC Eb = 100 Ec1 = -1.0 Triode Gm measured
12AL5	1 of 1	-	26	-	10	Ef = 12.6 VAC Ebb = 6.0 Rl = 100 Ω Ib measured Dual Test: 1st Diode: pins 1 & 7 used 2nd Diode: pins 2 & 5 used
12AL8	1 of 2	5700	-	-	70	Ef = 12.6 VAC Eb = 9.0 Ec2 = -1.0 Ec1 = 9.0 Pent. G2-P, G1 Gm measured
12AL8	2 of 2	-	0.3	0	10	Ef = 12.6 VAC Eb = 1.0 Ec1 = 0 Triode Ib measured
12AQ5	1 of 1	4700	-	-	50	Ef = 12.6 VAC Eb = 150 Ec2 = 150 Ec1 = -4.2 G1-P Gm measured
12AS5	1 of 1	7000	-	-	50	Ef = 12.6 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -6.5 G1-P Gm measured
12AT6	1 of 2	1700	-	-	20	Ef = 12.6 VAC Eb = 100 Ec1 = -1.0 Triode Gm measured
12AT6	2 of 2	-	0.6	-	20	Ef = 12.6 VAC Ebb = 20 Rl = 33,300 Ω Diode Ib measured Dual Test: 1st Diode: P pin 6 used 2nd Diode: P pin 5 used
12AT7	1 of 1	5000	-	-	20	Ef = 6.3 VAC (Para.) Eb = 100 Rk = 270 Ω Gm measured Dual Test: 1st Triode; pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
12AU6	1 of 1	6300	-	-	20	Ef = 12.6 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 70 Ω G1-P Gm measured
12AU7	1 of 1	3800	-	-	20	Ef = 6.3 VAC (Para.) Eb = 150 Ec1 = -3.0 Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
12AU8	1 of 2	8800	-	-	20	Ef = 12.6 VAC Eb = 100 Ec2 = 100 Rk = 60 Ω Pent. G1-P Gm measured
12AU8	2 of 2	6200	-	-	20	Ef = 12.6 VAC Eb = 150 Rk = 150 Ω Triode Gm measured
12AV5	1 of 2	6900	-	-	100	Ef = 12.6 VAC Eb = 150 Ec2 = 150 Ec1 = -21 Pent. G1-P Gm measured
12AV5	2 of 2	-	316	-	100	Ef = 12.6 VAC Ebb = 230 Rl = 750 Ω Ec2 = 150 Ec1 = 0 Ib measured
12AV6	1 of 2	1600	-	-	20	Ef = 12.6 VAC Eb = 100 Ec1 = -1.0 Triode Gm measured
12AV6	2 of 2	-	0.6	-	20	Ef = 12.6 VAC Ebb = 20 Rl = 33,300 Ω Diode Ib measured Dual Test: 1st Diode: P pin 6 used 2nd Diode: P pin 5 used

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
12AV7	1 of 1	10,700	-	-	20	Ef = 6.3 VAC (Para.) Eb = 150 Rk = 60 Ω Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
12AW6	1 of 1	6000	-	-	20	Ef = 12.6 VAC Eb = 100 Ec2 = 100 Rk = 100 Ω G1-P Gm measured
12AX4	1 of 1	-	148	-	10	Ef = 12.6 VAC Epp = 500 VAC (H-W) Rl = 5500 Ω Cl = 4 μf Io measured
12AX7	1 of 1	1600	-	-	20	Ef = 6.3 VAC (Para.) Eb = 250 Ec1 = -2.0 Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
12AY3	1 of 1	-	148	-	10	Ef = 12.6 VAC Epp = 500 VAC (H-W) Rl = 5500 Ω Cl = 4 μf Io measured Hickok Adapter 1050-144 required
12AY7	1 of 1	2200	-	-	10	Ef = 6.3 VAC (Para.) Eb = 150 Ec1 = -2.0 Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
12AZ7	1 of 1	5000	-	-	20	Ef = 6.3 VAC (Para.) Eb = 100 Rk = 270 Ω Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
12B4A	1 of 1	7900	-	-	20	Ef = 6.3 VAC (Para.) Eb = 150 Ec1 = -18 Gm measured
12BA6	1 of 1	5400	-	-	20	Ef = 12.6 VAC Eb = 100 Ec2 = 100 Rk = 70 Ω G1-P Gm measured
12BA7	1 of 2	2200	-	-	20	Ef = 12.6 VAC Eb = 100 Ec5 = 0 Ec2, 4 = 100 Ec1, 3 = -1.0 G3-P Gm measured
12BA7	2 of 2	8800	-	-	20	Ef = 12.6 VAC Eb = 100 Ec3, 5 = 0 Ec2, 4 = 100 Ec1 = -1.0 G1-P, G2, G4 Gm measured
12BD6	1 of 1	3200	-	-	20	Ef = 12.6 VAC Eb = 100 Ec2 = 100 Ec1 = -1.0 G1-P Gm measured
12BE6	1 of 2	600	-	-	20	Ef = 12.6 VAC Eb = 100 Ec2 = 100 Ec1 = -3.1 G3-P Gm measured
12BE6	2 of 2	8600	-	-	20	Ef = 12.6 VAC Eb = 100 Ec2, 4 = 100 Ec3 = 0 Ec1 = -1.0 G1-P, G2, G4 Gm measured
12BF6	1 of 2	2500	-	-	20	Ef = 12.6 VAC Eb = 150 Ec1 = -3.0 Triode Gm measured
12BF6	2 of 2	-	0.6	-	20	Ef = 12.6 VAC Ebb = 20 Rl = 33,300 Ω Diode Ib measured Dual Test: 1st Diode: P pin 6 used 2nd Diode: P pin 5 used
12BH7A	1 of 1	4800	-	-	20	Ef = 6.3 VAC (Para.) Eb = 150 Ec1 = -5.0 Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
12BK5	1 of 1	10,000	-	-	70	Ef = 12.6 VAC Eb = 150 Ec2 = 150 Ec1 = -1.0 G1-P Gm measured
12BK6	1 of 2	1600	-	-	20	Ef = 12.6 VAC Eb = 100 Ec1 = -1.0 Triode Gm measured
12BK6	2 of 2	-	1.2	-	20	Ef = 12.6 VAC Ebb = 20 Rl = 16,700 Ω Diode Ib measured Dual Test: 1st Diode: P pin 6 used 2nd Diode: P pin 5 used
12BL6	1 of 1	1700	-	-	20	Ef = 12.6 VAC Eb = 9.0 Ec2 = 9.0 Ec3 = 0 Ec1 = -0.9 G1-P, G2 Gm measured
12BN6	1 of 2	1500	-	-	20	Ef = 12.6 VAC Eb = 50 Ec2, 3 = 50 Rk = 350 Ω G1-P Gm measured
12BN6	2 of 2	1500	-	-	20	Ef = 12.6 VAC Eb = 50 Ec1, 2 = 50 Rk = 150 Ω G1-P Gm measured
12BQ6	1 of 2	6900	-	-	100	Ef = 12.6 VAC Eb = 150 Ec2 = 150 Ec1 = -21 G1-P Gm measured
12BQ6	2 of 2	-	316	-	100	Ef = 12.6 VAC Ebb = 230 Ec2 = 150 Ec1 = 0 Rl = 750 Ω Ib measured
12BR7	1 of 2	5000	-	-	20	Ef = 6.3 VAC (Para.) Eb = 100 Rk = 270 Ω Triode Gm measured
12BR7	2 of 2	-	18	-	10	Ef = 6.3 VAC (Para.) Ebb = 9.0 Rl = 140 Ω Diode Ib measured Dual Test: 1st Diode: P pin 7 used 2nd Diode: P pin 6 used
12BS3	1 of 1	-	148	-	10	Ef = 12.6 VAC Epp = 500 VAC (H-W) Rl = 6100 Ω Cl = 4 μf Io measured Hickok Adapter 1050-144 required
12BT6	1 of 2	1700	-	-	20	Ef = 12.6 VAC Eb = 100 Ec1 = -1.0 Triode Gm measured
12BT6	2 of 2	-	1.2	-	20	Ef = 12.6 VAC Ebb = 20 Rl = 16,700 Ω Diode Ib measured Dual Test: 1st Diode: P pin 6 used 2nd Diode: P pin 5 used
12BV7	1 of 1	13,800	-	-	20	Ef = 6.3 VAC (Para.) Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 70 Ω G1-P Gm measured
12BW4	1 of 1	-	160	-	150	Ef = 12.6 VAC Epp = 250 VAC (F-W) Rl = 2400 Ω Cl = 4 μf Io measured
12BX6	1 of 2	9300	-	-	20	Ef = 12.6 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Ec1 = -1.7 Pent. G1-P Gm measured K pin 3 used
12BX6	2 of 2	9300	-	-	20	Ef = 12.6 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Ec1 = -1.7 Pent. G1-P Gm measured K pin 1 used

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
12BY7A	1 of 1	13,800	-	-	20	Ef = 6.3 VAC (Para.) Eb = 150 Ec2 = 150 Rk = 70 Ω G1-P Gm measured
12BZ6	1 of 1	7300	-	-	20	Ef = 12.6 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 180 Ω G1-P Gm measured
12BZ7	1 of 1	4500	-	-	20	Ef = 6.3 VAC (Para.) Eb = 150 Ec1 = -1.0 Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
12C5	1 of 1	10,000	-	-	70	Ef = 12.6 VAC Eb = 100 Ec2 = 100 Ec1 = -6.2 G1-P Gm measured
12C8	1 of 2	1200	-	-	20	Ef = 12.6 VAC Eb = 100 Ec2 = 100 Ec1 = -3.0 Pent. G1-P Gm measured
12C8	2 of 2	-	0.6	-	20	Ef = 12.6 VAC Ebb = 20 Rl = 33,300 Ω Diode Ib measured Dual Test: 1st Diode: P pin 5 used 2nd Diode: P pin 4 used
12CA5	1 of 1	10,000	-	-	70	Ef = 12.6 VAC Eb = 100 Ec2 = 100 Ec1 = -3.2 G1-P Gm measured G pin 2 used
12CM6	1 of 1	4700	-	-	50	Ef = 12.6 VAC Eb = 150 Ec2 = 150 Ec1 = -4.2 G1-P Gm measured G pin 3 used
12CN5	1 of 1	3200	-	-	50	Ef = 12.6 VAC Eb = 9.0 Ec2 = 9.0 Ec1 = -1.0 G1-P Gm measured
12CR6	1 of 2	2500	-	-	20	Ef = 12.6 VAC Eb = 100 Ec2 = 100 Ec1 = -2.0 Pent. G1-P Gm measured
12CR6	2 of 2	-	0.6	-	20	Ef = 12.6 VAC Ebb = 20 Rl = 33,300 Ω Diode Ib measured
12CS6	1 of 2	1500	-	-	20	Ef = 12.6 VAC Eb = 50 Ec2, 4 = 50 Ec3 = 0 Ec1 = -1.5 G1-P Gm measured
12CS6	2 of 2	1500	-	-	20	Ef = 12.6 VAC Eb = 50 Ec2, 4 = 50 Ec3 = -1.0 Ec1 = 0 G3-P Gm measured
12CT8	1 of 2	8800	-	-	20	Ef = 12.6 VAC Eb = 100 Ec2 = 100 Rk = 60 Ω Pent. G1-P Gm measured
12CT8	2 of 2	6200	-	-	20	Ef = 12.6 VAC Eb = 150 Rk = 150 Ω Triode Gm measured
12CU5	1 of 1	9400	-	-	70	Ef = 12.6 VAC Eb = 100 Ec2 = 100 Ec1 = -6.2 G1-P Gm measured
12CU6	1 of 2	6900	-	-	100	Ef = 12.6 VAC Eb = 150 Ec2 = 150 Ec1 = -21 G1-P Gm measured
12CU6	2 of 2	-	316	-	100	Ef = 12.6 VAC Ebb = 230 Ec2 = 150 Ec1 = 0 Rl = 750 Ω Ib measured

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
12CX6	1 of 1	2900	-	-	20	Ef = 12.6 VAC Eb = 9.0 Ec3 = 0 Ec2 = 9.0 Ec1 = -1.0 G1-P, G2 Gm measured
12D4	1 of 1	-	148	-	10	Ef = 12.6 VAC Epp = 500 VAC (H-W) Rl = 5500 Ω Cl = 4 μf Io measured
12DB5	1 of 2	10, 100	-	-	70	Ef = 12.6 VAC Eb = 150 Ec2 = 150 Ec1 = -12 G1-P Gm measured G pin 6 used K pin 7 used
12DB5	2 of 2	10, 100	-	-	70	Ef = 12.6 VAC Eb = 150 Ec2 = 150 Ec1 = -12 G1-P Gm measured G pin 3 used K pin 2 used
12DE8	1 of 2	1900	-	-	20	Ef = 12.6 VAC Eb = 9.0 Ec3 = 0 Ec2 = 9.0 Ec1 = -0.8 Pent. G1-P, G2 Gm measured
12DE8	2 of 2	-	24	-	20	Ef = 12.6 VAC Ebb = 9.0 Rl = 275 Ω Diode Ib measured
12DF5	1 of 1	-	160	-	100	Ef = 6.3 VAC (Para.) Epp = 250 VAC (H-W) Rl = 1000 Ω Cl = 4 μf Io measured Dual Test: 1st Diode: pins 6, 8 used 2nd Diode: pins 1, 3 used
12DF7	1 of 1	2200	-	-	10	Ef = 6.3 VAC (Para.) Eb = 150 Ec1 = -1.0 Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
12DJ8	1 of 1	15,800	-	-	10	Ef = 12.6 VAC Eb = 100 Ec1 = -1.5 Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
12DK6	1 of 1	11,100	-	-	20	Ef = 12.6 VAC Eb = 150 Ec2 = 150 Rk = 120 Ω G1-P Gm measured
12DK7	1 of 2	4300	-	-	50	Ef = 12.6 VAC Eb = 9.0 Ec3 = 0 Ec2 = 9.0 Ec1 = -1.0 Tetrode G1-P, G2 Gm measured
12DK7	2 of 2	-	.48	-	50	Ef = 12.6 VAC Ebb = 9.0 Rl = 11,150 Ω Diode Ib measured Dual Test: 1st Diode: P pin 9 used 2nd Diode: P pin 6 used
12DL8	1 of 2	10,000	-	-	100	Ef = 12.6 VAC Eb = 9.0 Ec2 = -0.5 Ec1 = +9.0 Pent. G3-P, G1 Gm measured
12DL8	2 of 2	-	.50	-	20	Ef = 12.6 VAC Ebb = 9.0 Rl = 11,150 Ω Diode Ib measured Dual Test: 1st Diode: P pin 9 used 2nd Diode: P pin 1 used
12DM4	1 of 1	-	148	-	10	Ef = 12.6 VAC Epp = 500 VAC (H-W) Rl = 5000 Ω Cl = 4 μf Io measured
12DM5	1 of 2	10,000	-	-	70	Ef = 12.6 VAC Eb = 100 Ec2 = 100 Ec1 = -6.2 G1-P Gm measured G pin 2 used

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
12DM5	2 of 2	10,000	-	-	70	Ef = 12.6 VAC Eb = 100 Ec2 = 100 Ec1 = -6.2 G1-P Gm measured G pin 5 used
12DQ4	1 of 1	-	150	-	10	Ef = 12.6 VAC Epp = 250 VAC (H-W) Rl = 5400 Ω Cl = 4 μf Io measured
12DQ6	1 of 2	7000	-	-	100	Ef = 12.6 VAC Eb = 150 Ec2 = 150 Ec1 = -21 G1-P Gm measured
12DQ6	2 of 2	-	420	-	100	Ef = 12.6 VAC Ebb = 207 Rl = 490 Ω Ec2 = 150 Ec1 = 0 Ib measured
12DQ7	1 of 2	12,600	-	-	20	Ef = 6.3 VAC (Para.) Eb = 100 Ec3 = 0 Ec2 = 100 Rk = 50 Ω G1-P Gm measured G3 pin 9 used
12DQ7	2 of 2	-	52	-	20	Ef = 6.3 VAC (Para.) Ebb = 312 Rl = 7800 Ω Ec3 = 0 Ec2 = 100 Ec1 = 0 Ib measured G3 pin 3 used
12DS7	1 of 2	10,000	-	-	100	Ef = 12.6 VAC Eb = 9.0 Ec2 = 9.0 Ec1 = -0.5 Pent. G2-P, G1 Gm measured
12DS7	2 of 2	-	0.50	-	100	Ef = 12.6 VAC Ebb = 9.0 Rl = 11,150 Ω Diode Ib measured Dual Test: 1st Diode: P pin 9 used 2nd Diode: P pin 1 used
12DT5	1 of 2	7800	-	-	50	Ef = 12.6 VAC Eb = 150 Ec2 = 150 Ec1 = -8.5 G1-P Gm measured G pin 3 used
12DT5	2 of 2	-	140	-	50	Ef = 12.6 VAC Ebb = 275 Rl = 2150 Ω Ec2 = 150 Ec1 = 0 Ib measured G pin 6 used
12DT7	1 of 1	2200	-	-	10	Ef = 6.3 VAC (Para.) Eb = 150 Ec1 = -1.0 Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
12DT8	1 of 1	5000	-	-	20	Ef = 12.6 VAC Eb = 100 Rk = 270 Ω Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
12DU7	1 of 2	6300	-	-	20	Ef = 12.6 VAC Eb = 9.0 Ec2 = 9.0 Ec1 = -1.0 Pent. G1-P, G2 Gm measured
12DU7	2 of 2	-	0.40	-	20	Ef = 12.6 VAC Ebb = 20 Rl = 50,000 Ω Diode Ib measured Dual Test: 1st Diode: P pin 9 used 2nd Diode: P pin 7 used
12DV7	1 of 2	500	-	-	20	Ef = 6.3 VAC (Para.) Eb = 9.0 Rk = 5100 Ω Triode Gm measured
12DV7	2 of 2	-	0.40	-	20	Ef = 6.3 VAC (Para.) Ebb = 20 Rl = 50,000 Ω Diode Ib measured Dual Test: 1st Diode: P pin 3 used 2nd Diode: P pin 2 used

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
12DV8	1 of 2	4500	-	-	100	Ef = 12.6 VAC Eb = 9.0 Ec1 = +9.0 Ec2 = -1.0 Pent. G2-P, G1 Gm measured
12DV8	2 of 2	-	0.50	-	20	Ef = 12.6 VAC Ebb = 9.0 Rl = 11,150 Ω Diode Ib measured Dual Test: 1st Diode: P pin 9 used 2nd Diode: P pin 1 used
12DW5	1 of 2	6900	-	-	100	Ef = 12.6 VAC Eb = 150 E2 = 150 Ec1 = -21 G1-P Gm measured G pin 3 used
12DW5	2 of 2	-	364	-	100	Ef = 12.6 VAC Ebb = 221 Rl = 620 Ω Ec2 = 150 Ec1 = 0 Ib measured G pin 6 used
12DW7	1 of 2	1600	-	-	20	Ef = 6.3 VAC (Para.) Eb = 100 Ec1 = -1.0 Gm measured Pins 6, 7, 8 used
12DW7	2 of 2	3800	-	-	20	Ef = 6.3 VAC (Para.) Eb = 150 Ec1 = -3.0 Gm measured Pins 1, 2, 3 used
12DW8	1 of 3	2600	-	-	50	Ef = 12.6 VAC Eb = 9.0 Ec1 = -1.0 Triode Gm measured Pins 6, 7, 8 used
12DW8	2 of 3	6900	-	-	50	Ef = 12.6 VAC Eb = 9.0 Ec1 = -1.0 Triode Gm measured Pins 1, 2, 3 used
12DW8	3 of 3	-	6.0	-	-	Ef = 12.6 VAC Ebb = 16 Rl = 2020 Ω Diode Ib measured
12DY8	1 of 2	5900	-	-	50	Ef = 12.6 VAC Eb = 9.0 Ec2 = 9.0 Ec1 = -0.8 Tetrode G1-P, G2 Gm measured
12DY8	2 of 2	800	-	-	20	Ef = 12.6 VAC Eb = 9.0 Rk = 2100 Ω Triode Gm measured
12DZ6	1 of 1	4500	-	-	50	Ef = 12.6 VAC Eb = 9.0 Ec3 = 0 Ec2 = 9.0 Ec1 = -1.0 G1-P, G2 Gm measured
12DZ8	1 of 2	9500	-	-	50	Ef = 12.0 VAC Eb = 100 Ec2 = 100 Rk = 140 Ω Pent. G1-P Gm measured
12DZ8	2 of 2	1800	-	-	20	Ef = 12.0 VAC Eb = 100 Rk = 1200 Ω Triode Gm measured
12EA6	1 of 1	4800	-	-	50	Ef = 12.6 VAC Eb = 9.0 Ec3 = 0 Ec2 = 9.0 Ec1 = -1.0 G1-P, G2 Gm measured
12EC8	1 of 3	-	-	-	50	Ef = 12.6 VAC Shorts and Leakage tests only. Meter deflection not dependent on tube. Pins 6, 7, 8, 9 used
12EC8	2 of 3	-	1.16	-	-	Ef = 12.6 VAC Eb = 12.6 Ec2 = 12.6 Ec1 = 0 Pent. Ib measured
12EC8	3 of 3	-	3.78	-	-	Ef = 12.6 VAC Eb = 12.6 Ec1 = 0 Triode Ib measured
12ED5	1 of 1	10,000	-	-	50	Ef = 12.6 VAC Eb = 100 Ec2 = 100 Ec1 = -3.2 G1-P Gm measured G pin 2 used

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
12EG6	1 of 2	1000	-	-	20	Ef = 12.6 VAC Eb = 9.0 Ec2, 4 = 9.0 Ec3 = 0 Ec1 = -2.0 G1-P, G2, G4 Gm measured
12EG6	2 of 2	1500	-	-	-	Ef = 12.6 VAC Eb = 22 Ec2, 4 = 12.6 Ec1, 3 = 0 G3-P Gm measured
12EH5	1 of 1	18,400	-	-	70	Ef = 12.6 VAC Eb = 100 Ec2 = 100 Rk = 50 Ω G1-P Gm measured G pin 2 used
12EK6	1 of 1	5300	-	-	20	Ef = 12.6 VAC Eb = 9.0 Ec3 = 0 Ec2 = 9.0 Ec1 = -1.1 G1-P, G2 Gm measured
12EL6	1 of 2	-	0.94	-	-	Ef = 12.6 VAC Eb = 12.6 Ec1 = 0 Triode Ib measured
12EL6	2 of 2	-	0.6	-	20	Ef = 12.6 VAC Ebb = 20 Rl = 33,300 Ω Diode Ib measured Dual Test: 1st Diode: P pin 6 used 2nd Diode: P pin 5 used
12EM6	1 of 2	4300	-	-	50	Ef = 12.6 VAC Eb = 9.0 Ec2 = 9.0 Ec1 = -1.0 Tetrode G1-P, G2 Gm measured
12EM6	2 of 2	-	0.48	-	50	Ef = 12.6 VAC Ebb = 9.0 Rl = 11,165 Ω Diode Ib measured
12EN6	1 of 2	10,000	-	-	70	Ef = 12.6 VAC Eb = 100 Ec2 = 100 Ec1 = -7.2 G1-P Gm measured
12EN6	2 of 2	-	192	-	70	Ef = 12.6 VAC Ebb = 271 Rl = 1840 Ω Ec2 = 100 Ec1 = 0 Ib measured
12EQ7	1 of 2	3500	-	-	20	Ef = 12.6 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -1.0 Pent. G1-P Gm measured
12EQ7	2 of 2	-	0.48	-	20	Ef = 12.6 VAC Ebb = 9.0 Rl = 11,150 Ω Diode Ib measured
12EZ6	1 of 1	3400	-	-	20	Ef = 12.6 VAC Eb = 9.0 Ec3 = 0 Ec2 = 9.0 Ec1 = -0.9 G1-P, G2 Gm measured
12F5	1 of 1	1400	-	-	20	Ef = 12.6 VAC Eb = 100 Ec1 = -1.0 Gm measured
12F8	1 of 2	630	-	-	20	Ef = 12.6 VAC Eb = 9.0 Ec3 = 0 Ec2 = 9.0 Ec1 = -1.0 Pent. G1-P, G2 Gm measured
12F8	2 of 2	-	0.6	-	20	Ef = 12.6 VAC Ebb = 20 Rl = 33,300 Ω Diode Ib measured Dual Test: 1st Diode: P pin 6 used 2nd Diode: P pin 1 used
12FK6	1 of 2	700	-	-	20	Ef = 12.6 VAC Eb = 9.0 Ec1 = -1.0 Triode Gm measured
12FK6	2 of 2	-	0.6	-	20	Ef = 12.6 VAC Ebb = 20 Rl = 33,300 Ω Diode Ib measured Dual Test: 1st Diode: P pin 6 used 2nd Diode: P pin 5 used

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
12FM6	1 of 2	1000	-	-	20	Ef = 12.6 VAC Eb = 9.0 Ec1 = -1.0 Triode Gm measured
12FM6	2 of 2	-	0.6	-	20	Ef = 12.6 VAC Ebb = 20 Rl = 33,300 Ω Diode Ib measured Dual Test: 1st Diode: P pin 6 used 2nd Diode: P pin 5 used
12FQ8	1 of 2	1300	-	-	20	Ef = 12.6 VAC Eb = 150 Ec1 = -1.2 Gm measured Dual Test: 1st Triode: pins 7, 8, 9 used 2nd Triode: pins 2, 3, 9 used
12FQ8	2 of 2	1300	-	-	20	Ef = 12.6 VAC Eb = 150 Ec1 = -1.2 Gm measured Dual Test: 1st Triode: pins 6, 7, 9 used 2nd Triode: pins 1, 2, 9 used
12FR8	1 of 3	2400	-	-	-	Ef = 12.6 VAC Eb = 9.0 Ec2 = 9.0 Ec1 = -1.0 G1-P, G2 Gm measured
12FR8	2 of 3	900	-	-	50	Ef = 12.6 VAC Eb = 9.0 Ec1 = -1.0 Triode Gm measured
12FR8	3 of 3	-	1.5	-	-	Ef = 12.6 VAC Ebb = 10 Rl = 1000 Ω Diode Ib measured OK over 0.3 MA
12FT6	1 of 2	900	-	-	20	Ef = 12.6 VAC Eb = 9.0 Ec1 = -1.0 Triode Gm measured
12FT6	2 of 2	-	0.9	-	20	Ef = 12.6 VAC Ebb = 20 Rl = 22,200 Ω Diode Ib measured 1st Diode: P pin 6 used 2nd Diode: P pin 5 used
12FV7	1 of 2	12,100	-	-	20	Ef = 6.3 VAC (Para.) Eb = 100 Ec1 = -2.0 Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
12FV7	2 of 2	-	0.2	-	20	Ef = 6.3 VAC (Para.) Eb = 100 Ec1 = -10 Ib measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
12FX8	1 of 2	1700	-	-	20	Ef = 12.6 VAC Eb = 9.0 Ec3 = 0 Ec2 = 9.0 Ec1 = -1.0 Pent. G1-P, G2 Gm measured
12FX8	2 of 2	1200	-	-	-	Ef = 12.6 VAC Eb = 9.0 Ec1 = -1.0 Triode Gm measured
12G8	1 of 1	3300	-	-	20	Ef = 6.3 VAC (Para.) Eb = 9.0 Ec1 = -1.5 Gm measured Pins 1 & 6 jumpered Pins 3 & 7 jumpered
12GA6	1 of 1	1300	-	-	20	Ef = 12.6 VAC Eb = 9.0 Ec2, 4 = 9.0 Ec3 = 0 Ec1 = -1.0 G1-P, G2, G4 Gm measured
12GC6	1 of 2	8300	-	-	100	Ef = 12.6 VAC Eb = 150 Ec2 = 150 Ec1 = -22 G1-P Gm measured G2 pin 8 used
12GC6	2 of 2	-	252	-	100	Ef = 12.6 VAC Ebb = 242 Rl = 910 Ω Ec2 = 100 Ec1 = 0 Ib measured G2 pin 4 used

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
12GJ5	1 of 2	8800	-	-	100	Ef = 12.6 VAC Eb = 150 Ec2 = 150 Ec1 = -21 G1-P Gm measured G1 pin 6 used G2 pin 7 used Hickok Adapter 1050-144 required
12GJ5	2 of 2	-	250	-	100	Ef = 12.6 VAC Ebb = 239 Rl = 900 Ω Ec2 = 100 Ec1 = 0 Ib measured G1 pin 2 used G2 pin 1 used Hickok Adapter 1050-144 required
12GN7	1 of 2	26,000	-	-	20	Ef = 6.3 VAC (Para.) Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 160 Ω G1-P Gm measured G3 pin 9 used
12GN7	2 of 2	26,000	-	-	20	Ef = 6.3 VAC (Para.) Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 160 Ω G1-P Gm measured G3 pin 3 used
12GT5	1 of 2	8800	-	-	100	Ef = 12.6 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Ec1 = -21 G1-P Gm measured G2 pin 7 used Hickok Adapter 1050-144 required
12GT5	2 of 2	-	250	-	100	Ef = 12.6 VAC Ebb = 239 Ec3 = 0 Ec2 = 100 Ec1 = 0 Rl = 900 Ω Ib measured G2 pin 1 used Hickok Adapter 1050-144 required
12GW6	1 of 2	8800	-	-	100	Ef = 12.6 VAC Eb = 150 Ec2 = 150 Ec1 = -21 G1-P Gm measured
12GW6	2 of 2	-	250	-	100	Ef = 12.6 VAC Ebb = 239 Rl = 900 Ω Ec2 = 100 Ec1 = 0 Ib measured
12H6	1 of 1	-	6.1	-	10	Ef = 12.6 VAC Eb = 9.0 Ib measured Dual Test: 1st Diode: pins 5 & 8 used 2nd Diode: pins 3 & 4 used
12HU8/ PLL80	1 of 2	7600	-	-	50	Ef = 12.6 VAC Eb = 150 Ec2 = 150 Rk = 160 Ω G1-P Gm measured Pins 1, 2, 3, 7 used
12HU8/ PLL80	2 of 2	7600	-	-	50	Ef = 12.6 VAC Eb = 150 Ec2 = 150 Rk = 160 Ω G1-P Gm measured Pins 6, 7, 8, 9 used
12J5	1 of 1	3500	-	-	20	Ef = 12.6 VAC Eb = 150 Ec1 = -2.9 Gm measured
12J7	1 of 1	1500	-	-	20	Ef = 12.6 VAC Eb = 100 Ec2 = 100 Ec1 = -3.0 G1-P Gm measured
12J8	1 of 3	5700	-	-	70	Ef = 12.6 VAC Eb = 9.0 Ec2 = 9.0 Ec1 = -1.0 Pent. G1-P, G2 Gm measured
12J8	2 of 3	-	8.1	-	10	Ef = 12.6 VAC Ebb = 9.0 Rl = 316 Ω Diode Ib measured P pin 9 used
12J8	3 of 3	-	14.1	-	10	Ef = 12.6 VAC Ebb = 9.0 Rl = 183 Ω Diode Ib measured P pin 8 used

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
12K5	1 of 1	8800	-	-	70	Ef = 12.6 VAC Eb = 9.0 Ec2 = -1.5 Ec1 = +9.0 G2-P, G1 Gm measured
12K7	1 of 1	2100	-	-	20	Ef = 12.6 VAC Eb = 100 Ec2 = 100 Ec1 = -1.0 G1-P Gm measured
12K8	1 of 2	900	-	-	20	Ef = 12.6 VAC Eb = 100 Ec2 = 100 Ec1, 3 = -3.0 Pent. G3-P Gm measured
12K8	2 of 2	3500	-	-	20	Ef = 12.6 VAC Eb = 100 Ec1 = -1.0 Triode Gm measured
12KL8	1 of 2	5000	-	-	20	Ef = 12.6 VAC Eb = 100 Ec2 = 100 Ec1 = -0.5 Pent. G1-P Gm measured
12KL8	2 of 2	-	0.6	-	20	Ef = 12.6 VAC Ebb = 20 Rl = 33,000 Ω Diode Ib measured
12L6	1 of 1	10,100	-	-	70	Ef = 12.6 VAC Eb = 150 Ec2 = 150 Ec1 = -12 G1-P Gm measured
12L8	1 of 2	2700	-	-	50	Ef = 12.6 VAC Eb = 150 Ec2 = 150 Ec1 = -6.3 G1-P Gm measured Pentode pins: 1, 2, 5, 8
12L8	2 of 2	2700	-	-	50	Ef = 12.6 VAC Eb = 150 Ec2 = 150 Ec1 = -6.3 G1-P Gm measured Pentode pins: 2, 3, 4, 5
12Q7	1 of 2	1500	-	-	20	Ef = 12.6 VAC Eb = 100 Ec1 = -1.0 Triode Gm measured
12Q7	2 of 2	-	0.6	-	20	Ef = 12.6 VAC Ebb = 20 Rl = 33,300 Ω Diode Ib measured Dual Test: 1st Diode: P pin 5 used 2nd Diode: P pin 4 used
12R5	1 of 1	8800	-	-	70	Ef = 12.6 VAC Eb = 100 Ec2 = 100 Ec1 = -6.8 G1-P Gm measured
12S8	1 of 3	1100	-	-	20	Ef = 12.6 VAC Eb = 100 Ec1 = -1.0 Triode Gm measured
12S8	2 of 3	-	0.74	-	20	Ef = 12.6 VAC Ebb = 20 Rl = 27,000 Ω Diode Ib measured Pins 3 & 5 used
12S8	3 of 3	-	0.74	-	20	Ef = 12.6 VAC Ebb = 20 Rl = 27,000 Ω Diode Ib measured Dual Test: 1st Diode: pins 2 & 4 used 2nd Diode: pins 1 & 2 used
12SA7	1 of 2	700	-	-	20	Ef = 12.6 VAC Eb = 100 Ec2, 4 = 100 Ec5 = 0 Ec1, 3 = -1.0 G3-P Gm measured
12SA7	2 of 2	4800	-	-	20	Ef = 12.6 VAC Eb = 100 Ec2, 4 = 100 Ec3, 5 = 0 Ec1 = -1.0 G1-P, G2, G4 Gm measured
12SC7	1 of 1	1400	-	-	20	Ef = 12.6 VAC Eb = 150 Ec1 = -1.0 Gm measured Dual Test: 1st Triode: pins 4, 5, 6 used 2nd Triode: pins 2, 3, 6 used
12SF5	1 of 1	1400	-	-	20	Ef = 12.6 VAC Eb = 100 Ec1 = -1.0 Gm measured

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
12SF7	1 of 2	2500	-	-	20	Ef = 12.6 VAC Eb = 100 Ec2 = 100 Ec1 = -1.0 Pent. G1-P Gm measured
12SF7	2 of 2	-	0.6	-	20	Ef = 12.6 VAC Ebb = 20 Rl = 33,300 Ω Diode Ib measured
12SG7	1 of 1	5100	-	-	20	Ef = 12.6 VAC Eb = 100 Ec2 = 100 Rk = 90 Ω G1-P Gm measured
12SH7	1 of 1	5000	-	-	20	Ef = 12.6 VAC Eb = 100 Ec2 = 100 Ec1 = -1.0 G1-P Gm measured
12SJ7	1 of 1	2000	-	-	20	Ef = 12.6 VAC Eb = 100 Ec2 = 100 Ec1 = -3.0 G1-P Gm measured
12SK7	1 of 1	3000	-	-	20	Ef = 12.6 VAC Eb = 100 Ec2 = 100 Ec3 = 0 Ec1 = -1.0 G1-P Gm measured
12SL7	1 of 1	1400	-	-	20	Ef = 12.6 VAC Eb = 100 Ec = -1.0 Gm measured Dual Test: 1st Triode: pins 4, 5, 6 used 2nd Triode: pins 1, 2, 3 used
12SN7	1 of 1	3500	-	-	20	Ef = 12.6 VAC Eb = 150 Ec1 = -2.9 Gm measured Dual Test: 1st Triode: pins 4, 5, 6 used 2nd Triode: pins 1, 2, 3 used
12SQ7	1 of 2	1100	-	-	20	Ef = 12.6 VAC Eb = 100 Ec1 = -1.0 Triode Gm measured
12SQ7	2 of 2	-	0.6	-	20	Ef = 12.6 VAC Ebb = 20 Rl = 33,300 Ω Diode Ib measured Dual Test: 1st Diode: P pin 5 used 2nd Diode: P pin 4 used
12SR7	1 of 2	2500	-	-	20	Ef = 12.6 VAC Eb = 150 Ec1 = -3.0 Triode Gm measured
12SR7	2 of 2	-	0.6	-	20	Ef = 12.6 VAC Ebb = 20 Rl = 33,300 Ω Diode Ib measured Dual Test: 1st Diode: P pin 5 used 2nd Diode: P pin 4 used
12SW7	1 of 2	2500	-	-	20	Ef = 12.6 VAC Eb = 150 Ec1 = -3.0 Triode Gm measured
12SW7	2 of 2	-	0.6	-	-	Ef = 12.6 VAC Ebb = 20 Rl = 33,300 Ω Diode Ib measured Dual Test: 1st Diode: P pin 5 used 2nd Diode: P pin 4 used
12SX7	1 of 1	2300	-	-	20	Ef = 12.6 VAC Eb = 50 Ec1 = -1.5 Gm measured Dual Test: 1st Triode: pins 4, 5, 6 used 2nd Triode: pins 1, 2, 3 used
12SY7	1 of 2	700	-	-	20	Ef = 12.6 VAC Eb = 100 Ec2, 4 = 100 Ec5 = 0 Ec1, 3 = -1.0 G3-P Gm measured
12SY7	2 of 2	4800	-	-	20	Ef = 12.6 VAC Eb = 100 Ec2,4 = 100 Ec3, 5 = 0 Ec1 = -1.0 G1-P, G2, G4 Gm measured

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
12U7	1 of 3	-	-	-	20	Ef = 6.3 VAC (Para.) Shorts and leakage tests only. Meter deflection not dependent on tube. Pins 1, 2, 3, 6, 7, 8 used K pins 3, 8 jumpered
12U7	2 of 3	-	1.26	-	-	Ef = 6.3 VAC (Para.) Eb = 12.6 Ec1 = 0 Ib measured Pins 6, 7, 8 used
12U7	3 of 3	-	1.26	-	-	Ef = 6.3 VAC (Para.) Eb = 12.6 Ec1 = 0 Ib measured Pins 1, 2, 3 used
12V6	1 of 1	4700	-	-	50	Ef = 12.6 VAC Eb = 150 Ec2 = 150 Ec1 = -4.2 G1-P Gm measured
12W6	1 of 1	10,100	-	-	70	Ef = 12.6 VAC Eb = 150 Ec2 = 150 Ec1 = -12 G1-P Gm measured
12X4	1 of 1	-	112	-	150	Ef = 12.6 VAC Epp = 250 VAC (F-W) Rl = 3950 Ω Cl = 4 μf Io measured
12Z3	1 of 1	-	88	-	100	Ef = 12.6 VAC Epp = 250 VAC (H-W) Rl = 4100 Ω Cl = 4 μf Io measured
13CM5/XL36	1 of 2	12,000	-	-	100	Ef = 12.8 VAC Eb = 150 Ec2 = 150 Ec1 = -20 G1-P Gm measured
13CM5/XL36	2 of 2	-	280	-	100	Ef = 12.8 VAC Eb = 250 Rl = 950 Ω Ec2 = 100 Ec1 = 0 Ib measured
13CW4	1 of 1	13,400	-	-	10	Ef = 13.5 VAC Eb = 100 Rk = 100 Ω Gm measured Hickok Adapter 1050-127 required
13DE7	1 of 3	3400	-	-	20	Ef = 13.3 VAC Eb = 150 Ec1 = -4.0 Gm measured Pins 6, 7, 8 used
13DE7	2 of 3	8200	-	-	20	Ef = 13.3 VAC Eb = 150 Ec1 = -18 Gm measured Pins 1, 3, 9 used
13DE7	3 of 3	-	98	-	20	Ef = 13.3 VAC Eb = 50 Ec1 = 0 Ib measured Pins 1, 2, 9 used
13DR7	1 of 3	2000	-	-	20	Ef = 13.0 VAC Eb = 150 Ec1 = -1.8 Gm measured Pins 6, 7, 8 used
13DR7	2 of 3	8200	-	-	20	Ef = 13.0 VAC Eb = 150 Ec1 = -18 Gm measured Pins 1, 3, 9 used
13DR7	3 of 3	-	98	-	20	Ef = 13.0 VAC Eb = 50 Ec1 = 0 Ib measured Pins 1, 2, 9 used
13EM7	1 of 3	2000	-	-	20	Ef = 13.0 VAC Eb = 150 Ec1 = -1.8 Gm measured
13EM7	2 of 3	9100	-	-	20	Ef = 13.0 VAC Eb = 150 Ec1 = -20 Gm measured Pins 1, 2, 3 used
13EM7	3 of 3	-	112	-	20	Ef = 13.0 VAC Eb = 50 Ec1 = 0 Ib measured Pins 1, 2, 3 used
13FD7	1 of 2	2000	-	-	20	Ef = 13.0 VAC Eb = 150 Ec1 = -1.8 Gm measured Pins 6, 7, 8 used
13FD7	2 of 2	9400	-	-	20	Ef = 13.0 VAC Eb = 150 Ec1 = -18 Gm measured Pins 1, 2, 9 used

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
13FR7	1 of 3	2000	-	-	20	Ef = 13.0 VAC Eb = 150 Ec1 = -1.8 Gm measured Pins 6, 7, 8 used
13FR7	2 of 3	9100	-	-	20	Ef = 13.0 VAC Eb = 150 Ec1 = -20 Gm measured Pins 1, 2, 9 used
13FR7	3 of 3	-	112	-	20	Ef = 13.0 VAC Eb = 50 Ec1 = 0 Ib measured Pins 1, 3, 9 used
13GF7	1 of 2	2000	-	-	20	Ef = 13.0 VAC Eb = 150 Ec1 = -1.8 Gm measured Pins 1, 8, 9 used Hickok Adapter 1050-144 required
13GF7	2 of 2	9100	-	-	100	Ef = 13.0 VAC Eb = 150 Ec1 = -20 Gm measured Pins 2, 3, 6 used Hickok Adapter 1050-144 required
14A4	1 of 1	3500	-	-	20	Ef = 12.6 VAC Eb = 150 Ec1 = -2.9 Gm measured
14A5	1 of 1	4000	-	-	100	Ef = 12.6 VAC Eb = 150 Ec2 = 150 Ec1 = -2.0 G1-P Gm measured
14A7	1 of 1	3000	-	-	20	Ef = 12.6 VAC Eb = 100 Ec2 = 100 Ec3 = 0 Ec1 = -1.0 G1-P Gm measured
14AF7	1 of 1	2400	-	-	20	Ef = 12.6 VAC Eb = 100 Ec1 = -3.0 Gm measured Dual Test: 1st Triode: pins 5, 6, 7 used 2nd Triode: pins 2, 3, 4 used
14B6	1 of 2	1100	-	-	20	Ef = 12.6 VAC Eb = 100 Ec1 = -1.0 Triode Gm measured
14B6	2 of 2	-	0.6	-	20	Ef = 12.6 VAC Ebb = 20 Rl = 33,300 Ω Diode Ib measured Dual Test: 1st Diode: P pin 6 used 2nd Diode: P pin 5 used
14B8	1 of 2	700	-	-	20	Ef = 12.6 VAC Eb = 100 Ec2, 3, 5 = 100 Ec1, 4 = -5.8 G4-P Gm measured
14B8	2 of 2	1800	-	-	20	Ef = 12.6 VAC Eb = 100 Ec2, 3, 5 = 100 Ec4 = 0 Ec1 = -7.6 G1-P, G3, G5 Gm measured
14C5	1 of 1	4700	-	-	50	Ef = 12.6 VAC Eb = 150 Ec2 = 150 Ec1 = -4.2 G1-P Gm measured
14C7	1 of 1	2900	-	-	20	Ef = 12.6 VAC Eb = 100 Ec2 = 100 Ec1 = -1.0 G1-P Gm measured
14E6	1 of 2	2500	-	-	20	Ef = 12.6 VAC Eb = 150 Ec1 = -3.0 Triode Gm measured
14E6	2 of 2	-	0.6	-	20	Ef = 12.6 VAC Ebb = 20 Rl = 33,300 Ω Diode Ib measured Dual Test: 1st Diode: P pin 6 used 2nd Diode: P pin 5 used
14E7	1 of 2	2000	-	-	20	Ef = 12.6 VAC Eb = 100 Ec2 = 100 Ec1 = -1.0 Pent. G1-P Gm measured

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
14E7	2 of 2	-	0.6	-	20	Ef = 12.6 VAC Ebb = 20 Rl = 33,300 Ω Diode Ib measured Dual Test: 1st Diode: P pin 4 used 2nd Diode: P pin 3 used
14F7	1 of 1	1400	-	-	20	Ef = 12.6 VAC Eb = 100 Ec1 = -1.0 Gm measured Dual Test: 1st Triode: pins 5, 6, 7 used 2nd Triode: pins 2, 3, 4 used
14F8	1 of 1	6500	-	-	10	Ef = 12.6 VAC Eb = 150 Rk = 100 Ω Gm measured Dual Test: 1st Triode: pins 5, 6, 8 used 2nd Triode: pins 1, 3, 4 used
14GT8	1 of 2	1400	-	-	20	Ef = 14.0 VAC Eb = 150 Ec1 = -1.6 Triode Gm measured
14GT8	2 of 2	-	22	-	20	Ef = 14.0 VAC Ebb = 9.0 Rl = 115 Ω Diode Ib measured Dual Test: 1st Diode: pins 1 & 6 used 2nd Diode: pins 2 & 3 used
14H7	1 of 1	5000	-	-	20	Ef = 12.6 VAC Eb = 100 Ec2 = 100 Ec1 = -1.5 G1-P Gm measured
14J7	1 of 2	1000	-	-	20	Ef = 12.6 VAC Eb = 100 Ec2, 4 = 100 Ec1, 3 = -3.0 Pent. G1-P Gm measured
14J7	2 of 2	1800	-	-	20	Ef = 12.6 VAC Eb = 150 Ec1 = -3.0 Triode Gm measured
14JG8	1 of 2	2800	-	-	20	Ef = 14.0 VAC Eb = 150 Ec1 = -0.9 Triode Gm measured
14JG8	2 of 2	-	22	-	10	Ef = 14.0 VAC Ebb = 9.0 Rl = 115 Ω Diode Ib measured Dual Test: 1st Diode: pins 2 & 3 used 2nd Diode: pins 1 & 6 used
14N7	1 of 1	3500	-	-	20	Ef = 12.6 VAC Eb = 150 Ec1 = -2.9 Gm measured Dual Test: 1st Triode: pins 5, 6, 7 used 2nd Triode: pins 2, 3, 4 used
14Q7	1 of 2	900	-	-	20	Ef = 12.6 VAC Eb = 100 Ec5 = 0 Ec2, 4 = 100 Ec1, 3 = -1.0 G3-P Gm measured
14Q7	2 of 2	5700	-	-	20	Ef = 12.6 VAC Eb = 100 Ec3, 5 = 0 Ec2, 4 = 100 Ec1 = -1.0 G1-P, G2, G4 Gm measured
14R7	1 of 2	3800	-	-	20	Ef = 12.6 VAC Eb = 100 Ec2 = 100 Ec1 = -1.0 Pent. G1-P Gm measured
14R7	2 of 2	-	0.6	-	20	Ef = 12.6 VAC Ebb = 20 Rl = 33,300 Ω Diode Ib measured Dual Test: 1st Diode: P pin 4 used 2nd Diode: P pin 3 used
14S7	1 of 2	1800	-	-	20	Ef = 12.6 VAC Eb = 100 Ec2, 4 = 100 Ec3 = 0 Rk = 240 Ω Pent. G1-P Gm measured
14S7	2 of 2	1900	-	-	20	Ef = 12.6 VAC Eb = 100 Ec1 = -1.0 Triode Gm measured

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
14W7	1 of 1	6900	-	-	20	Ef = 12.6 VAC Eb = 150 Ec2 = 150 Rk = 160 Ω G1-P Gm measured
14X7	1 of 2	1400	-	-	20	Ef = 12.6 VAC Eb = 150 Ec1 = -1.0 Triode Gm measured
14X7	2 of 2	-	5.05	-	20	Ef = 12.6 VAC Ebb = 9.0 Rl = 255 Ω Diode Ib measured Dual Test: 1st Diode: pins 6 & 7 used 2nd Diode: pins 4 & 5 used
14Y4	1 of 1	-	112	-	150	Ef = 12.6 VAC Epp = 250 VAC (F-W) Rl = 3950 Ω Cl = 4 μf Io measured
15	1 of 1	800	-	-	20	Ef = 2.0 VAC Eb = 50 Ec2 = 50 Ec1 = -1.0 G1-P Gm measured
15A6/ PL83	1 of 1	12,600	-	-	50	Ef = 15.0 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Ec1 = -1.0 G1-P Gm measured
15CW5/ PL84	1 of 1	14,000	-	-	100	Ef = 15.0 VAC Eb = 150 Ec2 = 150 Ec1 = -10 G1-P Gm measured
15EA7	1 of 3	2400	-	-	20	Ef = 14.8 VAC Eb = 150 Ec1 = -1.6 Gm measured Pins 4, 5, 6 used
15EA7	2 of 3	8200	-	-	50	Ef = 14.8 VAC Eb = 150 Ec1 = -21 Gm measured Pins 1, 2, 3 used
15EA7	3 of 3	-	134	-	50	Ef = 14.8 VAC Ebb = 150 Rl = 930 Ω Ec1 = 0 Ib measured Pins 1, 2, 3 used
15EW6	1 of 1	17,600	-	-	20	Ef = 15.0 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 70 Ω G1-P Gm measured
15HB6	1 of 2	26,000	-	-	50	Ef = 15.0 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 60 Ω Pent. G1-P Gm measured
15HB6	2 of 2	-	96	-	50	Ef = 15.0 VAC Eb = 30 Ec3 = 0 Ec2 = 150 Ec1 = 0 Ib measured
16A5/ PL82	1 of 1	11,300	-	-	50	Ef = 16.5 VAC Eb = 150 Ec2 = 150 Ec1 = -9.0 G1-P Gm measured
16A8/ PCL82	1 of 2	8600	-	-	50	Ef = 16.0 VAC Eb = 100 Ec2 = 100 Ec1 = -6.0 Pent. G1-P Gm measured
16A8/ PCL82	2 of 2	3200	-	-	20	Ef = 16.0 VAC Eb = 150 Ec1 = -1.2 Triode Gm measured
16AQ3/ XY88	1 of 1	-	148	-	10	Ef = 16.0 VAC Epp = 500 VAC (H-W) Rl = 5300 Ω Cl = 4 μf Io measured
17AV5	1 of 2	6900	-	-	100	Ef = 16.8 VAC Eb = 150 Ec2 = 150 Ec1 = -21 G1-P Gm measured
17AV5	2 of 2	-	316	-	100	Ef = 16.8 VAC Ebb = 230 Rl = 750 Ω Ec2 = 150 Ec1 = 0 Ib measured
17AX4	1 of 1	-	148	-	10	Ef = 16.8 VAC Epp = 500 VAC (H-W) Rl = 5500 Ω Cl = 4 μf Io measured

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
17AY3	1 of 1	-	148	-	10	Ef = 16.8 VAC Epp = 500 VAC (H-W) Rl = 5500 Ω Cl = 4 μf Io measured Hickok Adapter 1050-144 required
17BH3	1 of 1	-	148	-	10	Ef = 17.0 VAC Epp = 500 VAC (H-W) Rl = 5500 Ω Cl = 4 μf Io measured Hickok Adapter 1050-144 required
17BQ6	1 of 2	6900	-	-	100	Ef = 16.8 VAC Eb = 150 Ec2 = 150 Ec1 = -21 G1-P Gm measured
17BQ6	2 of 2	-	316	-	100	Ef = 16.8 VAC Ebb = 230 Rl = 750 Ω Ec2 = 150 Ec1 = 0 Ib measured
17BS3	1 of 1	-	92	-	10	Ef = 16.8 VAC Epp = 500 VAC (H-W) Rl = 6100 Ω Cl = 4 μf Io measured Hickok Adapter 1050-144 required
17C5	1 of 1	10,000	-	-	70	Ef = 16.8 VAC Eb = 100 Ec2 = 100 Ec1 = -6.2 G1-P Gm measured
17CA5	1 of 1	10,000	-	-	70	Ef = 16.8 VAC Eb = 100 Ec2 = 100 Ec1 = -3.2 G1-P Gm measured G1 pin 2 used
17CQ4	1 of 1	-	148	-	10	Ef = 16.8 VAC Epp = 500 VAC (H-W) Rl = 5000 Ω Cl = 4 μf Io measured
17CU5	1 of 1	9400	-	-	70	Ef = 16.8 VAC Eb = 100 Ec2 = 100 Ec1 = -6.2 G1-P Gm measured
17D4	1 of 1	-	148	-	10	Ef = 16.8 VAC Epp = 500 VAC (H-W) Rl = 5500 Ω Cl = 4 μf Io measured
17DE4	1 of 1	-	148	-	10	Ef = 17.0 VAC Epp = 500 VAC (H-W) Rl = 5000 Ω Cl = 4 μf Io measured
17DM4	1 of 1	-	148	-	10	Ef = 16.8 VAC Epp = 500 VAC (H-W) Rl = 5000 Ω Cl = 4 μf Io measured
17DQ4	1 of 1	-	150	-	10	Ef = 16.8 VAC Epp = 250 VAC (H-W) Rl = 5400 Ω Cl = 4 μf Io measured
17DQ6	1 of 2	7000	-	-	100	Ef = 16.8 VAC Eb = 150 Ec2 = 150 Ec1 = -21 G1-P Gm measured
17DQ6	2 of 2	-	420	-	100	Ef = 16.8 VAC Ebb = 207 Rl = 490 Ω Ec2 = 150 Ec1 = 0 Ib measured
17EW8/ HCC85	1 of 1	5800	-	-	20	Ef = 17.5 VAC Eb = 100 Ec1 = -1.1 Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
17GJ5	1 of 2	8800	-	-	100	Ef = 16.8 VAC Eb = 150 Ec2 = 150 Ec1 = -21 G1-P Gm measured G1 pin 6 used G2 pin 7 used Hickok Adapter 1050-144 required

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
17GJ5	2 of 2	-	250	-	100	Ef = 16.8 VAC Eb = 239 Ec2 = 150 Ec1 = 0 Ib measured G1 pin 2 used G2 pin 1 used Hickok Adapter 1050-144 required
17GT5	1 of 2	8800	-	-	100	Ef = 16.8 VAC Eb = 150 Ec2 = 150 Ec1 = -21 G1-P Gm measured G2 pin 7 used Hickok Adapter 1050-144 required
17GT5	2 of 2	-	250	-	100	Ef = 16.8 VAC Ebb = 239 Ec3 = 0 Ec2 = 100 Ec1 = 0 Rl = 900 Ω Ib measured G2 pin 1 used Hickok Adapter 1050-144 required
17GW6	1 of 2	8800	-	-	100	Ef = 16.8 VAC Eb = 150 Ec2 = 150 Ec1 = -21 G1-P Gm measured
17GW6	2 of 2	-	250	-	100	Ef = 16.8 VAC Ebb = 239 Rl = 900 Ω Ec2 = 100 Ec1 = 0 Ib measured
17H3	1 of 1	-	162	-	10	Ef = 17.5 VAC Epp = 500 VAC (H-W) Rl = 6800 Ω Cl = 4 μf Io measured
17HC8	1 of 3	6400	-	-	50	Ef = 16.8 VAC Eb = 150 Ec2 = 150 Ec1 = -8.3 Pent. G1-P Gm measured
17HC8	2 of 3	-	100	-	50	Ef = 16.8 VAC Ebb = 287 Rl = 3120 Ω Ec2 = 150 Ec1 = 0 Pent. Ib measured
17HC8	3 of 3	2500	-	-	20	Ef = 16.8 VAC Eb = 150 Ec1 = -1.7 Triode Gm measured
17JB6	1 of 2	8800	-	-	100	Ef = 16.8 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Ec1 = -21 G1-P Gm measured G1 pin 6 used G2 pin 7 used Hickok Adapter 1050-144 required
17JB6	2 of 2	-	250	-	100	Ef = 16.8 VAC Ebb = 239 Rl = 900 Ω Ec3 = 0 Ec2 = 100 Ec1 = 0 Ib measured G1 pin 2 used G2 pin 1 used Hickok Adapter 1050-144 required
17JK8	1 of 2	8500	-	-	20	Ef = 16.8 VAC Eb = 100 Ec1 = -1.0 Gm measured Pins 6, 7, 8 used
17JK8	2 of 2	16,000	-	-	20	Ef = 16.8 VAC Eb = 150 Ec1 = -1.4 Gm measured Pins 1, 2, 3 used
17L6	1 of 1	10,100	-	-	70	Ef = 16.8 VAC Eb = 150 Ec2 = 150 Ec1 = -12 G1-P Gm measured
17R5	1 of 1	8800	-	-	70	Ef = 16.8 VAC Eb = 100 Ec2 = 100 Ec1 = -6.8 G1-P Gm measured
17Z3/ PY81	1 of 1	-	148	-	10	Ef = 17.0 VAC Epp = 500 VAC (H-W) Rl = 5000 Ω Cl = 4 μf Io measured
18A5	1 of 2	6300	-	-	100	Ef = 18.5 VAC Eb = 100 Ec2 = 100 Ec1 = -12 G1-P Gm measured

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
18A5	2 of 2	-	146	-	100	Ef = 18.5 VAC Ebb = 235 Rl = 820 Ω Ec2 = 150 Ec1 = 0 Ib measured
18DZ8	1 of 2	9500	-	-	50	Ef = 18.0 VAC Eb = 100 Ec2 = 100 Rk = 140 Ω Pent. G1-P Gm measured
18DZ8	2 of 2	1800	-	-	20	Ef = 18.0 VAC Eb = 100 Rk = 1200 Ω Triode Gm measured
18FW6	1 of 1	5200	-	-	10	Ef = 18.0 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Rk = 70 Ω G1-P Gm measured
18FX6	1 of 2	2600	-	-	10	Ef = 18.0 VAC Eb = 100 Ec2, 4 = 100 Ec1, 3 = -1.5 G1, G3-P Gm measured
18FX6	2 of 2	7600	-	-	10	Ef = 18.0 VAC Eb = 100 Ec2, 4 = 100 Ec3 = 0 Ec1 = -1.0 G1-P, G2, G4 Gm measured
18FY6	1 of 2	1600	-	-	20	Ef = 1800 VAC Eb = 100 Ec1 = -1.0 Triode Gm measured
18FY6	2 of 2	-	0.6	-	20	Ef = 18.0 VAC Ebb = 20 Rl = 33,300 Ω Diode Ib measured Dual Test: 1st Diode: P pin 6 used 2nd Diode: P pin 5 used
18GD6	1 of 1	5400	-	-	20	Ef = 18.0 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Rk = 150 Ω G1-P Gm measured
18HB8	1 of 2	7800	-	-	50	Ef = 18.0 VAC Eb = 100 Ec2 = 100 Rk = 130 Ω Pent. G1-P Gm measured
18HB8	2 of 2	4900	-	-	50	Ef = 18.0 VAC Eb = 100 Rk = 360 Ω Triode Gm measured
19	1 of 1	-	3.3	-	-	Ef = 20 VAC Eb = 100 Rk = 750 Ω Ib measured OK 1.4 to 3.0 MA Dual Test: 1st Triode: pins 4 & 5 used 2nd Triode: pins 2 & 3 used
19AJ8	1 of 2	2600	-	-	20	Ef = 19.0 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Ec1 = -4.0 Heptode G1-P Gm measured
19AJ8	2 of 2	4000	-	-	20	Ef = 19.0 VAC Eb = 100 Ec1 = -1.0 Triode Gm measured
19AU4	1 of 1	-	148	-	10	Ef = 18.9 VAC Epp = 500 VAC (H-W) Rl = 5800 Ω Cl = 4 μf Io measured
19BG6	1 of 2	8800	-	-	100	Ef = 18.9 VAC Eb = 150 Ec2 = 150 Ec1 = -1.9 G1-P Gm measured
19BG6	2 of 2	-	63	-	100	Ef = 18.9 VAC Ebb = 285 Rl = 2610 Ω Ec2 = 150 Ec1 = 0 Ib measured
19C8	1 of 3	1500	-	-	20	Ef = 18.9 VAC Eb = 100 Ec1 = -1.0 Triode Gm measured Pins 7, 8, 9 used
19C8	2 of 3	-	20	-	20	Ef = 18.9 VAC Ebb = 9.0 Rl = 200 Ω Diode Ib measured Pins 6 & 7 used

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
19C8	3 of 3	-	20	-	20	Ef = 18.9 VAC Ebb = 9.0 Rl = 200 Ω Diode Ib measured Dual Test: 1st Diode: pins 2 & 3 used 2nd Diode: pins 1 & 7 used
19CL8	1 of 2	6000	-	-	20	Ef = 18.9 VAC Eb = 150 Ec2 = 150 Ec1 = -2.0 Tetrode G1-P Gm measured
19CL8	2 of 2	6300	-	-	20	Ef = 18.9 VAC Eb = 150 Rk = 220 Ω Triode Gm measured
19D8/ UCH81	1 of 2	2600	-	-	20	Ef = 19.0 VAC Eb = 150 Ec2, 4 = 150 Ec3 = 0 Ec1 = -4.0 Heptode G1-P Gm measured
19D8/ UCH81	2 of 2	4000	-	-	20	Ef = 19.0 VAC Eb = 100 Ec1 = -1.0 Triode Gm measured
19EA8	1 of 2	6900	-	-	20	Ef = 18.9 VAC Eb = 100 Ec2 = 100 Ec1 = -1.0 Pent. G1-P Gm measured
19EA8	2 of 2	10,700	-	-	20	Ef = 18.9 VAC Eb = 150 Rk = 60 Ω Triode Gm measured
19EZ8	1 of 2	5300	-	-	20	Ef = 18.9 VAC Eb = 150 Ec1 = -1.3 Gm measured Pins 1, 2, 3 used
19EZ8	2 of 2	5300	-	-	-	Ef = 18.9 VAC Eb = 150 Ec1 = -1.3 Gm measured Dual Test: 1st Triode: pins 4, 8, 9 used 2nd Triode: pins 4, 6, 7 used
19G3	1 of 1	-	80	-		Ef = 4.0 VAC Epp = 250 VAC (H-W) Rl = 4600 Ω Cl = 4 μf Io measured
19HR6	1 of 1	8800	-	-	20	Ef = 18.9 VAC Eb = 150 Ec2 = 150 Rk = 100 Ω G1-P Gm measured
19HS6	1 of 1	12,000	-	-	20	Ef = 18.9 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Rk = 90 Ω G1-P Gm measured
19HV8	1 of 2	8200	-	-	20	Ef = 18.9 VAC Eb = 150 Ec2 = 150 Ec1 = -1.4 Pent. G1-P Gm measured
19HV8	2 of 2	1700	-	-	20	Ef = 18.9 VAC Eb = 100 Ec1 = -1.0 Triode Gm measured
19J6	1 of 1	6600	-	-	20	Ef = 18.9 VAC Eb = 100 Rk = 50 Ω Gm measured Dual Test: 1st Triode: pins 2, 5, 7 used 2nd Triode: pins 1, 6, 7 used
19JN8	1 of 2	9400	-	-	20	Ef = 18.9 VAC Eb = 150 Ec2 = 150 Ec1 = -1.3 V Pent. G1-P Gm measured
19JN8	2 of 2	9100	-	-	20	Ef = 18.9 VAC Eb = 150 Ec1 = -1.7 Triode Gm measured
19KG8	1 of 2	9400	-	-	20	Ef = 18.9 VAC Eb = 150 Ec2 = 150 Ec1 = -1.3 Pent. G1-P Gm measured
19KG8	2 of 2	10,800	-	-	20	Ef = 18.9 VAC Eb = 150 Ec1 = -1.3 Triode Gm measured
19T8	1 of 3	1600	-	-	20	Ef = 18.9 VAC Eb = 100 Ec1 = -1.0 Triode Gm measured

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
19T8	2 of 3	-	22	-	10	Ef = 18.9 VAC Ebb = 9.0 Rl = 115 Ω Diode Ib measured Pins: 6 & 7 used
19T8	3 of 3	-	22	-	10	Ef = 18.9 VAC Ebb = 9 Rl = 115 Ω Diode Ib measured Dual Test: 1st Diode: pins 2 & 3 used 2nd Diode: pins 1 & 7 used
19V8	1 of 3	1600	-	-	20	Ef = 18.9 VAC Eb = 100 Ec1 = -1.0 Triode Gm measured
19V8	2 of 3	-	0.6	-	20	Ef = 18.9 VAC Ebb = 20 Rl = 33,300 Ω Diode Ib measured Pins 3 & 9 used
19V8	3 of 3	-	44	-	10	Ef = 18.9 VAC Ebb = 9 Rl = 58 Ω Diode Ib measured Dual Test: 1st Diode: pins 7 & 8 used 2nd Diode: pins 2 & 3 used
19X8	1 of 2	5800	-	-	20	Ef = 18.9 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 200 Ω Pent. G1-P Gm measured
19X8	2 of 2	7300	-	-	20	Ef = 18.9 VAC Eb = 100 Rk = 100 Ω Triode Gm measured
20EQ7	1 of 2	3500	-	-	20	Ef = 20.0 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -1.0 Pent. G1-P Gm measured
20EQ7	2 of 2	-	0.48	-	20	Ef = 20.0 VAC Ebb = 9.0 Rl = 11,100 Ω Diode Ib measured
20EZ7	1 of 1	1600	-	-	20	Ef = 10.0 VAC (Para.) Eb = 100 Ec1 = -1.0 Gm measured Dual Test: 1st Triode: pins 7, 8, 9 used 2nd Triode: pins 4, 5, 6 used
21A6/ PL81	1 of 2	7800	-	-	100	Ef = 21.5 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Ec1 = -19 G1-P Gm measured
21A6/ PL81	2 of 2	-	224	-	100	Ef = 21.5 VAC Ebb = 255 Rl = 1350 Ω Ec3 = 0 Ec2 = 100 Ec1 = 0 Ib measured
21EX6	1 of 2	10,700	-	-	100	Ef = 21.5 VAC Eb = 150 Ec2 = 150 Ec1 = -23 G1-P Gm measured
21EX6	2 of 2	-	322	-	100	Ef = 21.5 VAC Ebb = 229 Rl = 730 Ω Ec2 = 100 Ec1 = 0 Ib measured
22BH3	1 of 1	-	148	-	10	Ef = 22.4 VAC Epp = 500 VAC (H-W) Rl = 5500 Ω Cl = 4 μf Ib measured Hickok Adapter 1050-144 required
22DE4	1 of 1	-	148	-	10	Ef = 22.4 VAC Epp = 500 VAC (H-W) Rl = 5000 Ω Cl = 4μf Io measured
24A	1 of 1	1200	-	-	20	Ef = 2.5 VAC Eb = 100 Ec2 = 100 Ec1 = -1.6 G1-P Gm measured
25A6	1 of 1	2500	-	-	70	Ef = 25.0 VAC Eb = 100 Ec2 = 100 Ec1 = -17 G1-P Gm measured

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
25A7	1 of 2	2300	-	-	50	Ef = 25.0 VAC Eb = 100 Ec2 = 100 Ec1 = -15 Pent. G1-P Gm measured
25A7	2 of 2	-	120	-	100	Ef = 25.0 VAC Epp = 250 VAC (H-W) Rl = 1350 Ω Diode Io measured Pins 1 & 6 used
25AV5	1 of 2	6900	-	-	100	Ef = 25.0 VAC Eb = 150 Ec2 = 150 Ec1 = -21 G1-P Gm measured
25AV5	2 of 2	-	316	-	100	Ef = 25.0 VAC Ebb = 230 Rl = 750 Ω Ec2 = 150 Ec1 = 0 Ib measured
25AX4	1 of 1	-	148	-	10	Ef = 25.0 VAC Epp = 500 VAC (H-W) Rl = 5500 Ω Cl = 4 μf Io measured
25BK5	1 of 1	10,000	-	-	70	Ef = 25.0 VAC Eb = 150 Ec2 = 150 Ec1 = -1.0 G1-P Gm measured
25BQ6	1 of 2	6900	-	-	100	Ef = 25.0 VAC Eb = 150 Ec2 = 150 Ec1 = -21 G1-P Gm measured
25BQ6	2 of 2	-	316	-	100	Ef = 25.0 VAC Ebb = 230 Ec2 = 150 Ec1 = 0 Rl = 750 Ω Ib measured
25C5	1 of 1	10,000	-	-	70	Ef = 25.0 VAC Eb = 100 Ec2 = 100 Ec1 = -6.2 G1-P Gm measured
25C6	1 of 1	9400	-	-	70	Ef = 25.0 VAC Eb = 100 Ec2 = 100 Ec1 = -8.0 G1-P Gm measured
25CA5	1 of 1	10,000	-	-	70	Ef = 25.0 VAC Eb = 100 Ec2 = 100 Ec1 = -3.2 G1-P Gm measured G pin 2 used
25CD6	1 of 2	10,700	-	-	100	Ef = 25.0 VAC Eb = 150 Ec2 = 150 Ec1 = -24 G1-P Gm measured
25CD6	2 of 2	-	316	-	100	Ef = 25.0 VAC Ebb = 230 Rl = 760 Ω Ec2 = 100 Ec1 = 0 Ib measured
25CU6	1 of 2	6900	-	-	100	Ef = 25.0 VAC Eb = 150 Ec2 = 150 Ec1 = -21 G1-P Gm measured
25CU6	2 of 2	-	316	-	100	Ef = 25.0 VAC Ebb = 230 Rl = 750 Ω Ec2 = 150 Ec1 = 0 Ib measured
25DK4	1 of 1	-	144	-	100	Ef = 25.0 VAC Epp = 250 VAC (H-W) Rl = 1120 Ω Io measured
25DN6	1 of 2	12,500	-	-	100	Ef = 25.0 VAC Eb = 100 Ec2 = 100 Ec1 = -12 G1-P Gm measured
25DN6	2 of 2	-	384	-	100	Ef = 25.0 VAC Ebb = 223 Rl = 720 Ω Ec2 = 100 Ec1 = 0 Ib measured
25DQ6	1 of 2	7000	-	-	100	Ef = 25.0 VAC Eb = 150 Ec2 = 150 Ec1 = -21 G1-P Gm measured
25DQ6	2 of 2	-	420	-	100	Ef = 25.0 VAC Ebb = 207 Rl = 490 Ω Ec2 = 150 Ec1 = 0 Ib measured

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
25DT5	1 of 2	7800	-	-	50	Ef = 25.0 VAC Eb = 150 Ec2 = 150 Ec1 = -8.5 G1-P Gm measured G pin 3 used
25DT5	2 of 2	-	140	-	50	Ef = 25.0 VAC Ebb = 275 Rl = 2150 Ω Ec2 = 150 Ec1 = 0 Ib measured G pin 6 used
25E5/ PL36	1 of 2	12,000	-	-	100	Ef = 25.0 VAC Eb = 150 Ec2 = 150 Ec1 = -20 G1-P Gm measured
25E5/ PL36	2 of 2	-	280	-	100	Ef = 25.0 VAC Ebb = 30 Rl = 950 Ω Ec2 = 100 Ec1 = 0 Ib measured
25EC6	1 of 2	10,700	-	-	100	Ef = 25.0 VAC Eb = 150 Ec2 = 150 Ec1 = -24 G1-P Gm measured
25EC6	2 of 2	-	316	-	100	Ef = 25.0 VAC Ebb = 230 Rl = 760 Ω Ec2 = 100 Ec1 = 0 Ib measured
25EH5	1 of 1	18,400	-	-	70	Ef = 25.0 VAC Eb = 100 Ec2 = 100 Rk = 50 Ω G1-P Gm measured G pin 2 used
25F5	1 of 1	7400	-	-	70	Ef = 25.0 VAC Eb = 100 Ec2 = 100 Ec1 = -6.0 G1-P Gm measured
25L6	1 of 1	10,100	-	-	70	Ef = 25.0 VAC Eb = 150 Ec2 = 150 Ec1 = -12 G1-P Gm measured
25W4	1 of 1	-	148	-	10	Ef = 25.0 VAC Epp = 500 VAC (H-W) Rl = 5800 Ω Cl = 4 μf Io measured
25W6	1 of 1	10,100	-	-	70	Ef = 25.0 VAC Eb = 150 Ec2 = 150 Ec1 = -12 G1-P Gm measured
25Y5	1 of 1	-	120	-	100	Ef = 25.0 VAC Epp = 250 VAC (H-W) Rl = 1200 Ω Io measured Dual Test: 1st Diode: pins 4 & 5 used 2nd Diode: pins 2 & 3 used
25Z5	1 of 1	-	120	-	100	Ef = 25.0 VAC Epp = 250 VAC (H-W) Rl = 1400 Ω Io measured Dual Test: 1st Diode: pins 4 & 5 used 2nd Diode: pins 2 & 3 used
25Z6	1 of 1	-	120	-	100	Ef = 25.0 VAC Epp = 250 VAC (H-W) Rl = 1400 Ω Io measured Dual Test: 1st Diode: pins 5 & 8 used 2nd Diode: pins 3 & 4 used
26	1 of 1	1400	-	-	-	Ef = 1.5 VAC Eb = 150 Ec1 = -12 Gm measured
26A6	1 of 1	5000	-	-	20	Ef = 26.5 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Rk = 120 Ω G1-P Gm measured
26A7	1 of 2	5800	-	-	100	Ef = 26.5 VAC Eb = 50 Ec2 = 50 Ec1 = -12 G1-P Gm measured Pins 1, 2, 5,8 used
26A7	2 of 2	5800	-	-	100	Ef = 26.5 VAC Eb = 50 Ec2 = 50 Ec1 = -12 G1-P Gm measured Pins 2, 3, 4,5 used

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
26AQ8/ UCC85	1 of 1	5000	-	-	20	Ef = 26.0 VAC Eb = 100 Ec1 = -1.0 Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
26BK6	1 of 2	1600	-	-	20	Ef = 26.5 VAC Eb = 100 Ec = -1.0 Triode Gm measured
26BK6	2 of 2	-	1.2	-	20	Ef = 26.5 VAC Ebb = 20 Rl = 16,700 Ω Diode Ib measured Dual Test: 1st Diode: P pin 6 used 2nd Diode: P pin 5 used
26C6	1 of 2	1400	-	-	20	Ef = 26.5 VAC Eb = 50 Ec1 = -1.4 Triode Gm measured
26C6	2 of 2	-	0.6	-	20	Ef = 26.5 VAC Ebb = 20 Rl = 33,300 Ω Diode Ib measured Dual Test: 1st Diode: P pin 6 used 2nd Diode: P pin 5 used
26D6	1 of 2	600	-	-	20	Ef = 26.5 VAC Eb = 50 Ec2, 4 = 50 Ec3-1 = -1.0 G3-P Gm measured
26D6	2 of 2	5300	-	-	20	Ef = 26.5 VAC Eb = 50 Ec3 = 0 Ec2 = 50 Ec1 = -1.0 G1-P, G2, G4 Gm measured
26E6	1 of 1	8900	-	-	70	Ef = 26.5 VAC Eb = 150 Ec2 = 150 Ec1 = -16 G1-P Gm measured
26Z5W	1 of 1	-	176	-	150	Ef = 13.3 VAC (Para.) Epp = 250 VAC (H-W) Rl = 1270 Ω Cl = 4 μf Io measured Dual Test: 1st Diode: pins 6 & 8 used 2nd Diode: pins 1 & 3 used
27	1 of 1	1200	-	-	20	Ef = 2.5 VAC Eb = 150 Ec1 = -11 Gm measured
28AK8/ UABC80	1 of 3	1800	-	-	20	Ef = 28.0 VAC Eb = 100 Ec1 = -1.0 Triode Gm measured
28AK8/ UABC80	2 of 3	-	0.54	-	10	Ef = 28.0 VAC Ebb = 9.0 Rl = 11,100 Ω Diode Ib measured Pins 6 & 7 used
28AK8/ UABC80	3 of 3	-	44	-	10	Ef = 28.0 VAC Ebb = 9.0 Rl = 58 Ω Diode Ib measured Dual Test: 1st Diode: pins 2 & 3 used 2nd Diode: pins 1 & 7 used
28D7	1 of 2	4300	-	-	150	Ef = 28.0 VAC Eb = 50 Ec2 = 50 Ec1 = -8.2 G1-P Gm measured Pins 3, 5, 6, 7 used
28D7	2 of 2	4300	-	-	150	Ef = 28.0 VAC Eb = 50 Ec2 = 50 Ec1 = -8.2 G1-P Gm measured Pins 2, 3, 4, 6 used
30	1 of 1	-	3.9	-	-	Ef = 2.0 VAC Eb = 150 Ec1 = -11 Ib measured
31	1 of 1	-	12	-	-	Ef = 2.0 VAC Eb = 150 Ec1 = -25 Ib measured

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
32	1 of 1	-	1.76	-	-	Ef = 2.0 VAC Eb = 50 Ec2 = 50 Ec1 = -1.0 Ib measured
32ET5	1 of 1	6900	-	-	50	Ef = 32.0 VAC Eb = 100 Ec2 = 100 Ec1 = -6.2 G1-P Gm measured G pin 2 used
32L7	1 of 2	8600	-	-	50	Ef = 32.5 VAC Eb = 100 Ec2 = 100 Ec1 = -5.5 Pent. G1-P Gm measured Pins 3, 4, 5, 8 used
32L7	2 of 2	-	96	-	100	Ef = 32.5 VAC Epp = 250 VAC (H-W) Rl = 1660 Ω Diode Io measured Pins 1 & 6 used
34GD5	1 of 1	7200	-	-	50	Ef = 34.0 VAC Eb = 100 Ec2 = 100 Ec1 = -5.4 G1-P Gm measured
35	1 of 1	1300	-	-	20	Ef = 2.5 VAC Eb = 100 Ec2 = 100 Ec1 = -1.5 G1-P Gm measured
35A5	1 of 1	7300	-	-	70	Ef = 35.0 VAC Eb = 100 Ec2 = 100 Ec1 = -6.0 G1-P Gm measured
35B5	1 of 1	7300	-	-	70	Ef = 35.0 VAC Eb = 100 Ec2 = 100 Ec1 = -6.0 G1-P Gm measured
35C5	1 of 1	7300	-	-	70	Ef = 35.0 VAC Eb = 100 Ec2 = 100 Ec1 = -6.0 G1-P Gm measured
35CD6	1 of 2	10,700	-	-	100	Ef = 35.0 VAC Eb = 150 Ec2 = 150 Ec1 = -24 G1-P Gm measured
35CD6	2 of 2	-	316	-	100	Ef = 35.0 VAC Ebb = 230 Rl = 760 Ω Ec2 = 100 Ec1 = 0 Ib measured
35DZ8	1 of 2	9500	-	-	50	Ef = 35.0 VAC Eb = 100 Ec2 = 100 Rk = 140 Ω Pent. G1-P Gm measured
35DZ8	2 of 2	1800	-	-	20	Ef = 35.0 VAC Eb = 100 Rk = 1200 Ω Triode Gm measured
35EH5	1 of 1	15,000	-	-	70	Ef = 35.0 VAC Eb = 100 Ec2 = 100 Rk = 50 Ω G1-P Gm measured G pin 2 used
35GL6	1 of 1	9500	-	-	70	Ef = 35.0 VAC Eb = 100 Ec2 = 100 Ec1 = -6.2 G1-P Gm measured
35HB8	1 of 2	7800	-	-	50	Ef = 35.0 VAC Eb = 100 Ec2 = 100 Rk = 130 Ω Pent. G1-P Gm measured
35HB8	2 of 2	4900	-	-	50	Ef = 35.0 VAC Eb = 100 Rk = 360 Ω Triode Gm measured
35L6	1 of 1	7300	-	-	70	Ef = 35.0 VAC Eb = 100 Ec2 = 100 Ec1 = -6.0 G1-P Gm measured
35W4	1 of 1	-	160	-	100	Ef = 35.0 VAC Epp = 250 VAC (H-W) Rl = 1040 Ω Io measured
35Y4	1 of 1	-	160	-	100	Ef = 35.0 VAC Epp = 250 VAC (H-W) Rl = 1040 Ω Io measured
35Z3	1 of 1	-	160	-	100	Ef = 35.0 VAC Epp = 250 VAC (H-W) Rl = 1040 Ω Io measured

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
35Z4	1 of 1	-	160	-	100	Ef = 35.0 VAC Epp = 250 VAC (H-W) Rl = 1040 Ω Io measured
35Z5	1 of 1	-	160	-	100	Ef = 35.0 VAC Epp = 250 VAC (H-W) Rl = 1040 Ω Io measured
35Z6	1 of 1	-	176	-	100	Ef = 35.0 VAC Epp = 250 VAC (H-W) Rl = 880 Ω Io measured Dual Test: 1st Diode: pins 5 & 8 used 2nd Diode: pins 3 & 4 used
36	1 of 1	900	-	-	20	Ef = 6.3 VAC Eb = 50 Ec2 = 50 Ec1 = -1.0 G1-P Gm measured
36AM3	1 of 1	-	120	-	70	Ef = 36.0 VAC Epp = 250 VAC (H-W) Rl = 1330 Ω Io measured
37	1 of 1	1100	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -11 Gm measured
38	1 of 1	1200	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -15 G1-P Gm measured
38A3/ UY85	1 of 1	-	176	-	150	Ef = 38.0 VAC Epp = 250 VAC (H-W) Rl = 1500 Ω Cl = 4 μf Io measured
39/44	1 of 1	1200	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -3.0 G1-P Gm measured
40FR5	1 of 1	7500	-	-	50	Ef = 40.0 VAC Eb = 100 Ec2 = 100 Ec1 = -6.0 G1-P Gm measured G pin 2 used
41	1 of 1	1900	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -7.0 G1-P Gm measured
42	1 of 1	3500	-	-	70	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -3.3 G1-P Gm measured
43	1 of 1	2500	-	-	70	Ef = 25.0 VAC Eb = 100 Ec2 = 100 Ec1 = -17 G1-P Gm measured
45	1 of 1	2500	-	-	-	Ef = 2.5 VAC Eb = 150 Ec1 = -25 Gm measured
45Z3	1 of 2	-	104	-	70	Ef = 45.0 VAC Epp = 250 VAC (H-W) Rl = 1510 Ω Io measured P pin 6 used
45Z3	2 of 2	-	104	-	70	Ef = 45.0 VAC Epp = 250 VAC (H-W) Rl = 1510 Ω Io measured P pin 2 used
46	1 of 1	-	26	-	-	Ef = 2.5 VAC Eb = 150 Ec2 = 150 Ec1 = -13 Ib measured
47	1 of 1	3200	-	-	-	Ef = 2.5 VAC Eb = 150 Ec2 = 150 Ec1 = -2.0 G1-P Gm measured
48	1 of 1	4900	-	-	50	Ef = 30.0 VAC Eb = 100 Ec2 = 100 Ec1 = -21 G1-P Gm measured
50A5	1 of 1	10, 100	-	-	70	Ef = 50.0 VAC Eb = 150 Ec2 = 150 Ec1 = -12 G1-P Gm measured
50B5	1 of 1	10,000	-	-	70	Ef = 50.0 VAC Eb = 100 Ec2 = 100 Ec1 = -6.2 G1-P Gm measured

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
50BK5	1 of 1	10,000	-	-	70	Ef = 50.0 VAC Eb = 150 Ec2 = 150 Ec1 = -1.0 G1-P Gm measured
50BM8/ UCL82	1 of 2	8600	-	-	50	Ef = 50.0 VAC Eb = 100 Ec2 = 100 Ec1 = -6.0 Pent. G1-P Gm measured
50BM8/ UCL82	2 of 2	3200	-	-	20	Ef = 50.0 VAC Eb = 150 Ec1 = -1.2 Triode Gm measured
50C5	1 of 1	10,000	-	-	70	Ef = 50.0 VAC Eb = 100 Ec2 = 100 Ec1 = -6.2 G1-P Gm measured
50C6	1 of 1	9400	-	-	70	Ef = 50.0 VAC Eb = 100 Ec2 = 100 Ec1 = -8.0 G1-P Gm measured
50DC4	1 of 1	-	192	-	100	Ef = 50.0 VAC Epp = 250 VAC (H-W) Rl = 750 Ω Io measured
50EH5	1 of 1	18,400	-	-	70	Ef = 50.0 VAC Eb = 100 Ec2 = 100 Rk = 50 Ω G1-P Gm measured G pin 2 used
50FA5	1 of 1	7300	-	-	50	Ef = 50.0 VAC Eb = 100 Ec2 = 100 Ec1 = -5.5 G1-P Gm measured
50FE5	1 of 1	12,000	-	-	100	Ef = 50.0 VAC Eb = 150 Ec2 = 150 Rk = 130 Ω G1-P Gm measured
50FK5	1 of 1	14,800	-	-	50	Ef = 50.0 VAC Eb = 100 Ec2 = 100 Rk = 60 Ω G1-P Gm measured G pin 2 used
50FY8	1 of 2	9400	-	-	50	Ef = 50.0 VAC Eb = 100 Ec2 = 100 Rk = 100 Ω Pent. G1-P Gm measured
50FY8	2 of 2	3400	-	-	20	Ef = 50.0 VAC Eb = 100 Ec = -1.9 Triode Gm measured
50HC6	1 of 1	18,400	-	-	70	Ef = 50.0 VAC Eb = 100 Ec2 = 100 Rk = 50 Ω G1-P Gm measured G pin 2 used
50HK6	1 of 1	10,000	-	-	70	Ef = 50.0 VAC Eb = 100 Ec2 = 100 Ec1 = -6.2 G1-P Gm measured
50L6	1 of 1	10, 100	-	-	70	Ef = 50.0 VAC Eb = 150 Ec2 = 150 Ec1 = -12 G1-P Gm measured
50X6	1 of 1	-	120	-	100	Ef = 50.0 VAC Epp = 250 VAC (H-W) Rl = 1400 Ω Io measured Dual Test: 1st Diode: pins 6 & 7 used 2nd Diode: pins 2 & 3 used
50Y6	1 of 1	-	120	-	100	Ef = 50.0 VAC Epp = 250 VAC (H-W) Rl = 1400 Ω Io measured Dual Test: 1st Diode: pins 5 & 8 used 2nd Diode: pins 3 & 4 used
50Y7	1 of 1	-	120	-	100	Ef = 50.0 VAC Epp = 250 VAC (H-W) Rl = 1400 Ω Io measured Dual Test: 1st Diode: pins 5 & 8 used 2nd Diode: pins 3 & 4 used

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
53	1 of 1	2100	-	-	20	Ef = 2.5 VAC Eb = 150 Ec1 = -2.0 Gm measured Dual Test: 1st Triode: pins 4, 5, 6 used 2nd Triode: pins 2, 3, 4 used
55	1 of 2	1100	-	-	20	Ef = 2.5 VAC Eb = 150 Ec = -11 Triode Gm measured
55	2 of 2	-	0.6	-	20	Ef = 2.5 VAC Ebb = 20 Rl = 33,300 Ω Diode Ib measured Dual Test: 1st Diode: P pin 4 used 2nd Diode: P pin 3 used
56	1 of 1	1400	-	-	20	Ef = 2.5 VAC Eb = 100 Ec1 = -5.0 Gm measured
57	1 of 1	1500	-	-	20	Ef = 2.5 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -3.0 G1-P Gm measured
58	1 of 1	1900	-	-	20	Ef = 2.5 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -3.0 G1-P Gm measured
59	1 of 1	3100	-	-	20	Ef = 2.5 VAC Eb = 150 Ec2 = 150 Ec1 = -9.0 G1-P Gm measured
60FX5	1 of 1	16,400	-	-	50	Ef = 60.0 VAC Eb = 100 Ec2 = 100 Rk = 60 Ω G1-P Gm measured G pin 2 used
70L7	1 of 2	9500	-	-	100	Ef = 70.0 VAC Eb = 100 Ec2 = 100 Ec1 = -6.0 Pent. G1-P Gm measured
70L7	2 of 2	-	112	-	150	Ef = 70.0 VAC Epp = 250 VAC (H-W) Rl = 1400 Ω Diode Io measured
71A	1 of 1	-	24	-	-	Ef = 50 VAC Eb = 150 Ec1 = -30 Ib measured
72	1 of 1	-	112	-	-	Ef = 2.5 VAC Ebb = 306 Rl = 1900 Ω Diode Ib measured OK 56 to 90 MA
75	1 of 2	1200	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -1.0 Triode Gm measured
75	2 of 2	-	0.6	-	20	Ef = 6.3 VAC Ebb = 20 Rl = 33,300 Ω Diode Ib measured Dual Test: 1st Diode: P pin 4 used 2nd Diode: P pin 3 used
76	1 of 1	1400	-	-	20	Ef = 6.3 VAC Eb = 100 Ec1 = -5.0 Gm measured
77	1 of 1	1500	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec3 = 0 Ec1 = -2.5 G1-P Gm measured
78	1 of 1	2100	-	-	20	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -1.0 G1-P Gm measured
79	1 of 1	1700	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -1.0 Gm measured Dual Test: 1st Triode: pins 4, 5 cap used 2nd Triode: pins 2, 3, 4 used
80	1 of 1	-	200	-	-	Ef = 5.0 VAC Epp = 250 VAC (F-W) Rl = 1700 Ω Cl = 4 μf Io measured

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
81	1 of 1	-	136	-	-	Ef = 7.5 VAC Epp = 500 VAC (H-W) Rl = 4300 Ω Cl = 4 μf Io measured
82	1 of 1	-	184	-	-	Ef = 2.5 VAC Epp = 250 VAC (F-W) Rl = 2200 Ω Cl = 4 μf Io measured
83	1 of 1	-	320	-	-	Ef = 5.0 VAC Epp = 250 VAC (F-W) Rl = 1160 Ω Cl = 4 μf Io measured
83V	1 of 1	-	280	-	-	Ef = 5.0 VAC Epp = 250 VAC (F-W) Rl = 1230 Ω Cl = 4 μf Io measured
84	1 of 1	-	96	-	150	Ef = 6.3 VAC Epp = 250 VAC (F-W) Rl = 5000 Ω Cl = 4 μf Io measured
85	1 of 2	1100	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -11 Triode Gm measured
85	2 of 2	-	0.6	-	20	Ef = 6.3 VAC Ebb = 20 Rl = 33,300 Ω Diode Ib measured Dual Test: 1st Diode: P pin 4 used 2nd Diode: P pin 3 used
89	1 of 1	1700	-	-	50	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Ec1 = -15 G1-P Gm measured
90C1	1 of 4	Instruction Card				
90C1	2 of 4	-	0.2	-	-	Leakage test at 50 volts
90C1	3 of 4	-	-	150	-	Etd measured at 5 MA
90C1	4 of 4	-	-	150	-	Etd measured at 40 MA

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
CK108	1 of 1	1500	-	-	20	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -2.5 G1-P Gm measured
117L7	1 of 2	6500	-	-	100	Ef = 117.0 VAC Eb = 100 Ec2 = 100 Ec1 = -5.0 Pent. G1-P Gm measured
117L7	2 of 2	-	120	-	150	Ef = 117.0 VAC Epp = 250 VAC (H-W) Rl = 3150 Ω Diode Io measured
117M7	1 of 2	6500	-	-	100	Ef = 117.0 VAC Eb = 100 Ec2 = 100 Ec1 = -5.0 Pent. G1-P Gm measured
117M7	2 of 2	-	120	-	150	Ef = 117.0 VAC Epp = 250 VAC (H-W) Rl = 3150 Ω Diode Io measured
117N7	1 of 3	8800	-	-	70	Ef = 117.0 VAC Eb = 100 Ec2 = 100 Ec1 = -6.0 Pent. G1-P Gm measured Pins 3, 4, 5, 6 used
117N7	2 of 3	-	14	-	70	Ef = 117.0 VAC Short Test Only. Meter deflection not dependent on tube Diode Pins: 7 & 8 used
117N7	3 of 3	-	26	-	-	Ef = 117.0 VAC Rectifier Epp = 117 VAC (H-W) Pentode: Eb = 150 (Peak) Ec2 = 50 Ec1 = 0 Io measured
117P7	1 of 3	6700	-	-	70	Ef = 117.0 VAC Eb = 100 Ec2 = 100 Ec1 = -4.4 G1-P Gm measured Pins 3, 4, 5, 6 used

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
117P7	2 of 3	-	14	-	150	Ef = 117.0 VAC Short test only. Meter deflection not dependent on tube. Pins 7 & 8 used
117P7	3 of 3	-	18	-	-	Ef = 117.0 VAC Rectifier Epp = 117 VAC (H-W) Pentode: Eb = 150 (Peak) Ec2 = 50 Ec1 = 0 Io measured
117Z3	1 of 1	-	144	-	100	Ef = 117.0 VAC Epp = 250 VAC (H-W) Rl = 1160 Ω Io measured
117Z4	1 of 1	-	144	-	100	Ef = 117.0 VAC Epp = 250 VAC (H-W) Rl = 1160 Ω Io measured
117Z6	1 of 1	-	96	-	100	Ef = 117.0 VAC Epp = 250 VAC (H-W) Rl = 1800 Ω Io measured Dual Test: 1st Diode: pins 5 & 8 used 2nd Diode: pins 3 & 4 used
X155	1 of 1	8200	-	-	20	Ef = 6.3 VAC Eb = 150 Rk = 150 Ω Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
TS251	1 of 2	2300	-	-	50	Ef = 50.0 VAC Eb = 100 Ec2 = 100 Ec1 = -15 Pent. G1-P Gm measured
TS251	2 of 2	-	120	-	100	Ef = 50.0 VAC Epp = 250 VAC (H-W) Rl = 1350 Ω Diode Ib measured
292A	1 of 2	1000	-	-	20	Ef = 10.0 VAC Eb = 180 Ec1 = -7.5 Triode Gm measured
292A	2 of 2	-	0.72	-	20	Ef = 10.0 VAC Ebb = 20 Rl = 27,800 Ω Diode Ib measured Dual Test: 1st Diode: P pin 4 used 2nd Diode: P pin 3 used
303A	1 of 2	1000	-	-	20	Ef = 2.0 VAC Eb = 180 Ec1 = -7.5 Triode Gm measured
303A	2 of 2	-	0.72	-	20	Ef = 2.0 VAC Ebb = 20 Rl = 27,800 Ω Diode Ib measured Dual Test: 1st Diode: P pin 4 used 2nd Diode: P pin 3 used
307A	1 of 1	-	64	-	-	Ef = 5.5 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Ec1 = -6.3 G1-P Gm measured
311A	1 of 1	3800	-	-	70	Ef = 10.0 VAC Eb = 150 Ec2 = 150 Ec1 = -17 G1-P Gm measured
347A	1 of 1	1100	-	-	20	Ef = 6.3 VAC Eb = 180 Ec1 = -7.5 Gm measured
351A	1 of 1	-	160	-	100	Ef = 6.3 VAC Epp = 250 VAC (F-W) Rl = 2500 Ω Cl = 4 μf Io measured
384A	1 of 2	Instruction Card				
384A	2 of 2	2800	-	-	20	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -1.4 G1-P Gm measured
395A	1 of 3	Instruction Card				
395A	2 of 3	-	-	100	-	Starter Etd measured at 10 MA OK 52 to 74 volts

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
395A	3 of 3	-	-	100		Anode Etd measured at 10 MA OK 68 to 85 volts
502A	1 of 3	-	166	-	20	Ef = 6.3 VAC Ebb = 150 Rl = 1350 Ω Ec2 = 0 Ec1 = 0 Ib measured
502A	2 of 3	-	-	100	20	Ef = 6.3 VAC Etd measured at 100 MA OK under 20 volts
502A	3 of 3	-	24	-	-	Ef = 6.3 VAC Epp = 250 Ec2 = 0 Ec1 = -21 Ib measured OK under 2.4 MA
CK512 AX	1 of 1	500	-	-	-	Ef = 0.62 VDC Eb = 19 Ec2 = 19 Ec1 = -1.0 G1-P, G2 Gm measured OK over 100 μmho
CK526 AX	1 of 1	-	0.64	-	-	Ef = 1.2 VAC Eb = 50 Ec2 = 50 Ec1 = -7.0 Ib measured
CK533 AX	1 of 1	-	0.5	-	-	Ef = 1.2 VAC Ebb = 50 Rl = 100,000 Ω Ec2 = 50 Ec1 = -3.1 Ib measured
559	1 of 1	-	44	-	20	Ef = 6.3 VAC Ebb = 9.0 Rl = 148 Ω Ib measured K pin 8 used
CK573 AX	1 of 1	-	14	-	-	Ef = 1.2 VAC Eb = 100 Ec1 = -5.0 Ib measured
629	1 of 3	-	67	-	20	Ef = 2.5 VAC Ebb = 150 Rl = 3380 Ω Ec = 0 Ib measured
629	2 of 3	-	-	100	20	Ef = 2.5 VAC Etd measured at 40 MA OK under 20 volts
629	3 of 3	-	30	-	-	Ef = 2.5 VAC Eb = 150 Ec1 = -18 Ib measured OK under 3 MA
713A	1 of 2	5000	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -1.2 G1-P Gm measured K pin 5 used
713A	2 of 2	5000	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -1.2 G1-P Gm measured K pin 3 used
717A	1 of 2	5000	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -1.2 G1-P Gm measured K pin 5 used
717A	2 of 2	5000	-	-	20	Ef = 6.3 VAC Eb = 120 Ec2 = 120 Ec1 = -2.0 G1-P Gm measured K pin 3 used
801A	1 of 2	-	18	-	-	Ef = 7.5 VAC Eb = 150 Ec1 = -5.8 Ib measured
801A	2 of 2	-	-	200	-	Ef = 7.5 VAC Etd measured at 60 MA OK under 100 volts
807	1 of 1	7500	-	-	100	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -1.5 G1-P Gm measured
809	1 of 1	-	316	-	-	Ef = 6.0 VAC Eb = 200 Ec1 = +50 Ib measured
811A	1 of 1	-	-	200	-	Ef = 4.5 VAC Etd measured at 60 MA OK under 100 volts
815	1 of 2	5000	-	-	50	Ef = 6.3 VAC (Para.) Eb = 150 Ec2 = 150 Ec1 = -12 G1-P Gm measured Pins 2, 3, 4, right cap used

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
815	2 of 2	5000	-	-	50	Ef = 6.3 VAC (Para.) Eb = 150 Ec2 = 150 Ec1 = -12 G1-P Gm measured Pins 4, 6, 7, left cap used
816	1 of 1	-	200	-	-	Ef = 2.5 VAC Epp = 250 VAC (H-W) Rl = 1160 Ω Cl = 4 μf Io measured
837	1 of 1	4300	-	-	100	Ef = 12.6 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Ec1 = -8.2 G1-P Gm measured
842	1 of 2	-	40	-	-	Ef = 7.5 VAC Eb = 150 Ec1 = -6.5 Ib measured
842	2 of 2	-	120	-	-	Ef = 7.5 VAC Eb = 100 Ec1 = +100 Ik measured
843	1 of 2	2000	-	-	100	Ef = 2.5 VAC Eb = 150 Ec1 = -1.9 Gm measured
843	2 of 2	-	-	140	100	Ef = 2.5 VAC Etd measured at 120 MA OK under 70 volts
865	1 of 1	-	14	-	-	Ef = 7.0 VAC Eb = 150 Ec2 = 150 Ec1 = -15 Ib measured
866A	1 of 1	-	320	-	-	Ef = 2.5 VAC Epp = 250 VAC (H-W) Rl = 500 Ω Cl = 4 μf Io measured
874	1 of 4	Instruction Card				
874	2 of 4	-	0.1	-	-	Leakage test at 50 volts
874	3 of 4	-	-	200	-	Etd measured at 10 MA
874	4 of 4	-	-	200	-	Etd measured at 50 MA

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
884	1 of 3	-	100	-	20	Ef = 6.3 VAC Ebb = 150 Rl = 2250 Ω Ec1 = 0 Ib measured
884	2 of 3	-	-	100	20	Ef = 6.3 VAC Etd measured at 60 MA OK under 20 volts
884	3 of 3	-	10	-	-	Ef = 6.3 VAC Eb = 150 Ec1 = -34 Ib measured OK under 1.0 MA
885	1 of 3	-	100	-	20	Ef = 2.5 VAC Ebb = 150 Rl = 2250 Ω Ec1 = 0 Ib measured
885	2 of 3	-	-	100	20	Ef = 2.5 VAC Etd measured at 60 MA OK under 20 volts
885	3 of 3	-	10	-	-	Ef = 2.5 VAC Eb = 150 Ec1 = -34 Ib measured OK under 1.0 MA
1005	1 of 3	-	124	-	-	Ef = 6.3 VAC Ebb = 295 Rl = 3600 Ω Ib measured P pins 3 & 5 jumpered
1005	2 of 3	-	-	100	-	Ef = 6.3 VAC Etd measured at 70 MA OK under 40 volts P pin 5 used
1005	3 of 3	-	-	100	-	Ef = 6.3 VAC Etd measured at 70 MA OK under 40 volts P pin 3 used
CK 1006	1 of 2	-	164	-	-	Ef = 1.75 VAC Epp = 500 VAC (H-W) Rl = 2000 Ω Io measured P pin 3 used
CK 1006	2 of 2	-	164	-	-	Ef = 1.75 VAC Epp = 500 VAC (H-W) Rl = 2000 Ω Io measured P pin 2 used
1007	1 of 3	-	192	-	-	Ef = 1.0 VAC Ebb = 277 Rl = 2100 Ω Ib measured P pins 3 & 5 jumpered

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
1007	2 of 3	-	-	100	-	Ef = 1.0 VAC Etd measured at 110 MA OK under 50 volts P pin 5 used
1007	3 of 3	-	-	100	-	Ef = 1.0 VAC Etd measured at 110 MA OK under 50 volts P pin 3 used
1229	1 of 1	-	1.76	-	-	Ef = 2.0 VAC Eb = 50 Ec2 = 50 Ec1 = -1.0 Ib measured
1273	1 of 1	2900	-	-	20	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -1.0 G1-P Gm measured
1280	1 of 1	2900	-	-	20	Ef = 12.6 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -1.0 G1-P Gm measured
1603	1 of 1	1500	-	-	10	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -3.0 G1-P Gm measured
1609	1 of 1	-	1.9	-	-	Ef = 1.1 VAC Eb = 50 Ec2 = 50 Ec1 = -1.0 Ib measured
1612	1 of 2	1200	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2,4 = 100 Ec1,3 = -3.0 G1-P Gm measured
1612	2 of 2	600	-	-	20	Ef = 6.3 VAC Eb = 50 Ec4, 2 = 50 Ec3 = -1.5 Ec1 = 0 G3-P Gm measured
1613	1 of 1	2400	-	-	70	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -10 G1-P Gm measured
1614	1 of 1	6700	-	-	70	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -7.0 G1-P Gm measured
1619	1 of 1	-	52	-	-	Ef = 2.5 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Ec1 = -1.0 G1-P Gm measured
1620	1 of 1	1500	-	-	20	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -3.0 G1-P Gm measured
1621	1 of 1	3500	-	-	70	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -3.3 G1-P Gm measured
1622	1 of 1	6700	-	-	70	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -7.0 G1-P Gm measured
1624	1 of 2	-	48	-	-	Ef = 2.5 VAC Eb = 150 Ec2 = 150 Ec1 = -1.5 Ib measured
1624	2 of 2	-	-	100	-	Ef = 2.5 VAC OK under 50 V Etd measured at 100 MA
1625	1 of 1	7500	-	-	100	Ef = 12.6 VAC Eb = 150 Ec2 = 150 Ec1 = -1.5 G1-P Gm measured
1626	1 of 1	2700	-	-	20	Ef = 12.6 VAC Eb = 150 Ec1 = -15 Gm measured
1629	1 of 2	-	-	-	20	Ef = 12.6 VAC E (Screen) = Open Ckt E (Target) = 300 Ec1 = 0 Eye open Quality Test: No Meter Reading

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
1629	2 of 2	-	-	-	20	Ef = 12.6 VAC E (Screen) = 150 E (Target) = 150 Ec1 = -64 Eye closed Quality Reading: No Meter Reading
1631	1 of 1	6700	-	-	70	Ef = 12.6 VAC Eb = 150 Ec2 = 150 Ec1 = -7.0 G1-P Gm measured
1633	1 of 1	3500	-	-	20	Ef = 25.0 VAC Eb = 150 Ec1 = -2.9 Gm measured Dual Test: 1st Triode: pins 4, 5, 6 used 2nd Triode: pins 1, 2, 3 used
1635	1 of 4	800	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -1.0 Gm measured P pin 6 used G pin 5 used
1635	2 of 4	-	-	100	20	Ef = 6.3 VAC Etd measured at 80 MA OK under 50 V P pin 6 used G pin 5 used
1635	3 of 4	800	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -1.0 Gm measured P pin 3 used G pin 4 used
1635	4 of 4	-	-	100	20	Ef = 6.3 VAC Etd measured at 80 MA OK under 50 P pin 3 used G pin 4 used
1641	1 of 2	-	320	-	-	Ef = 5.0 VAC Epp = 250 VAC (H-W) Rl = 310 Ω Cl = 4 μf Io measured P: 1st cap used
1641	2 of 2	-	320	-	-	Ef = 5.0 VAC Epp = 250 VAC (H-W) Rl = 310 Ω Cl = 4 μf Io measured P: 2nd cap used
1644	1 of 2	2700	-	-	50	Ef = 12.6 VAC Eb = 150 Ec2 = 150 Ec1 = -6.3 G1-P Gm measured G pin 1 used P pin 8 used
1644	2 of 2	2700	-	-	50	Ef = 12.6 VAC Eb = 150 Ec2 = 150 Ec1 = -6.3 G1-P Gm measured G pin 3 used P pin 4 used
1851	1 of 1	11,300	-	-	20	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 160 Ω G1-P Gm measured
1852	1 of 1	11,300	-	-	20	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 160 Ω G1-P Gm measured
2050	1 of 3	-	166	-	20	Ef = 6.3 VAC Ebb = 150 Ec2, 1 = 0 Rl = 1350 Ω Ib measured
2050	2 of 3	-	-	100	20	Ef = 6.3 VAC Etd measured at 100 MA OK under 20 V
2050	3 of 3	-	24	-	-	Ef = 6.3 VAC Ebb = 250 Rl = 10,000 Ω Ec2 = 0 Ec1 = -21 Ib cutoff test OK under 2.4 MA
2051	1 of 3	-	124	-	20	Ef = 6.3 VAC Ebb = 150 Ec2, 1 = 0 Rl = 1750 Ω Ib measured
2051	2 of 3	-	-	100	20	Ef = 6.3 VAC Etd measured at 75 MA OK under 20 V
2051	3 of 3	-	24	-	-	Ef = 6.3 VAC Ebb = 250 Rl = 10,000 Ω Ec2 = 0 Ec1 = -25 Ib cutoff test OK under 2.4 MA

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
5608A	1 of 1	2100	-	-	20	Ef = 2.5 VAC Eb = 150 Ec1 = -2.0 Gm measured Dual Test: 1st Triode: pins 4, 5, 6 used 2nd Triode: pins 2, 3, 4 used
5618	1 of 1	-	24	-	-	Ef = 3.0 VAC (Para.) Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -9.2 G1-P Gm measured
5636	1 of 2	4700	-	-	10	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Rk = 150 Ω G1-P Gm measured K pin 2 used
5636	2 of 2	1800	-	-	10	Ef = 6.3 VAC Eb = 50 Ec3 = 0 Ec2 = 50 Rk = 200 Ω G3-P Gm measured K pin 8 used OK over 540 μmhos
5639	1 of 1	13,100	-	-	50	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Rk = 100 Ω G1-P Gm measured
5641	1 of 3	-	80	-	20	Ef = 6.3 VAC Epp = 250 VAC (H-W) Rl = 5000 Ω Cl = 4 μf Io measured P pin 8 used
5641	2 of 3	-	80	-	20	Ef = 6.3 VAC Epp = 250 VAC (H-W) Rl = 5000 Ω Cl = 4 μf Io measured P pin 4 used
5641	3 of 3	-	80	-	20	Ef = 6.3 VAC Epp = 250 VAC (H-W) Rl = 5000 Ω Cl = 4 μf Io measured P pin 2 used
5642	1 of 1	-	7.1	-	-	Ef = 1.2 VAC Eb = 50 Ib measured
5643	1 of 3	-	26	-	20	Ef = 6.3 VAC Ebb = 150 Ec2, 1 = 0 Rl = 8750 Ω Ib measured G2 pin 2 used
5643	2 of 3	-	-	100	20	Ef = 6.3 VAC Etd measured at 16 MA OK under 15 V G2 pin 4 used
5643	3 of 3	-	24	-	-	Ef = 6.3 VAC Epp = 250 VAC Rl = 10,000 Ω Ec2 = 0 Ec1 = -31 Ib cutoff test OK under 2.4 MA G2 pin 8 used
5644	1 of 4	Instruction Card				
5644	2 of 4	-	0.1	-	-	Leakage test at 50 V
5644	3 of 4	-	-	200	-	Etd measured at 5 MA
5644	4 of 4	-	-	200	-	Etd measured at 25 MA
5647	1 of 2	Instruction Card				
5647	2 of 2	-	16	-	10	Ef = 6.3 VAC Epp = 250 VAC (H-W) Rl = 10,900 Ω Io measured
5651	1 of 4	Instruction Card				
5651	2 of 4	-	0.2	-	-	Leakage test at 50 V
5651	3 of 4	-	-	150	-	Etd measured at 1.5 MA
5651	4 of 4	-	-	150	-	Etd measured at 3.5 MA
5654	1 of 2	7100	-	-	10	Ef = 6.3 VAC Eb = 120 Ec2 = 120 Ec1 = -2.0 G1-P Gm measured K pin 7 used
5654	2 of 2	7100	-	-	10	Ef = 6.3 VAC Eb = 120 Ec2 = 120 Ec1 = -2.0 G1-P Gm measured K pin 2 used

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
5656	1 of 2	6800	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -1.0 G1-P Gm measured P pin 8 used G1 pin 2 used K pin 9 used
5656	2 of 2	6800	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -1.0 G1-P Gm measured P pin 7 used G1 pin 3 used K pin 6 used
5659	1 of 1	4000	-	-	100	Ef = 12.6 VAC Eb = 150 Ec2 = 150 Ec1 = -2.0 G1-P Gm measured
5661	1 of 1	3000	-	-	20	Ef = 12.6 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -1.0 G1-P Gm measured
5663	1 of 3	-	32	-	20	Ef = 6.3 VAC Ebb = 150 Ec2, 1 = 0 Rl = 6900 Ω Ib measured
5663	2 of 3	-	-	100	20	Ef = 6.3 VAC Etd measured at 60 MA OK under 15 V
5663	3 of 3	-	24	-	-	Ef = 6.3 VAC Epp = 250 VAC Ec1 = -28 Ec2 = 0 Rl = 10,000 Ω Ib cutoff test OK under 2.4 MA
5670	1 of 1	7700	-	-	10	Ef = 6.3 VAC Eb = 150 Rk = 240 Ω Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 2, 3, 4 used
5672	1 of 1	800	-	-	-	Ef = 1.2 VAC Eb = 50 Ec2 = 50 Ec1 = -4.5 G1-P Gm measured
5676	1 of 1	2000	-	-	-	Ef = 1.2 VAC Eb = 100 Ec1 = -3.0 Gm measured
5677	1 of 1	-	2.6	-	-	Ef = 1.3 VAC Eb = 100 Ec1 = -3.6 Ib measured
5678	1 of 1	1000	-	-	-	Ef = 1.2 VAC Eb = 50 Ec2 = 50 Ec1 = -1.0 G1-P Gm measured
5686	1 of 3	4400	-	-	50	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -2.5 G1-P Gm measured K pin 8 used G2 pin 9 used
5686	2 of 3	-	34	-	50	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -2.5 Ib measured K pin 3 used G2 pin 6 used
5686	3 of 3	-	-	60	50	Ef = 6.3 VAC Etd measured at 59 MA OK under 30 V K pin 1 used
5687	1 of 2	16,000	-	-	20	Ef = 6.3 VAC (Para.) Eb = 120 Ec1 = -2.0 Gm measured Dual Test: 1st Triode: pins 6, 7, 9 used 2nd Triode: pins 1, 2, 3 used
5687	2 of 2	-	50	-	20	Ef = 6.3 VAC (Para.) Eb = 120 Ec1 = -2.0 Ib measured Dual Test: 1st Triode: pins 6, 7, 9 used 2nd Triode: pins 1, 2, 3 used
5690	1 of 2	-	216	-	100	Ef = 6.3 VAC Epp = 250 VAC (H-W) Rl = 900 Ω Cl = 4 μf Io measured Pins 5 & 8 used

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
5690	2 of 2	-	216	-	100	Ef = 6.3 VAC Epp = 250 VAC (H-W) Rl = 900 Ω Cl = 4 μf Io measured Pins 3 & 4 used
5691	1 of 1	1500	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -1.5 Gm measured Dual Test: 1st Triode: pins 4, 5, 6 used 2nd Triode: pins 1, 2, 3 used
5692	1 of 1	2200	-	-	10	Ef = 6.3 VAC Eb = 150 Ec1 = -4.2 Gm measured Dual Test: 1st Triode: pins 4, 5, 6 used 2nd Triode: pins 1, 2, 3 used
5693	1 of 1	2500	-	-	10	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -3.0 G1-P Gm measured
5696	1 of 3	-	42	-	20	Ef = 6.3 VAC Ebb = 150 Rl = 5600 Ω Ec2, 1 = 0 Ik measured G2 pin 7 used
5696	2 of 3	-	-	100	-	Ef = 6.3 VAC Etd measured at 28 MA OK under 15 V G2 pin 5 used
5696	3 of 3	-	24	-	-	Ef = 6.3 VAC Epp = 250 VAC Ec2 = 0 Ec1 = -50 Rl = 10,000 Ω Ib cutoff test OK under 2.4 MA
5702	1 of 1	6500	-	-	10	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Rk = 100 Ω G1-P Gm measured
5703	1 of 3	6300	-	-	20	Ef = 6.3 VAC Eb = 100 Rk = 150 Ω Gm measured
5703	2 of 3	-	12	-	20	Ef = 6.3 VAC Eb = 100 Rk = 150 Ω Ib measured OK 6.75 to 10.1 MA
5703	3 of 3	-	0.1	-	20	Ef = 6.3 VAC Eb = 100 Ec1 = -7.0 Ib cutoff test OK under 0.05 MA
5704	1 of 1	-	14	-	20	Ef = 6.3 VAC Epp = 250 VAC (H-W) Rl = 11,100 Ω Io measured
5718	1 of 1	9000	-	-	10	Ef = 6.3 VAC Eb = 100 Rk = 150 Ω Gm measured
5719	1 of 3	2400	-	-	10	Ef = 6.3 VAC Eb = 100 Rk = 1500 Ω Gm measured
5719	2 of 3	-	1.0	-	10	Ef = 6.3 VAC Eb = 100 Rk = 1500 Ω Ib measured OK 0.5 to 0.9 MA
5719	3 of 3	-	0.1	-	10	Ef = 6.3 VAC Eb = 100 Ec1 = -2.5 Ib cutoff test OK under 0.05 MA
5725	1 of 2	4500	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -1.0 G1-P Gm measured
5725	2 of 2	1100	-	-	20	Ef = 6.3 VAC Eb = 100 Ec3 = -1.0 Ec2 = 100 Ec1 = -1.0 G3-P Gm measured
5726	1 of 1	-	26	-	10	Ef = 6.3 VAC Ebb = 9.0 Rl = 100 Ω Ib measured Dual Test: 1st Diode: pins 1 & 7 used 2nd Diode: pins 2 & 5 used
5727	1 of 3	-	166	-	20	Ef = 6.3 VAC Ebb = 150 Ec2, 1 = 0 Rl = 1450 Ω Ib measured G2 pin 7 used

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
5727	2 of 3	-	-	100	20	Ef = 6.3 VAC Etd measured at 100 MA OK under 10 V G2 pin 5 used
5727	3 of 3	-	24	-	-	Ef = 6.3 VAC Epp = 250 VAC Ec2 = 0 Ec1 = -21 Rl = 10,000 Ω Ib cutoff test OK under 2.4 MA G2 pin 7 used
5744	1 of 2	4500	-	-	10	Ef = 6.3 VAC Eb = 150 Rk = 390 Ω Gm measured
5744	2 of 2	-	0.1	-	10	Ef = 6.3 VAC Eb = 150 Ec1 = -4.0 Ib cutoff test OK under 0.05 MA
5749	1 of 1	5800	-	-	10	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Rk = 70 Ω G1-P Gm measured
5750	1 of 2	500	-	-	20	Ef = 6.3 VAC Eb = 100 Ec4, 2 = 100 Ec3, 1 = -3.1 G3-P Gm measured
5750	2 of 2	9200	-	-	20	Ef = 6.3 VAC Eb = 100 Ec4, 2 = 100 Ec3 = 0 Ec1 = -1.0 G1-G2, G4, Gm measured
5751	1 of 1	1600	-	-	10	Ef = 6.3 VAC (Para.) Eb = 100 Ec1 = -1.0 Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
5763	1 of 2	8800	-	-	50	Ef = 6.0 VAC Eb = 150 V Ec3 = 0 Ec2 = 150 Ec1 = -2.3 G1-P Gm measured G1 pin 9 used
5763	2 of 2	8800	-	-	50	Ef = 6.0 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Ec1 = -2.3 G1-P Gm measured G1 pin 8 used
5783	1 of 4	Instruction Card				
5783	2 of 4	-	0.2	-	-	Leakage test at 50 V
5783	3 of 4	-	-	150	-	Etd measured at 1.5 MA
5783	4 of 4	-	-	150	-	Etd measured at 3.5 MA
5784	1 of 2	4500	-	-	10	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -1.0 G1-P Gm measured
5784	2 of 2	1100	-	-	10	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec3, 1 = -1.0 G3-P Gm measured
5787	1 of 4	Instruction Card				
5787	2 of 4	-	0.2	-	-	Leakage test at 50 V
5787	3 of 4	-	-	200	-	Etd measured at 5 MA
5787	4 of 4	-	-	200	-	Etd measured at 30 MA
5798	1 of 1	4500	-	-	10	Ef = 26.5 VAC Eb = 50 Ec1 = -1.0 Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
5812	1 of 1	-	50	-	-	Ef = 3.0 VAC (Para.) Eb = 150 Ec3 = 0 Ec2 = 150 Ec1 = -9.5 Ib measured

TABLE 2-2. (continued

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
5814A	1 of 1	3400	-	-	10	Ef = 6.3 VAC (Para.) Eb = 150 Ec1 = -3.0 Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
5829	1 of 1	-	14	-	10	Ef = 6.3 VAC Ebb = 100 R1 = 9600 Ω Ib measured Dual Test: 1st Diode: pins 6 & 7 used 2nd Diode: pins 1 & 2 used
5838	1 of 1	-	120	-	50	Ef = 12.6 VAC Epp = 250 VAC (F-W) R1 = 3600 Ω C1 = 4 μf Io measured
5839	1 of 1	-	120	-	50	Ef = 26.5 VAC Epp = 250 VAC (F-W) R1 = 3600 Ω C1 = 4 μf Io measured
5840	1 of 3	7500	-	-	10	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Rk = 150 Ω G1-P Gm measured K pin 8 used
5840	2 of 3	-	10	-	10	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Rk = 150 Ω Ib measured K pin 4 used
5840	3 of 3	-	0.1	-	10	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -9.0 Ib cutoff test OK under 0.05 MA K pin 2 used
5842	1 of 4	32,000	-	-	20	Ef = 6.3 VAC Eb = 150 Rk = 60 Ω Gm measured G pin 8 used
5842	2 of 4	-	34	-	20	Ef = 6.3 VAC Eb = 150 Rk = 60 Ω Ib measured G pin 7 used
5842	3 of 4	-	34	-	20	Ef = 6.3 VAC Eb = 150 Rk = 60 Ω Ib measured G pin 5 used
5842	4 of 4	-	0.2	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -10 Ib cutoff test OK under 0.1 MA G pin 4 used
5844	1 of 3	4300	-	-	20	Ef = 6.3 VAC Eb = 100 Rk = 470 Ω Gm measured Dual Test: 1st Triode: pins 2, 5, 7 used 2nd Triode: pins 1, 6, 7 used
5844	2 of 3	-	8.1	-	20	Ef = 6.3 VAC Ebb = 100 Ec1 = 0 R1 = 11, 100 Ω Ib measured Dual Test: 1st Triode: pins 2, 5, 7 used 2nd Triode: pins 1, 6, 7 used
5844	3 of 3	-	0.2	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -10.0 Ib cutoff test OK under 0.1 MA Dual Test: 1st Triode: pins 2, 5, 7 used 2nd Triode: pins 1, 6, 7 used
5847	1 of 3	17,000	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Rk = 110 Ω G1-P Gm measured
5847	2 of 3	-	20	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Rk = 110 Ω Ib measured OK 8.8 to 18.0 MA
5847	3 of 3	-	0.1	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -10 Ib cutoff test OK under 0.05 MA
5852	1 of 1	-	120	-	50	Ef = 6.3 VAC Epp = 250 VAC (F-W) R1 = 3600 Ω C1 = 4 μf Io measured

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
5854	1 of 1	-	1.28	-	-	Ef = 1.3 VAC Eb = 50 Ec2 = 50 Ec1 = -3.0 Ib measured OK 0.32 to 1.14 MA
5875	1 of 1	-	4.4	-	-	Ef = 1.3 VAC Eb = 100 Ec2 = 100 Ec1 = -0.8 Ib measured
5879	1 of 1	1200	-	-	10	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -2.8 G1-P Gm measured
5881	1 of 1	6700	-	-	70	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -7.0 G1-P Gm measured
5886	1 of 2	-	14	-	-	Ef = 1.2 VAC Shorts Test Only Meter deflection not due to tube
5886	2 of 2	-	0.24	-	-	Ef = 1.2 VAC Eb = 9.0 Ec2 = 9.0 Ec1 = -3.5 Ib measured
5896	1 of 1	-	28	-	10	Ef = 6.3 VAC Ebb = 100 Rl = 5210 Ω Ib measured Dual Test: 1st Diode: pins 5 & 7 used 2nd Diode: pins 1 & 2 used
5899	1 of 3	5700	-	-	10	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Rk = 120 Ω G1-P Gm measured K pin 8 used
5899	2 of 3	-	10	-	10	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Rk = 120 Ω Ib measured K pin 4 used OK 4.5 to 9.2 MA
5899	3 of 3	500	-	-	10	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -14 G1-P Gm cutoff test OK under 75 μmhos K pin 2 used
5902	1 of 3	5300	-	-	50	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Rk = 220 Ω G1-P Gm measured K pin 8 used
5902	2 of 3	-	50	-	50	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Rk = 220 Ω Ib measured OK 23 to 27 MA K pin 4 used
5902	3 of 3	-	0.2	-	50	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -36 Ib cutoff test OK under 0.1 MA K pin 2 used
5903	1 of 1	-	28	-	10	Ef = 26.5 VAC Ebb = 100 Rl = 5210 Ω Ib measured Dual test: 1st Diode: pins 5 & 7 used 2nd Diode: pins 1 & 2 used
5904	1 of 1	6300	-	-	10	Ef = 26.5 VAC Eb = 50 Ec1 = -2.2 Gm measured
5905	1 of 3	3600	-	-	10	Ef = 26.5 VAC Eb = 50 Ec2 = 50 Ec1 = -1.8 G1-P Gm measured K pin 8 used
5905	2 of 3	-	3.2	-	10	Ef = 26.5 VAC Eb = 50 Ec2 = 50 Rk = 550 Ω Ib measured OK 1.6 to 2.9 MA K pin 4 used
5905	3 of 3	-	0.2	-	10	Ef = 26.5 VAC Eb = 50 Ec2 = 50 Ec1 = -4.9 Ib cutoff test OK under 0.1 MA K pin 2 used
5906	1 of 3	6500	-	-	10	Ef = 26.5 VAC Eb = 100 Ec2 = 100 Rk = 150 Ω G1-P Gm measured K pin 2 used

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
5906	2 of 3	-	10	-	10	Ef = 26.5 VAC Eb = 100 Ec2 = 100 Rk = 150 Ω Ib measured OK 5.0 to 9.5 MA K pin 4 used
5906	3 of 3	-	0.1	-	10	Ef = 26.5 VAC Eb = 100 Ec2 = 100 Ec1 = -9.0 Ib cutoff test OK under 0.05 MA K pin 8 used
5907	1 of 3	3600	-	-	10	Ef = 26.5 VAC Eb = 50 Ec2 = 50 Ec1 = -2.5 G1-P Gm measured K pin 8 used
5907	2 of 3	3600	-	-	10	Ef = 26.5 VAC Eb = 50 Ec2 = 50 Ec1 = -2.5 G1-P Gm measured K pin 4 used
5907	3 of 3	-	4.1	-	10	Ef = 26.5 VAC Eb = 50 Ec2 = 50 Ec1 = -2.5 Ib measured OK 1.7 to 3.7 MA K pin 2 used
5908	1 of 2	3000	-	-	10	Ef = 26.5 VAC Eb = 50 Ec3 = 0 Ec2 = 50 Ec1 = -2.8 G1-P Gm measured K pin 8 used
5908	2 of 2	-	4.0	-	10	Ef = 26.5 VAC Eb = 50 Ec2 = 50 Ec3, 1 = -2.4 Ib measured K pin 2 used
5910	1 of 2	-	2.34	-	-	Ef = 1.4 VAC Eb = 100 Ec2 = 100 Ec1 = -1.0 Ib measured OK 0.95 to 2.1 MA Fil pins 1 & 7 used
5910	2 of 2	-	0.1	-	-	Ef = 1.4 VAC Eb = 100 Ec2 = 100 Ec1 = -6.0 Ib measured OK under 0.03 MA Fil pins 5 & 7 used
5915	1 of 4	3000	-	-	20	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -2.0 G1-P Gm measured
5915	2 of 4	-	8.1	-	20	Ef = 6.3 VAC Ebb = 340 Ec3, 1 = 0 Ec2 = 50 Rl = 50,000 Ω Ib measured OK 4.0 to 5.8 MA
5915	3 of 4	-	0.4	-	20	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -13 Ib cutoff test OK below 0.2 MA
5915	4 of 4	-	0.4	-	20	Ef = 6.3 VAC Eb = 50 Ec3 = -5.0 Ec2 = 50 Ec1 = 0 Ib cutoff test OK under 0.2 MA
5920/ E90CC	1 of 3	7600	-	-	10	Ef = 6.3 VAC Eb = 100 Rk = 250 Ω Gm measured Dual Test: 1st Triode: pins 2, 5, 7 used 2nd Triode: pins 1, 6, 7 used
5920/ E90CC	2 of 3	-	8.0	-	10	Ef = 6.3 VAC Ebb = 150 Rl = 20,000 Ω Ec1 = 0 Ib measured Dual Test: 1st Triode: pins 2, 5, 7 used 2nd Triode: pins 1, 6, 7 used
5920/ E90CC	3 of 3	-	0.2	-	10	Ef = 6.3 VAC Eb = 150 Ec1 = -10 Ib measured OK 0 to 0.1 MA Dual Test: 1st Triode: pins 2, 5, 7 used 2nd Triode: pins 1, 6, 7 used
5930	1 of 1	-	66	-	-	Ef = 2.5 VAC Eb = 150 Ec1 = -2.3 Ib measured
5931	1 of 1	-	320	-	-	Ef = 5.0 VAC Epp = 250 VAC (F-W) Rl = 950 Ω Cl = 4 μf Io measured

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
5932	1 of 1	6700	-	-	70	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -7.0 G1-P Gm measured
5933	1 of 1	7500	-	-	100	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -1.5 G1-P Gm measured
5963	1 of 3	3600	-	-	20	Ef = 6.3 VAC (Para.) Eb = 100 Ec1 = -1.0 Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
5963	2 of 3	-	10	-	20	Ef = 6.3 VAC (Para.) Ebb = 100 Ec1 = 0 Rl = 8330 Ω Ib measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
5963	3 of 3	-	0.10	-	20	Ef = 6.3 VAC (Para.) Eb = 150 Ec1 = -15 Ib cutoff test OK under 0.05 MA Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
5964	1 of 3	7600	-	-	20	Ef = 6.3 VAC Eb = 100 Rk = 50 Ω Gm measured Dual Test: 1st Triode: pins 2, 5, 7 used 2nd Triode: pins 1, 6, 7 used
5964	2 of 3	-	6.1	-	20	Ef = 6.3 VAC Ebb = 100 Ec1 = 0 Rl = 11,100 Ω Ib measured OK 3.4 to 5.68 MA Dual Test: 1st Triode: pins 2, 5, 7 used 2nd Triode: pins 1, 6, 7 used
5964	3 of 3	-	0.4	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -10 Ib cutoff test OK under 0.2 MA Dual Test: 1st Triode: pins 2, 5, 7 used 2nd Triode: pins 1, 6, 7 used
5965	1 of 3	8200	-	-	20	Ef = 6.3 VAC (Para.) Eb = 150 Rk = 220 Ω Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
5965	2 of 3	-	14	-	20	Ef = 6.3 VAC (Para.) Ebb = 150 Ec1 = 0 Rl = 7000 Ω Ib measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
5965	3 of 3	-	0.3	-	20	Ef = 6.3 VAC (Para.) Eb = 150 Ec1 = -7.5 Ib cutoff test OK under 0.15 MA Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
5971	1 of 2	-	5.0	-	-	Ef = 1.25 VAC Eb = 100 Ec1 = -1.7 Ib measured G pin 4 used
5971	2 of 2	-	0.1	-	-	Ef = 1.25 VAC Eb = 100 Ec1 = -7.0 Ib measured OK under 0.05 MA G pin 2 used
5977	1 of 2	6600	-	-	10	Ef = 6.3 VAC Eb = 100 Rk = 270 Ω Gm measured
5977	2 of 2	-	0.2	-	10	Ef = 6.3 VAC Eb = 100 Ec1 = -13 Ib cutoff test OK under 0.1 MA

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
5987	1 of 3	2500	-	-	50	Ef = 6.3 VAC Eb = 100 Ec1 = -18 Gm measured P pin 8 used
5987	2 of 3	2500	-	-	50	Ef = 6.3 VAC Eb = 100 Ec1 = -18 Gm measured P pin 4 used
5987	3 of 3	-	12	-	50	Ef = 6.3 VAC Eb = 100 Ec1 = -18 Ib measured P pin 2 used
5992	1 of 2	4900	-	-	10	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -6.0 G1-P Gm measured
5992	2 of 2	-	38	-	10	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -6.0 Ib measured
5993	1 of 1	-	112	-	10	Ef = 6.3 VAC Epp = 250 VAC (F-W) Rl = 4000 Ω Cl = 4 μf Io measured
6000	1 of 2	9400	-	-	70	Ef = 26.5 VAC Eb = 150 Ec2 = 150 Ec1 = -9.0 G1-P Gm measured
6000	2 of 2	-	-	100	70	Ef = 26.5 VAC Etd measured at 240 MA OK under 40 volts
6004	1 of 2	-	190	-	-	Ef = 5.0 VAC Epp = 250 VAC (H-W) Rl = 600 Ω Cl = 4 μf Io measured P: 1st cap used
6004	2 of 2	-	190	-	-	Ef = 5.0 VAC Epp = 250 VAC (H-W) Rl = 600 Ω Cl = 4 μf Io measured P: 2nd cap used
6005	1 of 2	4700	-	-	50	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -4.2 G1-P Gm measured G1 pin 7 used

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
6005	2 of 2	4700	-	-	50	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -4.2 G1-P Gm measured G1 pin 1 used
6007/ DL67	1 of 1	-	0.6	-	-	Ef = 1.20 VAC Eb = 50 Ec2 = 50 Ec1 = -3.8 Ib measured
6021	1 of 2	7600	-	-	20	Ef = 6.3 VAC Eb = 100 Rk = 150 Ω Gm measured Dual Test: 1st Triode: pins 5, 7, 8 used 2nd Triode: pins 1, 2, 4 used
6021	2 of 2	-	0.2	-	20	Ef = 6.3 VAC Eb = 100 Ec1 = -6.5 Ib cutoff test OK under 0.1 MA Dual Test: 1st Triode: pins 5, 7, 8 used 2nd Triode: pins 1, 2, 4 used
6028	1 of 2	6500	-	-	20	Ef = 20.0 VAC Eb = 100 Ec2 = 100 Rk = 100 Ω G1-P Gm measured K pin 7 used
6028	2 of 2	6500	-	-	20	Ef = 20.0 VAC Eb = 100 Ec2 = 100 Rk = 100 Ω G1-P Gm measured K pin 2 used
6029	1 of 1	-	14	-	-	Ef = 1.25 VAC Eb = 100 Ec1 = -5.0 Ib measured
X6030	1 of 2	-	8.0	-	-	Ef = 2.6 VAC Ebb = 300 Rl = 10,000 Ω P pin 5 used Io measured
X6030	2 of 2	-	6.0	-	-	Ef = 2.6 VAC Eb = 50 Io measured P pin 4 used
6050	1 of 1	-	5.0	-	-	Ef = 1.2 VAC Eb = 100 Ec1 = -3.0 Ib measured

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
6051	1 of 1	1500	-	-	-	Ef = 1.25 VDC Eb = 50 Ec2 = 50 Ec1 = -6.8 to Fil center G1-P Gm measured
6064	1 of 1	8200	-	-	20	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 160 Ω G1-P Gm measured
6065/ EF92	1 of 1	2900	-	-	20	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Ec1 = -1.0 G1-P Gm measured
6072	1 of 2	2200	-	-	10	Ef = 6.3 VAC (Para.) Eb = 150 Ec1 = -2.0 Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
6072	2 of 2	-	0.2	-	10	Ef = 6.3 VAC (Para.) Eb = 150 Ec1 = -6.8 Ib measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
6073	1 of 1	Instruction Card				
6074	1 of 1	Instruction Card				
6080	1 of 3	8300	-	-	100	Ef = 6.3 VAC Eb = 150 Rk = 370 Ω Gm measured Dual Test: 1st Triode: pins 4, 5, 6 used 2nd Triode: pins 1, 2, 3 used
6080	2 of 3	-	-	100	100	Ef = 6.3 VAC Etd measured at 100 MA OK under 50 V Dual Test: 1st Triode: pins 4, 5, 6 used 2nd Triode: pins 1, 2, 3 used
6080	3 of 3	-	20	-	100	Ef = 6.3 VAC Eb = 100 Ec1 = -60 Ib cutoff test OK under 10 MA Dual Test: 1st Triode: pins 4, 5, 6 used 2nd Triode: pins 1, 2, 3 used
6082	1 of 3	8300	-	-	100	Ef = 26.5 VAC Eb = 150 Rk = 370 Ω Gm measured Dual Test: 1st Triode: pins 4, 5, 6 used 2nd Triode: pins 1, 2, 3 used
6082	2 of 3	-	-	100	100	Ef = 26.5 VAC Etd measured at 100 MA OK under 50 V Dual Test: 1st Triode: pins 4, 5, 6 used 2nd Triode: pins 1, 2, 3 used
6082	3 of 3	-	20	-	100	Ef = 26.5 VAC Eb = 100 Ec1 = -60 Ib cutoff test OK under 10 MA Dual Test: 1st Triode: pins 4, 5, 6 used 2nd Triode: pins 1, 2, 3 used
6084/ E80F	1 of 1	2400	-	-	10	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Rk = 550 Ω G1-P Gm measured
6085/ E80CC	1 of 1	3500	-	-	10	Ef = 6.3 VAC (Para.) Eb = 150 Ec1 = -2.0 Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
6087	1 of 1	-	200	-	-	Ef = 5.0 VAC Epp = 250 VAC (F-W) Rl = 1650 Ω Cl = 4 μf Io measured

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
6088	1 of 1	-	0.8	-	-	Ef = 1.2 VAC Eb = 50 Ec2 = 50 Ec1 = -2.2 Ib measured
6094	1 of 2	4700	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -4.2 G1-P Gm measured P pin 9 used G1 pin 6 used G2 pin 7 used
6094	2 of 2	4700	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -4.2 G1-P Gm measured P pin 4 used G1 pin 1 used G2 pin 2 used
6095	1 of 2	4700	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -4.2 G1-P Gm measured G pin 7 used
6095	2 of 2	4700	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -4.2 G1-P Gm measured G pin 1 used
6098	1 of 1	6700	-	-	70	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -10 G1-P Gm measured
6099	1 of 3	8000	-	-	10	Ef = 6.3 VAC Eb = 100 Rk = 50 Ω Gm measured Dual Test: 1st Triode: pins 1, 6, 7 used 2nd Triode: pins 2, 5, 7 used
6099	2 of 3	-	12	-	10	Ef = 6.3 VAC Eb = 100 Rk = 50 Ω Ib measured Dual Test: 1st Triode: pins 1, 6, 7 used 2nd Triode: pins 2, 5, 7 used
6099	3 of 3	-	0.4	-	10	Ef = 6.3 VAC Eb = 150 Ec1 = -8.0 Ib measured OK under 0.2 MA Dual Test: 1st Triode: pins 1, 6, 7 used 2nd Triode: pins 2, 5, 7 used
6100	1 of 3	3800	-	-	10	Ef = 6.3 VAC Eb = 150 Ec1 = -3.0 Gm measured P pin 5 used
6100	2 of 3	-	16	-	10	Ef = 6.3 VAC Eb = 150 Ec1 = -3.0 Ib measured OK 6 to 14.5 MA P pin 1 used
6100	3 of 3	-	0.1	-	10	Ef = 6.3 VAC Eb = 150 Ec1 = -15 Ib measured OK under 0.02 MA P pin 1 used
6101	1 of 1	7600	-	-	10	Ef = 6.3 VAC Eb = 100 Rk = 50 Ω Gm measured Dual Test: 1st Triode: pins 2, 5, 7 used 2nd Triode: pins 1, 6, 7 used
6106	1 of 1	-	200	-	-	Ef = 5.0 VAC Epp = 250 VAC (F-W) Rl = 1500 Ω Cl = 4 μf Io measured
6110	1 of 1	-	10	-	20	Ef = 6.3 VAC Ebb = 9.0 Rl = 253 Ω Ib measured Dual Test: 1st Diode: pins 5 & 7 used 2nd Diode: pins 1 & 2 used
6111	1 of 1	7500	-	-	10	Ef = 6.3 VAC Eb = 100 Rk = 220 Ω Gm measured Dual Test: 1st Triode: pins 5, 7, 8 used 2nd Triode: pins 1, 2, 4 used

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
6112	1 of 1	2400	-	-	10	Ef = 6.3 VAC Eb = 100 Rk = 1500 Ω Gm measured Dual Test: 1st Triode: pins 5, 7, 8 used 2nd Triode: pins 1, 2, 4 used
6113	1 of 1	1400	-	-	20	Ef = 6.3 VAC Eb = 100 Ec1 = -1.0 Gm measured Dual Test: 1st Triode: pins 4, 5, 6 used 2nd Triode: pins 1, 2, 3 used
6134	1 of 1	11,300	-	-	20	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 160 Ω G1-P Gm measured
6135	1 of 2	3400	-	-	10	Ef = 6.3 VAC Eb = 150 Ec1 = -3.0 Gm measured P pin 5 used
6135	2 of 2	3400	-	-	10	Ef = 6.3 VAC Eb = 150 Ec1 = -3.0 Gm measured P pin 1 used
6136	1 of 1	4900	-	-	10	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Rk = 150 Ω G1-P Gm measured
6137	1 of 1	3000	-	-	10	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -1.0 G1-P Gm measured
6146	1 of 3	9500	-	-	100	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -15 G1-P Gm measured K pin 1 used
6146	2 of 3	9500	-	-	100	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -15 G1-P Gm measured K pin 4 used
6146	3 of 3	9500	-	-	100	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -15 G1-P Gm measured K pin 6 used
6147	1 of 1	-	8.0	-	-	Ef = 1.3 VDC (Para.) Eb = 100 Ec2 = 100 Ec1 = -5.0 Ib measured OK 3.2 to 7.5 MA
6148	1 of 1	6500	-	-	10	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec3 = 0 Rk = 100 Ω G1-P Gm measured
6159	1 of 3	9500	-	-	100	Ef = 26.5 VAC Eb = 150 Ec2 = 150 Ec1 = -15 G1-P Gm measured K pin 1 used
6159	2 of 3	9500	-	-	100	Ef = 26.5 VAC Eb = 150 Ec2 = 150 Ec1 = -15 G1-P Gm measured K pin 4 used
6159	3 of 3	9500	-	-	100	Ef = 26.5 VAC Eb = 150 Ec2 = 150 Ec1 = -15 G1-P Gm measured K pin 6 used
6184	1 of 1	-	24	-	10	Ef = 6.3 VAC Eb = 100 Rl = 5800 Ib measured Dual Test: 1st Diode: pins 5 & 7 used 2nd Diode: pins 2 & 4 used
6186	1 of 3	7000	-	-	10	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Rk = 200 Ω G1-P Gm measured K pin 7 used
6186	2 of 3	-	10	-	10	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Rk = 200 Ω Ib measured OK 5.2 to 8.8 MA K pin 2 used

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
6186	3 of 3	-	0.2	-	10	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -10 Ib cutoff test OK under 0.1 MA K pin 2 used
6188	1 of 2	1900	-	-	10	Ef = 6.3 VAC Eb = 150 Ec1 = -1.0 Gm measured Dual Test: 1st Triode: pins 4, 5, 6 used 2nd Triode: pins 1, 2, 3 used
6188	2 of 2	-	0.4	-	10	Ef = 6.3 VAC Eb = 150 Ec1 = -2.8 Ib cutoff test OK under 0.2 MA Dual Test: 1st Triode: pins 4, 5, 6 used 2nd Triode: pins 1, 2, 3 used
6189	1 of 3	3800	-	-	10	Ef = 6.3 VAC (Para.) Eb = 150 Ec1 = -3.0 Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
6189	2 of 3	-	16	-	10	Ef = 6.3 VAC Eb = 150 Ec1 = -3.0 Ib measured OK 6 to 14.5 MA Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
6189	3 of 3	-	0.1	-	10	Ef = 6.3 VAC (Para.) Eb = 150 Ec1 = -15 Ib cutoff test OK under 0.02 MA Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
6197	1 of 3	14,000	-	-	50	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -3.0 G1-P Gm measured G1 pin 9 used G2 pin 8 used
6197	2 of 3	-	48	-	50	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = 0 Ib measured G1 pin 2 used G2 pin 3 used
6197	3 of 3	-	0.2	-	50	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -12 Ib cutoff test OK under 0.1 MA G1 pin 2 used G2 pin 3 used
6201	1 of 1	5000	-	-	10	Ef = 6.3 VAC (Para.) Eb = 100 Rk = 270 Ω Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
6202	1 of 1	-	80	-	20	Ef = 6.3 VAC Epp = 250 VAC (F-W) Rl = 5700 Ω Cl = 4 μf Io measured
6203	1 of 1	-	112	-	20	Ef = 6.3 VAC Epp = 250 VAC (F-W) Rl = 3900 Ω Cl = 4 μf Io measured
6205	1 of 3	7500	-	-	10	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Rk = 150 Ω G1-P Gm measured K pin 8 used
6205	2 of 3	-	10	-	10	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Rk = 150 Ω Ib measured OK 5.5 to 9.5 MA K pin 2 used
6205	3 of 3	-	0.1	-	10	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -9.0 Ib cutoff test OK under 0.05 MA K pin 2 used

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
6206	1 of 3	5700	-	-	10	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Rk = 120 Ω G1-P Gm measured K pin 8 used
6206	2 of 3	-	10	-	10	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Rk = 120 Ω Ib measured OK 4.5 to 9.2 MA K pin 2 used
6206	3 of 3	500	-	-	10	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -14 G1-P Gm cutoff test OK under 75 μmhos K pin 2 used
6211	1 of 3	4500	-	-	20	Ef = 6.3 VAC (Para.) Eb = 100 Rk = 470 Ω Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
6211	2 of 3	-	8.1	-	20	Ef = 6.3 VAC (Para.) Ebb = 100 Ec1 = 0 Rl = 11,100 Ω Ib measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
6211	3 of 3	-	0.2	-	20	Ef = 6.3 VAC (Para.) Eb = 150 Ec1 = -10 Ib cutoff test OK under 0.1 MA Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
6216	1 of 2	15,700	-	-	100	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -3.0 G1-P Gm measured P pin 6 used K pin 8 used
6216	2 of 2	-	100	-	100	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -3.0 Ib measured OK 44 to 95 MA P pin 1 used K pin 3 used
6221	1 of 2	9000	-	-	10	Ef = 6.3 VAC Eb = 100 Rk = 150 Ω Gm measured P pin 8 used
6221	2 of 2	-	12	-	10	Ef = 6.3 VAC Eb = 100 Rk = 150 Ω Ib measured OK 5.0 to 11.0 MA P pin 4 used
6222	1 of 2	2400	-	-	10	Ef = 6.3 VAC Eb = 100 Rk = 1500 Ω Gm measured P pin 8 used
6222	2 of 2	-	0.1	-	10	Ef = 6.3 VAC Eb = 100 Ec1 = -2.5 Ib measured OK under 0.05 MA P pin 4 used
6223	1 of 3	7500	-	-	10	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Rk = 150 Ω G1-P Gm measured K pin 8 used
6223	2 of 3	-	10	-	10	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Rk = 150 Ω Ib measured OK 5 to 9.5 MA K pin 4 used
6223	3 of 3	-	0.1	-	10	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -9.0 Ib measured OK under 0.05 MA K pin 2 used
6225	1 of 3	6000	-	-	10	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Rk = 120 Ω G1-P Gm measured K pin 8 used

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
6225	2 of 3	6000	-	-	10	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Rk = 120 Ω G1-P Gm measured K pin 4 used
6225	3 of 3	-	10	-	10	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Rk = 120 Ω Ib measured K pin 2 used
6227/ E80L	1 of 1	11,300	-	-	50	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 70 Ω G1-P Gm measured
6245	1 of 2	6500	-	-	10	Ef = 6.3 VAC Eb = 120 Ec3 = 0 Ec2 = 120 Rk = 200 Ω G1-P Gm measured
6245	2 of 2	-	0.1	-	10	Ef = 6.3 VAC Eb = 120 Ec3 = 0 Ec2 = 120 Ec1 = -9.0 Ib measured OK under 0.05 MA
6247	1 of 2	2800	-	-	10	Ef = 6.3 VAC Eb = 150 Rk = 500 Ω Gm measured G pin 1 used P pin 8 used
6247	2 of 2	-	2.46	-	10	Ef = 6.3 VAC Eb = 150 Rk = 500 Ω Ib measured G pin 2 used P pin 4 used
6265	1 of 2	6200	-	-	10	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 100 Ω G1-P Gm measured OK 3100 μmhos to 5500 μmhos
6265	2 of 2	-	0.1	-	10	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Ec1 = -8.5 Ib cutoff test OK under 0.035 MA

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
6267/ EF86	1 of 1	2500	-	-	20	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Ec1 = -2.1 G1-P Gm measured
6286	1 of 1	-	5.0	-	-	Ef = 1.2 VAC Eb = 100 Ec1 = -5.7 Ib measured
6293	1 of 3	9200	-	-	100	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Rk = 180 Ω G1-P Gm measured K pin 6 used
6293	2 of 3	-	100	-	100	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -19 Ib measured K pin 4 used
6293	3 of 3	-	2.0	-	100	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -50 Ib cutoff test OK under 1 MA K pin 1 used
6308	1 of 4	Instruction Card				
6308	2 of 4	-	0.2	-	-	Leakage test at 50 volts
6308	3 of 4	-	-	150	-	Etd measured at 1.5 MA
6308	4 of 4	-	-	150	-	Etd measured at 3.5 MA
6350	1 of 3	5800	-	-	20	Ef = 6.3 VAC (Para.) Eb = 150 Ec1 = -5.0 Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
6350	2 of 3	-	36	-	20	Ef = 6.3 VAC (Para.) Eb = 100 Ec1 = 0 Ib measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
6350	3 of 3	-	0.2	-	20	Ef = 6.3 VAC (Para.) Eb = 150 Ec1 = -12.0 Ib cutoff test OK under 0.1 MA Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
6354/ 150B2	1 of 3	Instruction Card				
6354/ 150B2	2 of 3	-	-	300	-	Etd measured at 5 MA
6354/ 150B2	3 of 3	-	-	300	-	Etd measured at 15 MA
6360	1 of 2	4100	-	-	50	Ef = 6.3 VAC (Para.) Eb = 150 Ec2 = 150 Ec1 = -9.0 G1-P Gm measured Pins 1, 2, 6, 7 used
6360	2 of 2	4100	-	-	50	Ef = 6.3 VAC (Para.) Eb = 150 Ec2 = 150 Ec1 = -9.0 G1-P Gm measured Pins 2, 3, 7, 8 used
6374/ EY84	1 of 1	-	240	-	150	Ef = 6.3 VAC Epp = 250 VAC (H-W) Rl = 700 Ω Cl = 4 μf Io measured
6384	1 of 1	8200	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -10 G1-P Gm measured
6385	1 of 1	6300	-	-	10	Ef = 6.3 VAC Eb = 150 Ec1 = -2.0 Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 2, 3, 4 used
6386	1 of 1	5600	-	-	10	Ef = 6.3 VAC Eb = 100 Rk = 200 Ω Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 2, 3, 4 used
6395	1 of 2	-	2.34	-	-	Ef = 1.25 VAC Eb = 100 Ec2 = 100 Ec1 = -1.0 Ib measured OK .95 to 2.1 MA Fil pins 1 & 7 used
6395	2 of 2	-	0.1	-	-	Ef = 1.25 VAC Eb = 100 Ec2 = 100 Ec1 = -6.0 Ib measured OK under 0.03 MA Fil pins 5 & 7 used
6397	1 of 1	2400	-	-	-	Ef = 1.2 VAC (Para.) Eb = 100 Ec2 = 100 Ec1 = -5.0 G1-P Gm measured
6414	1 of 3	7000	-	-	10	Ef = 6.3 VAC (Para.) Eb = 150 Ec1 = -1.4 Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
6414	2 of 3	-	14.1	-	10	Ef = 6.3 VAC (Para.) Eb = 100 Ec1 = 0 Ib measured OK 7.05 to 12.7 MA Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
6414	3 of 3	-	0.3	-	10	Ef = 6.3 VAC (Para.) Eb = 150 Ec1 = -7.5 Ib cutoff test OK under 0.15 MA Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
6418	1 of 2	-	-	-	-	Ef = 1.2 VAC Shorts test only
6418	2 of 2	-	0.34	-	-	Ef = 1.2 VAC Ebb = 50 VAC Rl = 100 K Ω G2 connected to P Ec1 = -2.7 Ib, IG2 measured
6463	1 of 3	9400	-	-	10	Ef = 6.3 VAC (Para.) Eb = 150 Rk = 130 Ω Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
6463	2 of 3	-	40	-	10	Ef = 6.3 VAC (Para.) Eb = 100 Ec1 = 0 Ib measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
6463	3 of 3	-	2.0	-	10	Ef = 6.3 VAC (Para.) Eb = 150 Ec1 = -11 Ib cutoff test OK under 0.1 MA Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
6485	1 of 1	11,300	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Rk = 160 Ω G1-P Gm measured
6526	1 of 1	2400	-	-	-	Ef = 1.25 VDC Eb = 110 Ec2 = 110 Ec1 = -6.0 G1-P Gm measured
6533	1 of 3	2400	-	-	10	Ef = 6.3 VAC Eb = 100 Rk = 1000 Ω Gm measured P pin 8 used G pin 2 used
6533	2 of 3	2400	-	-	10	Ef = 6.3 VAC Eb = 100 Rk = 1000 Ω Gm measured P pin 4 used G pin 3 used
6533	3 of 3	-	1.4	-	10	Ef = 6.3 VAC Eb = 100 Rk = 1000 Ω Ib measured P pin 1 used G pin 3 used
6540	1 of 1	6300	-	-	10	Ef = 6.3 VAC Eb = 120 Ec2 = 120 Rk = 200 Ω G1-P Gm measured
6542	1 of 4	Instruction Card				
6542	2 of 4	-	0.2	-	-	Leakage test at 50 volts
6542	3 of 4	-	-	300	-	Etd measured at 5 MA
6542	4 of 4	-	-	300	-	Etd measured at 25 MA
6550	1 of 1	12,600	-	-	100	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -6.0 G1-P Gm measured
6626	1 of 1	Instruction Card				
6627	1 of 1	Instruction Card				
6660	1 of 1	5400	-	-	20	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Rk = 70 Ω G1-P Gm measured
6661	1 of 1	5700	-	-	20	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 100 Ω G1-P Gm measured
6662	1 of 1	4600	-	-	20	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Rk = 80 Ω G1-P Gm measured
6663	1 of 1	-	26	-	10	Ef = 6.3 VAC Ebb = 9.0 Rl = 100 Ω Diode Ib measured Dual Test: 1st Diode: pins 1 & 7 used 2nd Diode: pins 2 & 5 used

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
6669	1 of 2	4700	-	-	50	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -4.2 G1-P Gm measured G pin 7 used
6669	2 of 2	4700	-	-	50	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -4.2 G1-P Gm measured G pin 1 used
6677	1 of 2	13,600	-	-	50	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -3.0 G1-P Gm measured G1 pin 9 used G2 pin 8 used
6677	2 of 2	10,900	-	-	50	Ef = 5.0 VAC Eb = 150 Ec2 = 150 Ec1 = -3.0 G1-P Gm measured G1 pin 2 used G2 pin 3 used
6678	1 of 4	5000	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Rk = 70 Ω Pent. G1-P Gm measured
6678	2 of 4	3900	-	-	20	Ef = 5.0 VAC Eb = 100 Ec2 = 100 Rk = 70 Ω Pent. G1-P Gm measured
6678	3 of 4	10,000	-	-	20	Ef = 6.3 VAC Eb = 150 Rk = 60 Ω Triode Gm measured
6678	4 of 4	8000	-	-	20	Ef = 5.0 VAC Eb = 150 Rk = 60 Ω Triode Gm measured
6679	1 of 2	7300	-	-	20	Ef = 6.3 VAC (Para.) Eb = 150 Rk = 150 Ω Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
6679	2 of 2	5900	-	-	20	Ef = 10.0 VAC Eb = 150 Rk = 150 Ω Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
6680	1 of 2	3900	-	-	20	Ef = 6.3 VAC (Para.) Eb = 150 Ec1 = -2.0 Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
6680	2 of 2	3100	-	-	20	Ef = 10.0 VAC Eb = 150 Ec1 = -2.0 Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
6681	1 of 1	2200	-	-	10	Ef = 6.3 VAC (Para.) Eb = 150 Ec1 = -1.0 Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
6686/ E81L	1 of 2	15,600	-	-	20	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 70 Ω G1-P Gm measured Internal shield pin 6 used
6686/ E81L	2 of 2	-	24.1	-	20	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 70 Ω Ib measured Internal shield pin 1 used
6687/ E91H	1 of 3	-	8.1	-	20	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 50 Ec1 = 0 Ib measured

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
6687/ E91H	2 of 3	-	0.4	-	20	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -13 Ib measured OK under 0.2 MA
6687/ E91H	3 of 3	-	0.4	-	20	Ef = 6.3 VAC Eb = 50 Ec3 = -5.0 Ec2 = 50 Ec1 = 0 Ib measured OK under 0.2 MA
6688/ E180F	1 of 2	22,000	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Rk = 80 Ω G1-P Gm measured K pin 3 used
6688/ E180F	2 of 2	-	13	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Rk = 80 Ω Ib measured K pin 1 used
6689/ E83F	1 of 1	9400	-	-	20	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Rk = 330 Ω G1-P Gm measured
6754	1 of 1	-	144	-	100	Ef = 6.3 VAC Epp = 250 VAC (F-W) Rl = 1700 Ω Cl = 4 μf Diode Ib measured Dual Test: 1st Diode: pins 9 & 7 used 2nd Diode: pins 1 & 3 used
6761	1 of 2	15,000	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Rk = 120 Ω G1-P Gm measured P pin 6 used K pin 8 used
6761	2 of 2	-	88	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Rk = 120 Ω Ib measured P pin 1 used K pin 3 used
6788	1 of 3	1400	-	-	10	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Rk = 1500 Ω G1-P Gm measured K pin 8 used
6788	2 of 3	-	1.0	-	10	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Rk = 1500 Ω Ib measured K pin 4 used
6788	3 of 3	-	0.10	-	10	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -4.0 Ib cutoff test OK under 0.05 MA K pin 2 used
6814	1 of 3	7500	-	-	10	Ef = 6.3 VAC Eb = 100 Rk = 150 Ω Gm measured
6814	2 of 3	-	26	-	10	Ef = 6.3 VAC Ebb = 150 Rl = 4300 Ω Ec1 = 0 Ib measured
6814	3 of 3	-	0.2	-	10	Ef = 6.3 VAC Eb = 150 Ec1 = -10 Ib measured OK under 0.1 MA
6829	1 of 3	9600	-	-	10	Ef = 6.3 VAC (Para.) Eb = 150 Rk = 220 Ω G1-P Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
6829	2 of 3	-	22	-	10	Ef = 6.3 VAC (Para.) Eb = 100 Ec1 = 0 Ib measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
6829	3 of 3	-	0.3	-	10	Ef = 6.3 VAC (Para.) Eb = 150 Ec1 = -7.5 Ib cutoff test OK under 0.15 MA Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
6832	1 of 3	1400	-	-	10	Ef = 6.3 VAC Eb = 100 Rk = 3000 Ω Gm measured Dual Test: 1st Triode: pins 5, 7, 8 used 2nd Triode: pins 1, 2, 4 used
6832	2 of 3	-	1.0	-	10	Ef = 6.3 VAC Eb = 100 Rk = 3000 Ω Ib measured Dual Test: 1st Triode: pins 5, 7, 8 used 2nd Triode: pins 1, 2, 4 used
6832	3 of 3	-	0.2	-	10	Ef = 6.3 VAC Eb = 100 Ec1 = -4.5 Ib cutoff test OK under 0. 1 MA Dual Test: 1st Triode: pins 5, 7, 8 used 2nd Triode: pins 1, 2, 4 used
6877	1 of 3	10,400	-	-	10	Ef = 6.3 VAC Eb = 100 Ec1 = -12 Gm measured Pins 6, 8, 9 used
6877	2 of 3	-	100	-	10	Ef = 6.3 VAC Eb = 100 Ec1 = -12 Ib measured OK 50 to 90 MA Pins 1, 4, 8 used
6877	3 of 3	-	4	-	10	Ef = 6.3 VAC Eb = 100 Ec1 = -100 Ib measured OK under 2 MA Pins 1, 4, 8 used
6883	1 of 3	9500	-	-	100	Ef = 12.6 VAC Eb = 150 Ec2 = 150 Ec1 = -15 G1-P Gm measured K pin 1 used
6883	2 of 3	9500	-	-	100	Ef = 12.6 VAC Eb = 150 Ec2 = 150 Ec1 = -15 G1-P Gm measured K pin 4 used
6883	3 of 3	9500	-	-	100	Ef = 12.6 VAC Eb = 150 Ec2 = 150 Ec1 = -15 G1-P Gm measured K pin 6 used
6887	1 of 2	-	4.8	-	20	Ef = 6.3 VAC Ebb = 1.6 Rl = 160 Ω Ib measured Pins 1 & 7 used
6887	2 of 2	-	4.8	-	20	Ef = 6.3 VAC Ebb = 1.6 Rl = 160 Ω Ib measured Pins 2 & 5 used
6888	1 of 3	-	46	-	50	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = 0 Ib measured
6888	2 of 3	-	0.1	-	50	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -18 Ib measured OK under 0.05 MA
6888	3 of 3	-	4.0	-	50	Ef = 6.3 VAC Eb = 100 Ec3 = -8.4 Ec2 = 100 Ec1 = 0 Ib measured OK under 2 MA
6900	1 of 2	15,000	-	-	20	Ef = 6.3 VAC (Para.) Eb = 120 Ec1 = -2.0 Gm measured Dual Test: 1st Triode: pins 6, 7, 9 used 2nd Triode: pins 1, 2, 3 used
6900	2 of 2	-	52	-	20	Ef = 6.3 VAC (Para.) Eb = 120 Ec1 = -2.0 Ib measured OK 22 to 47 MA Dual Test: 1st Triode: pins 6, 7, 9 used 2nd Triode: pins 1, 2, 3 used

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
6922/ E88CC	1 of 3	15,700	-	-	20	Ef = 6.3 VAC Eb = 100 Rk = 80 Ω Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
6922/ E88CC	2 of 3	-	12	-	20	Ef = 6.3 VAC Ebb = 50 Ec1 = 0 Rl = 1390 Ω Ib measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
6922/ E88CC	3 of 3	-	0.2	-	200	Ef = 6.3 VAC Eb = 150 Ec1 = -8.5 Ib cutoff test OK under 0.1 MA Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
6939	1 of 2	13,200	-	-	50	Ef = 6.3 VAC (Para.) Eb = 150 Ec2 = 150 Ec1 = -2.0 G1-P Gm measured Pins 1, 2, 6, 7 used
6939	2 of 2	13,200	-	-	50	Ef = 6.3 VAC (Para.) Eb = 150 Ec2 = 150 Ec1 = -2.0 G1-P Gm measured Pins 2, 3, 7, 8 used
6943	1 of 2	4800	-	-	10	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Rk = 150 Ω G1-P Gm measured K pin 8 used
6943	2 of 2	-	0.2	-	10	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -7.5 Ib measured OK under 0.1 MA K pin 2 used
6947	1 of 1	5000	-	-	10	Ef = 6.3 VAC Eb = 150 Rk = 270 Ω Gm measured Dual Test: 1st Triode: pins 5, 7, 8 used 2nd Triode: pins 1, 2, 4 used
6948	1 of 1	2000	-	-	10	Ef = 6.3 VAC Eb = 100 Rk = 1500 Ω Gm measured Dual Test: 1st Triode: pins 5, 7, 8 used 2nd Triode: pins 1, 2, 4 used
6973	1 of 2	6000	-	-	50	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -5.0 G1-P Gm measured Pins 6, 7, 8, 9 used
6973	2 of 2	6000	-	-	50	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -5.0 G1-P Gm measured Pins 1, 3, 7, 9 used
6977	1 of 2	-	0.74	-	-	Ef = 1.0 VAC Eb = 50 Ec1 = 0 Ib measured Phosphor glows
6977	2 of 2	-	0.1	-	-	Ef = 1.0 VAC Eb = 50 Ec1 = -3.0 Ib measured OK under 0.05 MA Phosphor does not glow
7025	1 of 1	1600	-	-	10	Ef = 6.3 VAC (Para.) Eb = 100 Ec1 = -1.0 Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
7027	1 of 2	7500	-	-	100	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Rk = 110 Ω G1-P Gm measured Pins 3, 4, 5, 8 used

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
7027	2 of 2	-	68	-	100	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Rk = 110 Ω Ib measured Pins 1, 3, 6, 8 used
7036	1 of 4	3000	-	-	20	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -2.0 G1-P Gm measured
7036	2 of 4	-	8.1	-	20	Ef = 6.3 VAC Ebb = 340 Ec3 = 0 Ec2 = 50 Ec1 = 0 Rl = 50,000 Ω Ib measured OK 4.0 to 5.8 MA
7036	3 of 4	-	0.4	-	20	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -13 Ib cutoff test OK under 0.2 MA
7036	4 of 4	-	0.4	-	20	Ef = 6.3 VAC Eb = 50 Ec3 = -5.0 Ec2 = 50 Ec1 = 0 Ib cutoff test OK under 0.2 MA
7044	1 of 3	12,600	-	-	50	Ef = 6.3 VAC (Para.) Eb = 100 Ec1 = -1.3 Gm measured Dual Test: 1st Triode: pins 6, 7, 9 used 2nd Triode: pins 1, 2, 3 used
7044	2 of 3	-	64	-	50	Ef = 6.3 VAC (Para.) Eb = 100 Ec1 = 0 Ib measured Dual Test: 1st Triode: pins 6, 7, 9 used 2nd Triode: pins 1, 2, 3 used
7044	3 of 3	-	0.4	-	50	Ef = 6.3 VAC (Para.) Eb = 150 Ec1 = -14 Ib cutoff test OK under 0.2 MA Dual Test 1st Triode: pins 6, 7, 9 used 2nd Triode: pins 1, 2, 3 used
7054	1 of 1	14,500	-	-	20	Ef = 13.5 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 100 Ω G1-P Gm measured G3 pin 3 used
7055	1 of 1	-	26	-	10	Ef = 12.6 VAC Ebb = 9.0 Rl = 100 Ω Diode Ib measured Dual Test: 1st Diode: pins 1 & 7 used 2nd Diode: pins 2 & 5 used
7056	1 of 1	7600	-	-	20	Ef = 13.5 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 180 Ω G1-P Gm measured
7057	1 of 1	8600	-	-	20	Ef = 13.5 VAC Eb = 150 Rk = 220 Ω Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
7058	1 of 1	1600	-	-	20	Ef = 13.5 VAC Eb = 100 Ec1 = -1.0 Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
7059	1 of 2	5700	-	-	10	Ef = 13.5 VAC Eb = 100 Ec2 = 100 Rk = 70 Ω Pent. G1-P Gm measured
7059	2 of 2	10,700	-	-	10	Ef = 13.5 VAC Eb = 150 Rk = 60 Ω Triode Gm measured

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
7060	1 of 2	8800	-	-	20	Ef = 13.5 VAC Eb = 100 Ec2 = 100 Rk = 60 Ω Pent. G1-P Gm measured
7060	2 of 2	6200	-	-	20	Ef = 13.5 VAC Eb = 150 Rk = 150 Triode Gm measured
7061	1 of 2	4700	-	-	50	Ef = 13.5 VAC Eb = 150 Ec2 = 150 Ec1 = -4.2 G1-P Gm measured Pins 1, 3, 7, 9 used
7061	2 of 2	-	28	-	50	Ef = 13.5 VAC Eb = 150 Ec2 = 150 Ec1 = -7.6 Ib measured Pins 6, 7, 8, 9 used
7062/ E180CC	1 of 3	7900	-	-	20	Ef = 6.3 VAC (Para.) Eb = 150 Ec1 = -1.9 Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
7062/ E180CC	2 of 3	-	22	-	20	Ef = 6.3 VAC (Para.) Eb = 100 Ec1 = 0 Ib measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
7062/ E180CC	3 of 3	-	0.3	-	20	Ef = 6.3 VAC (Para.) Eb = 150 Ec1 = -7.5 Ib measured OK under 0.15 MA Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
7119/ E182CC	1 of 3	18,900	-	-	20	Ef = 6.3 VAC (Para.) Eb = 120 Ec1 = -2.0 Gm measured Dual Test: 1st Triode: pins 6, 7, 9 used 2nd Triode: pins 1, 2, 3 used
7119/ E182CC	2 of 3	-	64	-	20	Ef = 6.3 VAC (Para.) Eb = 90 Ec1 = 0 Ib measured Dual Test: 1st Triode: pins 6, 7, 9 used 2nd Triode: pins 1, 2, 3 used
7119/ E182CC	3 of 3	-	0.4	-	20	Ef = 6.3 VAC (Para.) Eb = 150 Ec1 = -14 Ib measured OK under 0.2 MA Dual Test: 1st Triode: pins 6, 7, 9 used 2nd Triode: pins 1, 2, 3 used
7137	1 of 3	11,700	-	-	20	Ef = 6.3 VAC Eb = 150 Rk = 100 Ω Gm measured OK 5300 to 10,500 μmhos G pin 6 used
7137	2 of 3	-	20.1	-	20	Ef = 6.3 VAC Eb = 150 Rk = 100 Ω Ib measured OK 8.0 to 18.0 MA G pin 5 used
7137	3 of 3	-	0.1	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -15 Ib measured OK under 0.04 MA G pin 1 used
7167	1 of 2	10,000	-	-	20	Ef = 13.5 VAC Eb = 100 Ec2 = 100 Ec1 = -1.4 G1-P Gm measured K pin 2 used
7167	2 of 2	10,000	-	-	20	Ef = 13.5 VAC Eb = 100 Ec2 = 100 Ec1 = -1.4 G1-P Gm measured K pin 7 used

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
7189	1 of 1	12,600	-	-	50	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -3.5 G1-P Gm measured
7193	1 of 2	Instruction Card				
7193	2 of 2	3800	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -4.0 Gm measured
7199	1 of 2	8800	-	-	10	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Rk = 70 Ω Pent. G1-P Gm measured
7199	2 of 2	2600	-	-	10	Ef = 6.3 VAC Eb = 150 Ec1 = -5.5 Triode Gm measured
7247	1 of 2	1600	-	-	20	Ef = 6.3 VAC (Para.) Eb = 100 Ec1 = -1.0 Gm measured Pins 6, 7, 8 used
7247	2 of 2	3800	-	-	20	Ef = 6.3 VAC (Para.) Eb = 150 Ec1 = -3.0 Gm measured Pins 1, 2, 3 used
7258	1 of 2	7600	-	-	20	Ef = 13.5 VAC Eb = 150 Ec2 = 150 Rk = 180 Ω Pent. G1-P Gm measured
7258	2 of 2	5700	-	-	20	Ef = 13.5 VAC Eb = 150 Ec1 = -3.0 Triode Gm measured
7308/ E188CC	1 of 2	11,300	-	-	20	Ef = 6.3 VAC Eb = 150 Rk = 360 Ω Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
7308/ E188CC	2 of 2	-	12	-	20	Ef = 6.3 VAC Eb = 150 Rk = 360 Ω Ib measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
7316	1 of 1	3800	-	-	20	Ef = 6.3 VAC (Para.) Eb = 150 Ec1 = -3.0 Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
7355	1 of 1	9500	-	-	50	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -7.5 G1-P Gm measured
7360	1 of 3	4500	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Rk = 150 Ω G1-P No. 1, P No 2 Gm measured
7360	2 of 3	-	0.2	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -1.0 Ib measured OK under 0.1 MA P No. 1 (Pin 7) used
7360	3 of 3	-	0.2	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -1.0 Ib measured OK under 0.1 MA P No. 2 (Pin 6) used
7370	1 of 2	16,000	-	-	20	Ef = 20.0 VAC (Para.) Eb = 120 Ec1 = -2.0 Gm measured Dual Test: 1st Triode: pins 6, 7, 9 used 2nd Triode: pins 1, 2, 3 used
7370	2 of 2	-	50	-	20	Ef = 20.0 VAC (Para.) Eb = 120 Ec1 = -2.0 Ib measured Dual Test: 1st Triode: pins 6, 7, 9 used 2nd Triode: pins 1, 2, 3 used
7408	1 of 2	4700	-	-	50	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -4.2 G1-P Gm measured

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
7408	2 of 2	-	70	-	50	Ef = 6.3 VAC Ebb = 304 Rl = 4760 Ω Ec2 = 150 Ec1 = 0 Ib measured
7534/ E130L	1 of 1	26,000	-	-	100	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Rk = 260 Ω G1-P Gm measured
7543	1 of 1	6300	-	-	20	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 70 Ω G1-P Gm measured
7551	1 of 2	6700	-	-	50	Ef = 13.5 VAC Eb = 250 Ec3 = 0 Ec2 = 250 Ec1 = -18 G1-P Gm measured Pins 2, 6, 7, 8, 9 used
7551	2 of 2	-	50	-	50	Ef = 13.5 VAC Eb = 250 Ec3 = 0 Ec2 = 250 Ec1 = -18 Ib measured Pins 1, 2, 3, 6, 7 used
7558	1 of 2	6700	-	-	50	Ef = 6.3 VAC Eb =250 Ec3 = 0 Ec2 = 250 Ec1 = -18 G1-P Gm measured Pins 2, 6, 7, 8, 9 used
7558	2 of 2	-	50	-	50	Ef = 6.3 VAC Eb = 250 Ec3 = 0 Ec2 = 250 Ec1 = -18 Ib measured Pins 1, 2, 3, 6, 7 used
7581	1 of 1	7500	-	-	70	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -6.1 G1-P Gm measured
7586	1 of 1	14,500	-	-	10	Ef = 6.3 VAC Eb = 50 Rk = 80 Ω Gm measured Hickok Adapter 1050-127 required
7587	1 of 1	11,700	-	-	10	Ef = 6.3 VAC Eb = 50 Ec2 = 50 Rk = 50 Ω G1-P Gm measured Hickok Adapter 1050-127 required
7591	1 of 2	11,300	-	-	50	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -4.0 G1-P Gm measured G2 pin 8 used
7591	2 of 2	-	84	-	50	Ef = 6.3 VAC Ebb = 298 Rl = 4470 Ω Ec2 = 150 Ec1 = 0 Ib measured G2 pin 4 used
7643/ E80CF	1 of 2	7800	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Rk = 130 Ω Pent. G1-P Gm measured
7643/ E80CF	2 of 2	6300	-	-	20	Ef = 6.3 VAC Eb = 100 Rk = 100 Ω Triode Gm measured
7687	1 of 2	6500	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Rk = 100 Ω Pent. G1-P Gm measured
7687	2 of 2	3100	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -6.0 Triode Gm measured
7693/ E90F	1 of 1	4300	-	-	20	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -1.0 G1-P Gm measured

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
7694/ E99F	1 of 1	4600	-	-	20	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -1.0 G1-P Gm measured
7695	1 of 1	9400	-	-	50	Ef = 50.0 VAC Eb = 100 Ec2 = 100 Ec1 = -11 G1-P Gm measured
7699	1 of 2	13,200	-	-	50	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -2.0 G1-P Gm measured Pins 1, 2, 6, 7 used
7699	2 of 2	13,200	-	-	50	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -2.0 G1-P Gm measured Pins 2, 3, 7, 8 used
7701	1 of 1	4500	-	-	50	Ef = 12.6 VAC Eb = 150 Ec2 = 150 Ec1 = -4.2 G1-P Gm measured Pins 1, 2, 6, 7 used
7716	1 of 2	2900	-	-	20	Ef = 13.6 VAC Eb = 100 Ec1 = -1.0 Triode Gm measured
7716	2 of 2	12,000	-	-	20	Ef = 13.6 VAC Eb = 150 Ec2 = 150 Rk = 80 Ω Pent. G1-P Gm measured
7717	1 of 1	10,000	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -1.4 G1-P Gm measured
7719	1 of 2	4400	-	-	20	Ef = 6.3 VAC (Para.) Eb = 150 Ec1 = -5.2 Gm measured Pins 3, 6, 7 used
7719	2 of 2	-	50	-	20	Ef = 6.3 VAC (Para.) Eb = 100 Ec1 = 0 Ib measured Pins 1, 2, 3 used
7722/ E280F	1 of 1	26,000	-	-	20	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 90 Ω G1-P Gm measured K pin 1 used
7724	1 of 2	1400	-	-	20	Ef = 14.0 VAC Eb = 150 Ec1 = -1.6 Gm measured
7724	2 of 2	-	22	-	20	Ef = 14.0 VAC Ebb = 9.0 Rl = 115 Ω Diode Ib measured Dual Test: 1st Diode: pins 1 & 6 used 2nd Diode: pins 2 & 3 used
7728	1 of 1	5000	-	-	20	Ef = 6.3 VAC (Para.) Eb = 100 Rk = 270 Ω Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
7729	1 of 1	1600	-	-	20	Ef = 6.3 VAC (Para.) Eb = 100 Ec1 = -1.0 Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
7730	1 of 1	3800	-	-	20	Ef = 6.3 VAC (Para.) Eb = 150 Ec1 = -3.0 Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
7731	1 of 2	5700	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Rk = 70 Ω Pent. G1-P Gm measured

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
7731	2 of 2	10,700	-	-	20	Ef = 6.3 VAC Eb = 150 Rk = 60 Ω Triode Gm measured
7732	1 of 1	7600	-	-	20	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 180 Ω G1-P Gm measured
7733	1 of 1	13,800	-	-	20	Ef = 6.3 VAC (Para.) Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 70 Ω G1-P Gm measured
7734	1 of 4	4000	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -2.0 Pent. G1-P Gm measured
7734	2 of 4	6300	-	-	50	Ef = 6.3 VAC Eb = 150 Ec1 = -21 Triode Gm measured
7734	3 of 4	-	88	-	50	Ef = 6.3 VAC Eb = 50 Ec1 = 0 Triode Ib measured
7734	4 of 4	-	1.5	-	50	Ef = 6.3 VAC Eb = 150 Ec1 = -42 Triode Ib cut-off test OK under 0.75 MA
7737/ E186F	1 of 2	22,000	-	-	20	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 80 Ω G1-P Gm measured K pin 3 used
7737/ E186F	2 of 2	-	22	-	20	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 80 Ω Ib measured K pin 1 used
7754	1 of 1	9400	-	-	50	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -11 G1-P Gm measured
7759	1 of 2	8000	-	-	10	Ef = 26.5 VAC Eb = 100 Rk = 150 Ω Gm measured Dual Test: 1st Triode: pins 5, 7, 8 used 2nd Triode: pins 1, 2, 4 used
7759	2 of 2	-	0.2	-	10	Ef = 26.5 VAC Eb = 100 Ec1 = -6.5 Ib measured OK under 0.1 MA Dual Test: 1st Triode: pins 5, 7, 8 used 2nd Triode: pins 1, 2, 4 used
7760	1 of 1	6300	-	-	10	Ef = 26.5 VAC Eb = 50 Ec1 = -2.2 Gm measured Dual Test: 1st Triode: pins 5, 7, 8 used 2nd Triode: pins 1, 2, 4 used
7761	1 of 1	13,100	-	-	50	Ef = 26.5 VAC Eb = 100 Ec2 = 100 Rk = 100 Ω G1-P Gm measured
7762	1 of 3	5300	-	-	50	Ef = 26.5 VAC Eb = 100 Ec2 = 100 Rk = 220 Ω G1-P Gm measured K pin 8 used
7762	2 of 3	-	50	-	50	Ef = 26.5 VAC Eb = 100 Ec2 = 100 Rk = 220 Ω Ib measured OK 23 to 37 MA K pin 4 used
7762	3 of 3	-	0.2	-	50	Ef = 26.5 VAC Eb = 100 Ec2 = 100 Ec1 = -36 Ib measured OK under 0.1 MA K pin 2 used
7788/ E810F	1 of 2	63,000	-	-	20	Ef = 6.3 VAC Eb = 160 Ec3 = 0 Ec2 = 160 Ec1 = +7.5 Rk = 240 Ω G1-P Gm measured Pins 2, 3, 7, 8, 9 used

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
7788/ E810F	2 of 2	-	44	-	20	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 50 Ω Ib measured Pins 1, 2, 6, 7, 8 used
7802	1 of 3	25,200	-	-	100	Ef = 6.3 VAC Eb = 100 Ec1 = -4.8 Gm measured Dual Test: 1st Triode: pins 4, 5, 6 used 2nd Triode: pins 1, 2, 3 used
7802	2 of 3	-	-	140	100	Ef = 6.3 VAC Etd measured at 98 MA OK under 70 V Dual Test: 1st Triode: pins 4, 5, 6 used 2nd Triode: pins 1, 2, 3 used
7802	3 of 3	-	6.0	-	100	Ef = 6.3 VAC Eb = 150 Ec1 = -30 Ib cutoff test OK under 3.0 MA Dual Test: 1st Triode: pins 4, 5, 6 used 2nd Triode: pins 1, 2, 3 used
7861	1 of 1	7700	-	-	10	Ef = 12.6 VAC Eb = 150 Rk = 240 Ω Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 2, 3, 4 used
7867	1 of 1	11,300	-	-	100	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Rk = 200 Ω G1-P Gm measured
7868	1 of 2	11,100	-	-	50	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -4.0 G1-P Gm measured G2 pin 7 used G1 pin 2 used
7868	2 of 2	-	76	-	50	Ef = 6.3 VAC Eb = 40 Ec2 = 150 Ec1 = 0 Ib measured G2 pin 1 used G1 pin 6 used
7889	1 of 2	2400	-	-	10	Ef = 26.5 VAC Eb = 100 Rk = 1500 Ω Gm measured Dual Test: 1st Triode: pins 5, 7, 8 used 2nd Triode: pins 1, 2, 4 used
7889	2 of 2	-	0.1	-	10	Ef = 26.5 VAC Eb = 100 Ec1 = -2.8 Ib measured OK under 0.05 MA Dual Test: 1st Triode: pins 5, 7, 8 used 2nd Triode: pins 1, 2, 4 used
7895	1 of 1	11,800	-	-	10	Ef = 6.3 VAC Eb = 100 Rk = 130 Ω Gm measured Hickok Adapter 1050-127 required
7898	1 of 1	5000	-	-	20	Ef = 13.5 VAC Eb = 100 Rk = 270 Ω Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
7905	1 of 2	-	42	-	-	Ef = 3.2 VAC (Para.) Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 90 Ω Ip measured G2 pin 8 used Fil C. T. pin 4 used
7905	2 of 2	-	42	-	-	Ef = 3.2 VAC (Para.) Eb = 150 Ec3 = 0 Ec2 = 150 Rk = 90 Ω Ip measured G2 pin 3 used Fil. C. T. pin 5 used
8013A	1 of 1	-	24	-	-	Ef = 2.5 VAC Ebb = 328 VDC Rl = 7100 Ω Ib measured

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
8016	1 of 1	-	6.0	-	-	Ef = 1.1 VAC Ebb = 100 Rl = 425 Ω Ib measured
8056	1 of 1	5000	-	-	20	Ef = 6.3 VAC Eb = 50 Rk = 470 Ω Gm measured Hickok Adapter 1050-127 required
8058	1 of 2	Instruction Card				
8058	2 of 2	12,300	-	-	10	Ef = 6.3 VAC Eb = 150 Rk = 150 Ω Gm measured K pin 2 used Hickok Adapter 1050-127 required
8102	1 of 2	7200	-	-	20	Ef = 13.5 VAC Eb = 100 Ec2 = 100 Ec1 = -1.0 Pent. G1-P Gm measured
8102	2 of 2	10,000	-	-	20	Ef = 13.5 VAC Eb = 150 Ec1 = -1.5 Triode Gm measured
8106	1 of 1	11,400	-	-	20	Ef = 13.5 V Eb = 150 Ec2 = 150 Ec1 = -3.3 G1-P Gm measured G2 pin 8 used K pin 9 used
8185	1 of 1	24,000	-	-	20	Ef = 6.3 VAC Eb = 150 Rk = 190 Ω Gm measured G1 pin 7 used
8186	1 of 1	24,000	-	-	20	Ef = 26.5 VAC Eb = 150 Rk = 190 Ω Gm measured G1 pin 7 used
9001	1 of 2	1600	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -3.0 G1-P Gm measured K pin 7 used
9001	2 of 2	1600	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -3.0 G1-P Gm measured K pin 2 used
9002	1 of 2	2400	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -4.1 Gm measured P pin 5 used K pin 7 used
9002	2 of 2	2400	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -4.1 Gm measured P pin 1 used K pin 2 used
9003	1 of 2	2100	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -3.0 G1-P Gm measured K pin 7 used
9003	2 of 2	2100	-	-	20	Ef = 6.3 VAC Eb = 100 Ec2 = 100 Ec1 = -3.0 G1-P Gm measured K pin 2 used
9006	1 of 2	-	8.1	-	20	Ef = 6.3 VAC Epp = 250 VAC (H-W) Rl = 58,100 Ω Cl = 4 μf Io measured P pin 5 used K pin 7 used
9006	2 of 2	-	8.1	-	20	Ef = 6.3 VAC Epp = 250 VAC (H-W) Rl = 58,100 Ω Cl = 4 μf Io measured P pin 1 used K pin 2 used
38142	1 of 1	-	38	-	-	Ef = 7.0 VAC Eb = 150 Ec1 = -23 Ib measured
DC90	1 of 2	-	3.8	-	-	Ef = 1.4 VAC Eb = 100 Ec1 = -4.4 Ib measured Pins 3 & 5 used
DC90	2 of 2	-	3.8	-	-	Ef = 1.4 VAC Eb = 100 Ec1 = -4.4 Ib measured Pins 2 & 6 used

TABLE 2-2. (continued)

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
E82CC	1 of 1	3800	-	-	20	Ef = 6.3 VAC (Para.) Eb = 150 Ec1 = -3.0 Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
E92CC	1 of 3	7500	-	-	20	Ef = 6.3 VAC Eb = 150 Rk = 200 Ω Gm measured Dual Test: 1st Triode: pins 2, 5, 7 used 2nd Triode: pins 1, 6, 7 used
E92CC	2 of 3	-	14	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -1.7 Ib measured OK 4.5 to 12.5 MA Dual Test: 1st Triode: pins 2, 5, 7 used 2nd Triode: pins 1, 6, 7 used
E92CC	3 of 3	-	0.2	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -10 Ib measured OK under 0.1 MA Dual Test: 1st Triode: pins 2, 5, 7 used 2nd Triode: pins 1, 6, 7 used
EAA91	1 of 1	-	26	-	10	Ef = 6.3 VAC Ebb = 9.0 Rl = 100 Ω Diode Ib measured Dual Test: 1st Diode: pins 1 & 7 used 2nd Diode: pins 2 & 5 used
EB91	1 of 1	-	26	-	10	Ef = 6.3 VAC Ebb = 9.0 Rl = 100 Ω Diode Ib measured Dual Test: 1st Diode: pins 1 & 7 used 2nd Diode: pins 2 & 5 used
ECC81	1 of 1	6300	-	-	20	Ef = 6.3 VAC (Para.) Eb = 150 Ec1 = -1.0 Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
ECC82	1 of 1	3800	-	-	20	Ef = 6.3 VAC (Para.) Eb = 150 Ec1 = -3.0 Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
ECC83	1 of 1	1600	-	-	10	Ef = 6.3 VAC (Para.) Eb = 100 Ec1 = -1.0 Gm measured Dual Test: 1st Triode: pins 6, 7, 8 used 2nd Triode: pins 1, 2, 3 used
ECF83	1 of 2	1640	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -2.2 Pent. G1-P Gm measured
ECF83	2 of 2	4400	-	-	20	Ef = 6.3 VAC Eb = 50 Rk = 600 Ω Triode Gm measured
ECF804	1 of 2	13,800	-	-	20	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -2.0 Pent. G1-P Gm measured
ECF804	2 of 2	9100	-	-	20	Ef = 6.3 VAC Eb = 150 Ec1 = -1.5 Triode Gm measured
ECH35	1 of 2	2000	-	-	20	Ef = 6.3 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Rk = 380 Ω Pent. G1-P Gm measured
ECH35	2 of 2	3200	-	-	20	Ef = 6.3 VAC Eb = 100 Ec1 = -1.0 Triode Gm measured

TUBE TYPE	TEST CARD	QUALITY TEST FULL SCALE			H-K	TEST CONDITIONS
		μMHOS	MA	VOLTS		
EF91	1 of 1	8200	-	-	20	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Ec1 = -1.2 G1-P Gm measured
EF804	1 of 1	2500	-	-	20	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Ec1 = -2.1 G1-P Gm measured
EL37	1 of 1	13,900	-	-	70	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -6.2 G1-P Gm measured
EL821	1 of 1	14,000	-	-	20	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Ec1 = -1.0 G1-P Gm measured
EL822	1 of 1	15,700	-	-	20	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Ec1 = -2.5 G1-P Gm measured
EZ90	1 of 1	-	112	-	150	Ef = 6.3 VAC Epp = 250 VAC (F-W) Rl = 4000 Ω Cl = 4 μf Io measured
GZ32	1 of 1	-	320	-	-	Ef = 5.0 VAC Epp = 250 VAC (F-W) Rl = 1100 Ω Cl = 4 μf Io measured
GZ33	1 of 1	-	320	-	-	Ef = 5.0 VAC Epp = 250 VAC (F-W) Rl = 1100 Ω Cl = 4 μf Io measured
KT61	1 of 1	13,200	-	-	50	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Rk = 40 Ω G1-P Gm measured
KT66	1 of 1	7900	-	-	70	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -5.3 G1-P Gm measured
KT88	1 of 1	12,600	-	-	100	Ef = 6.3 VAC Eb = 150 Ec2 = 150 Ec1 = -7.0 G1-P Gm measured
UF89	1 of 1	4500	-	-	20	Ef = 12.6 VAC Eb = 100 Ec3 = 0 Ec2 = 100 Ec1 = -1.9 G1-P Gm measured
W77	1 of 1	2900	-	-	20	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Ec1 = -1.0 G1-P Gm measured
Z729	1 of 1	2300	-	-	20	Ef = 6.3 VAC Eb = 150 Ec3 = 0 Ec2 = 150 Ec1 = -2.1 G1-P Gm measured